

材料与能源前沿科学:

“能源转换和储存中的基础科学问题” 培训班

# 铜铟镓硒与铜锌锡硫薄膜太阳能电池

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2022-11-03

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3. 溶液法CIGS电池：材料合成与晶粒生长机制
4. 总结与展望

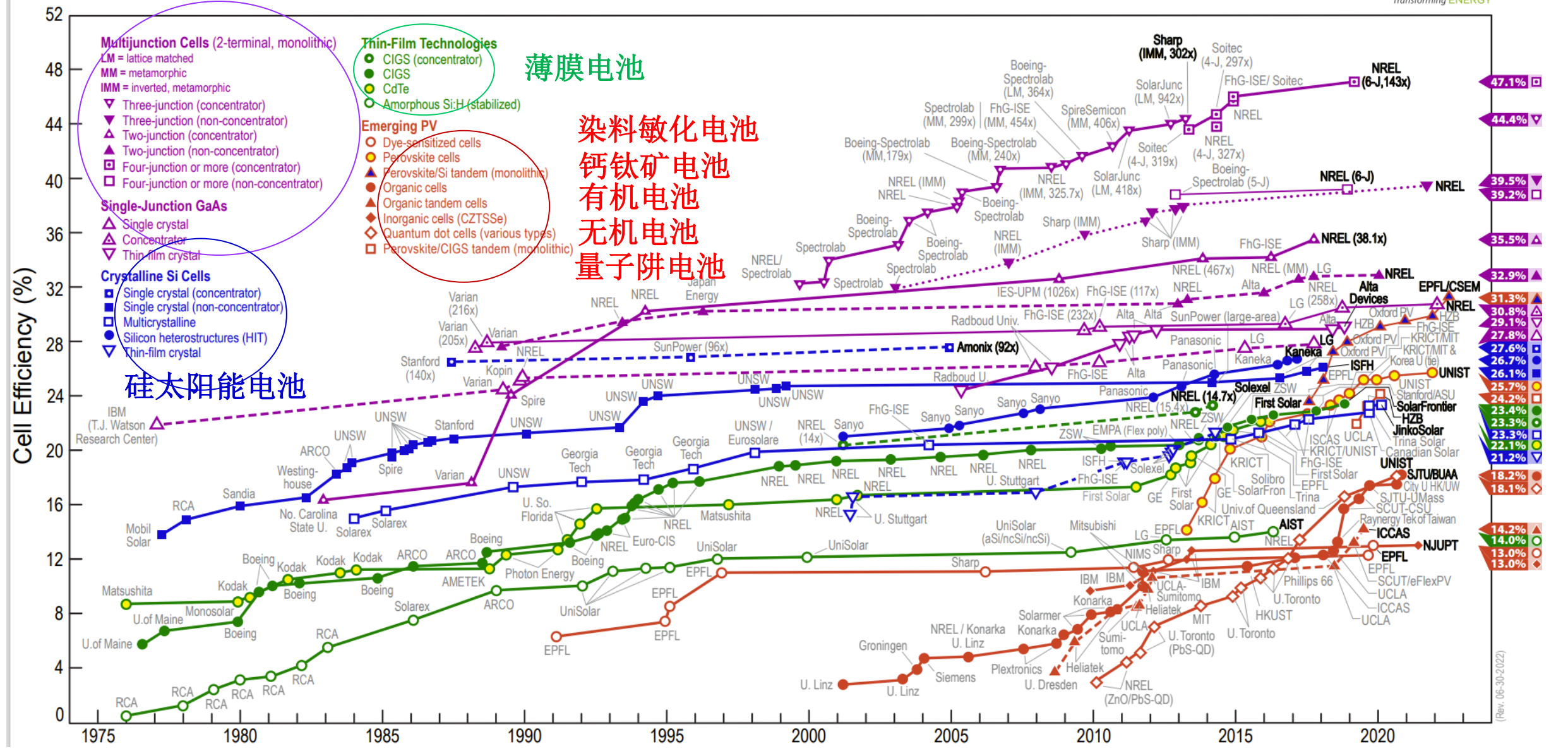
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4. 总结与展望

## III. 致谢

# Best Research-Cell Efficiencies

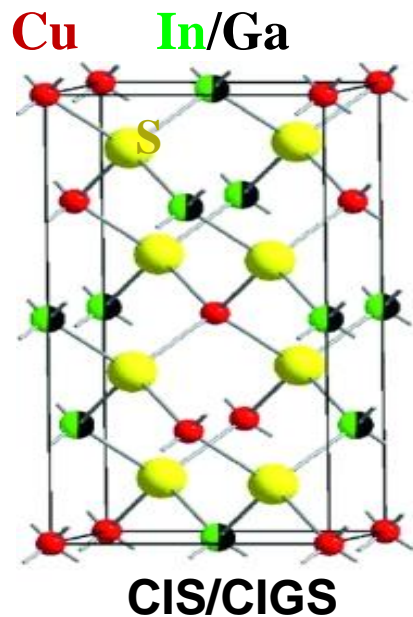
# 太阳能电池类型



This plot is courtesy of the National Renewable Energy Laboratory, Golden, CO.

(Rev. 06-30-2022)

# 1. CIGS薄膜太阳能电池简介



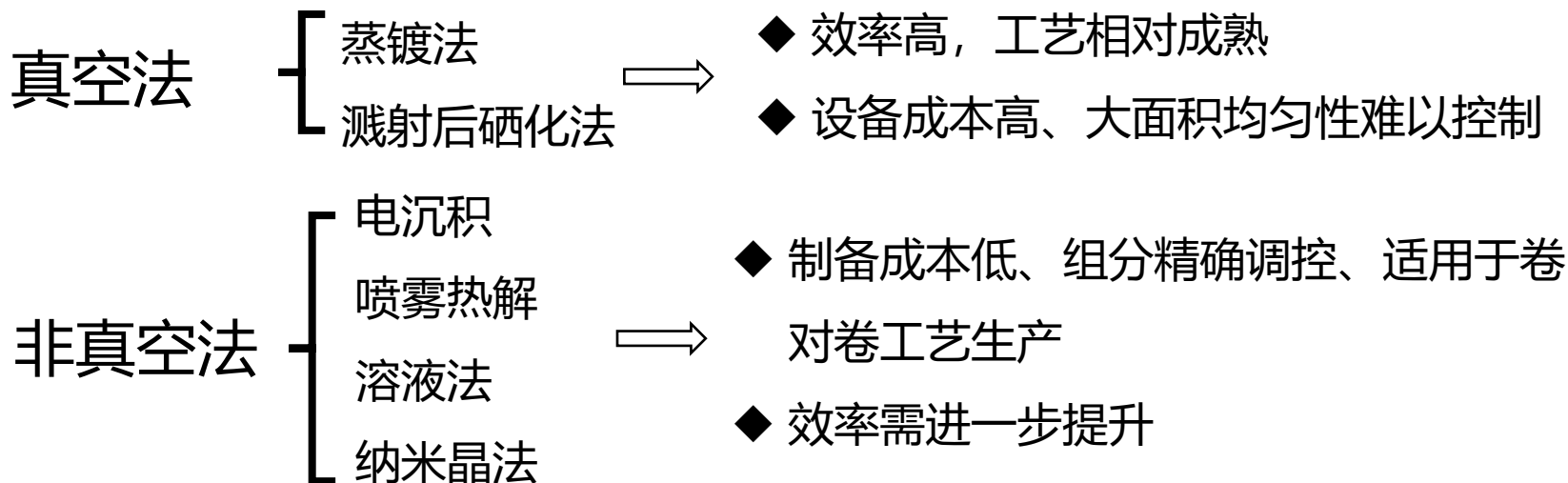
CIGS晶体结构

本征p-型半导体 ( $V_{Cu}$ )

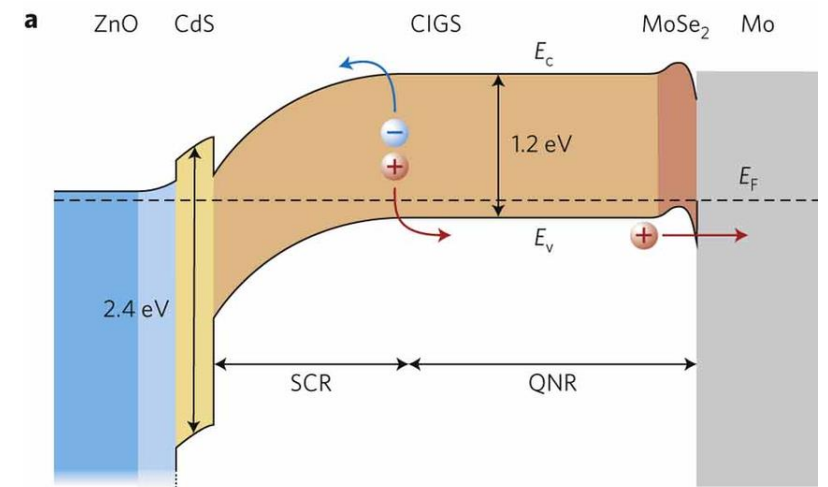
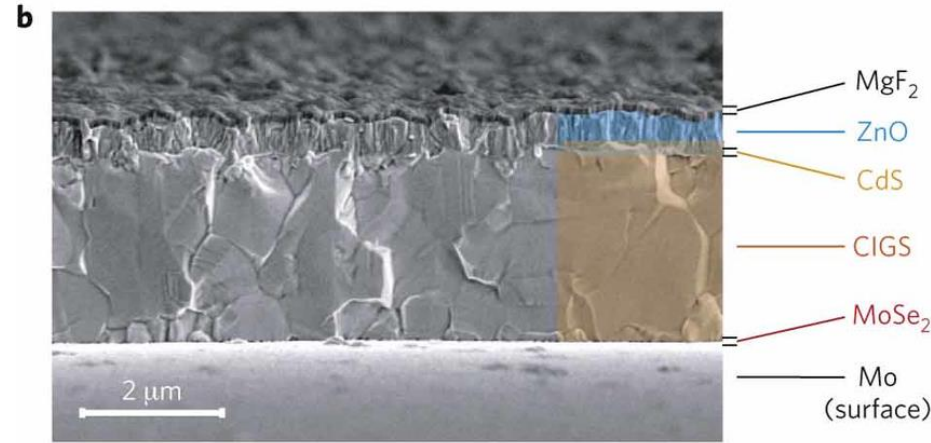
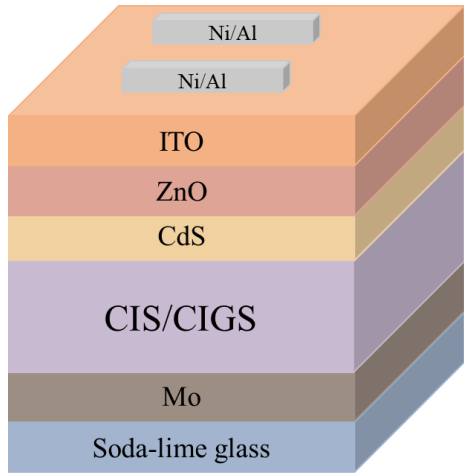
- 直接带隙
- 吸光系数高 ( $10^5 \text{ cm}^{-1}$ )
- 带隙可调 (1.04 eV-1.67 eV)
- 理论效率高 (32%-33%)
- 多晶薄膜: 较高的缺陷耐受度

CIGS电池

- 成本相对低
- 稳定性好
- 效率高
- 轻薄
- 可柔性



# Device Structure and Energy Diagram

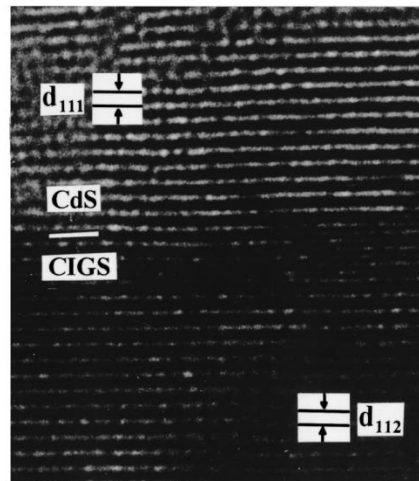


多晶薄膜：晶粒内和晶界处缺陷

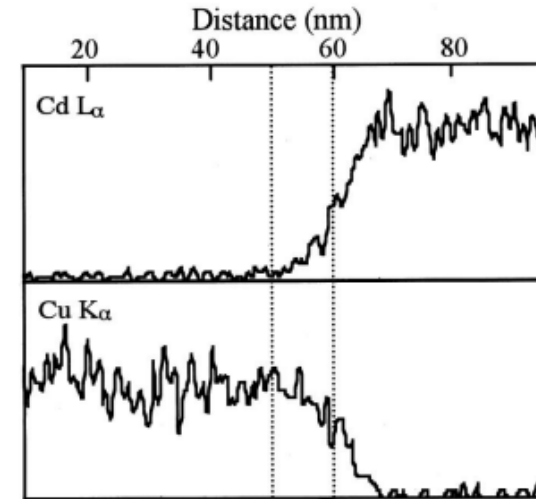
## 晶格匹配

	Zinc-blende	(112)/(111) in-plane cons.	layer distance
<b>CdS</b>	5.848	4.136	3.376
<b>CuInSe<sub>2</sub></b>	a=5.781	4.103	3.349

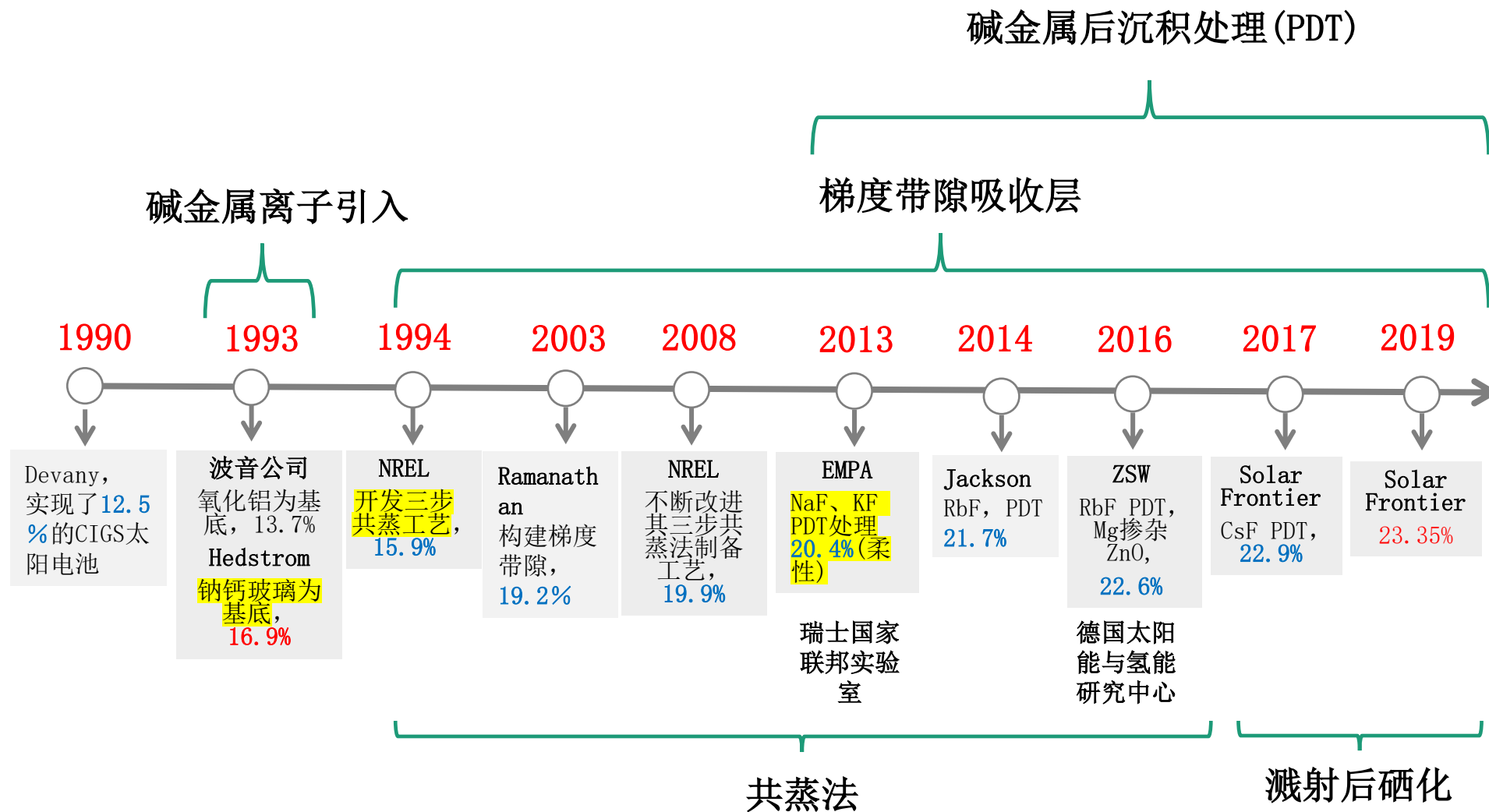
## 外延型异质结界面



## Cu-poor 表面, 内埋异质结

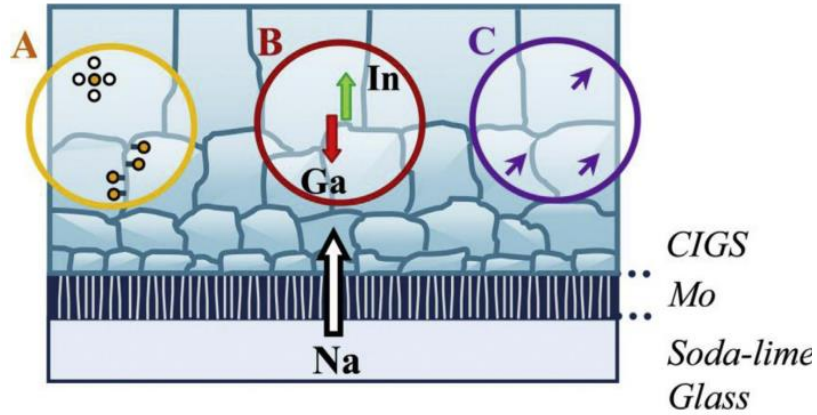


# 2. 真空法CIGS电池提高历程



## 2.1 碱金属离子引入 (Na掺杂)

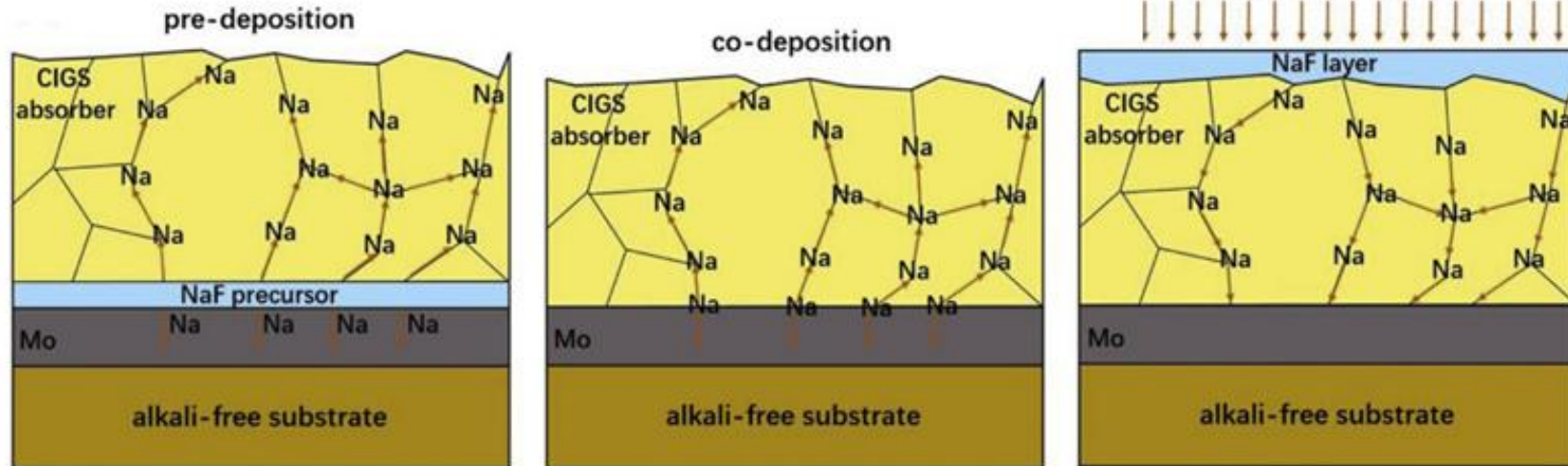
1993年, Hedstrom以钠钙玻璃为基底制备CIGS电池效率16.9%



CIGS吸收膜掺入Na可改善器件性能  
经Na掺入CIGS薄膜后发生:

- (A) 载流子密度增加和钝化晶界
- (B) 镓的偏析
- (C) 晶面生长取向变化

钠钙玻璃中的Na能扩散至吸收膜中, 对于不含碱金属的衬底可采用如下方法:

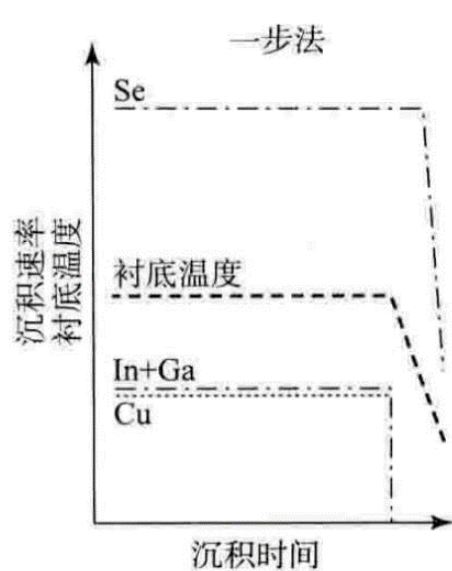


预沉积

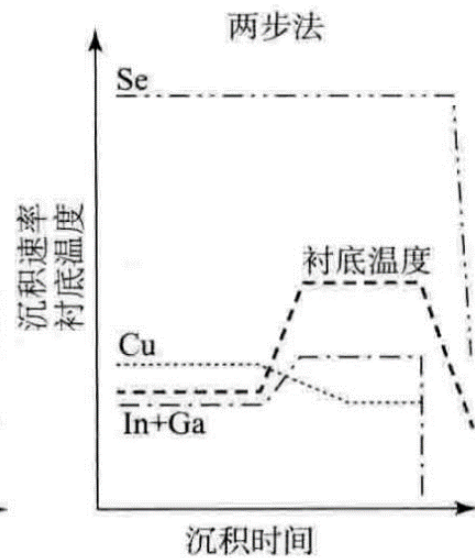
共沉积

后沉积

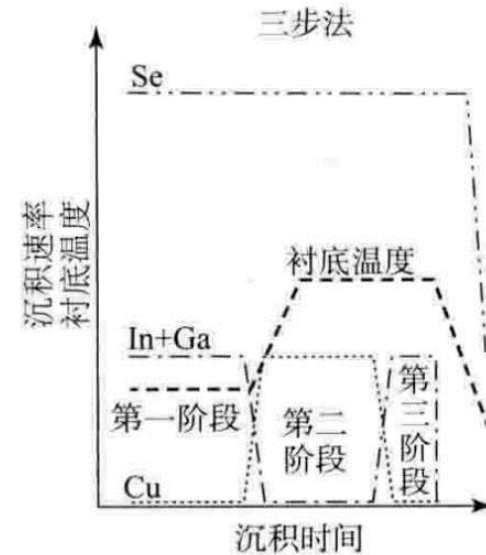
## 2.2 梯度带隙吸收层 (三步共蒸法)



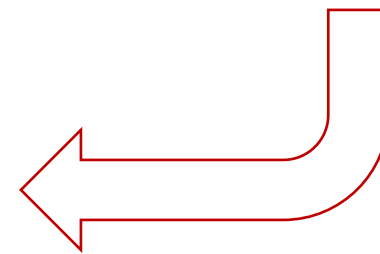
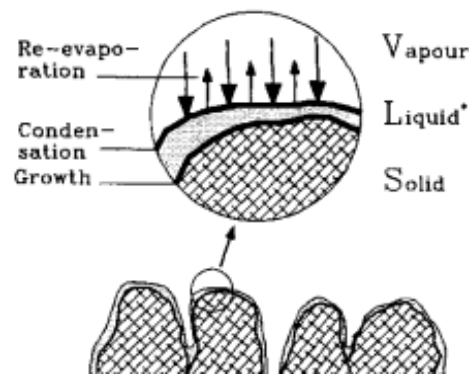
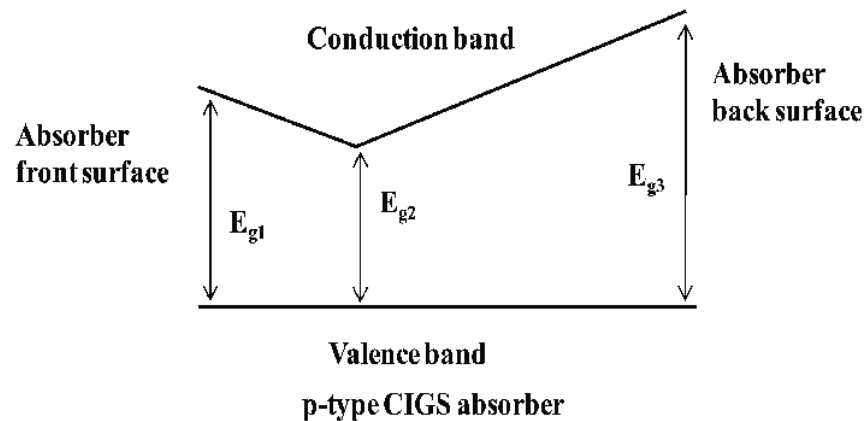
组分贫铜  
工艺简单  
结晶质量低



第一步富铜  
第二步贫铜  
薄膜晶粒大，组分贫铜



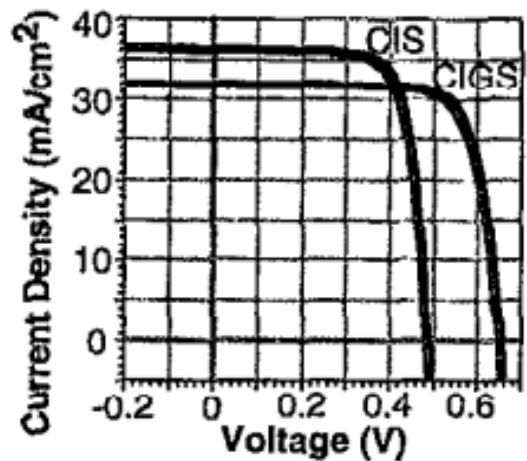
第一、三步沉积In、Ga、Se  
第二步沉积Cu、Se  
可构建梯度带隙，结晶质量高



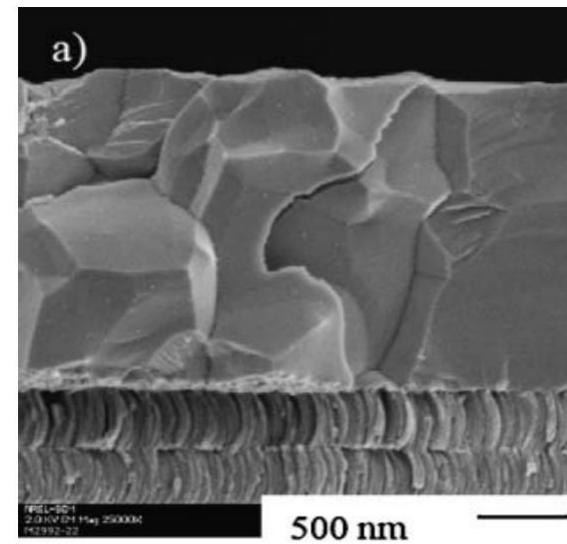
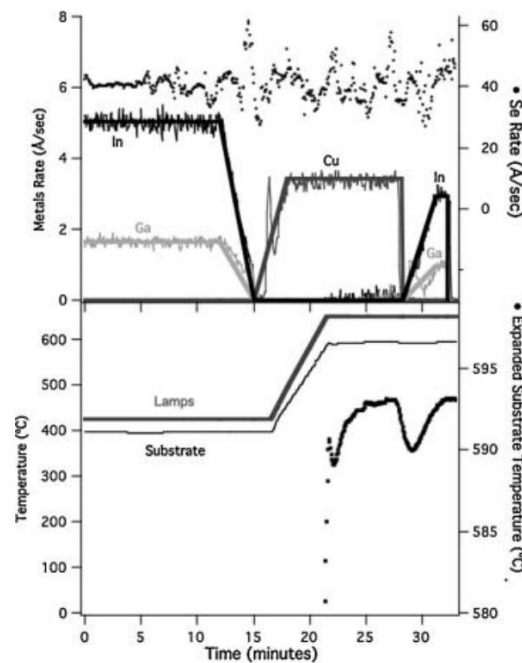


NREL, 首次开发三步共蒸工艺, 15.9%

不断改进的三步共蒸法制备工艺, 效率19.9%



	<u>CIS</u>	<u>CIGS</u>
Area (cm <sup>2</sup> )	0.395	0.437
Voc (V)	0.484	0.649
Jsc (mA/cm <sup>2</sup> )	36.29	31.88
FF (%)	75.10	76.60
Eff. (%)	13.2	15.9

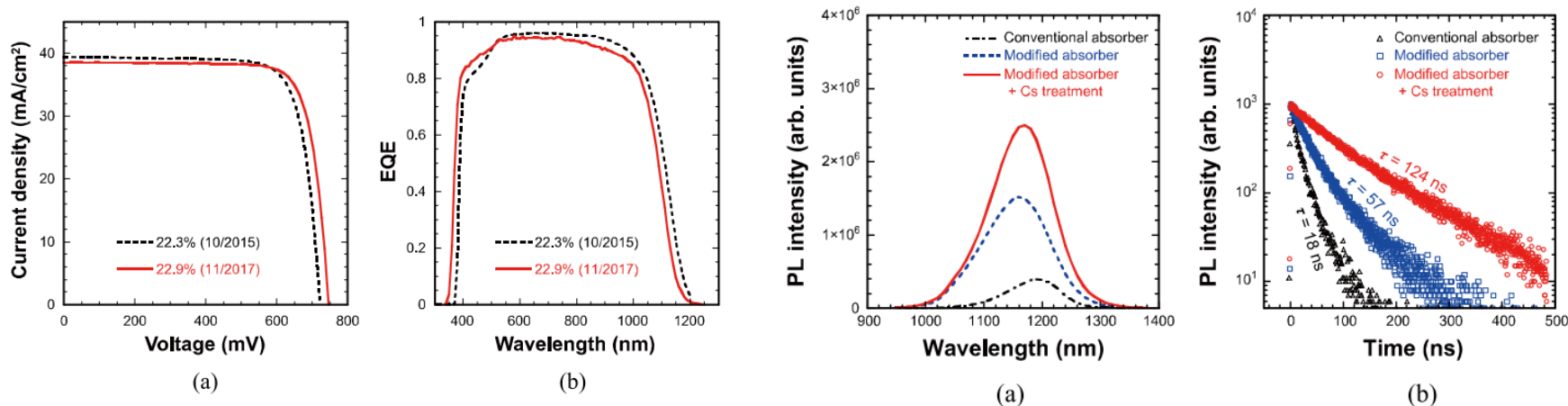


Applied Physics Letters 1994, 65(2):198-200.

Progress in Photovoltaics: Research and Applications, 2008, 16(3): 23523-9.

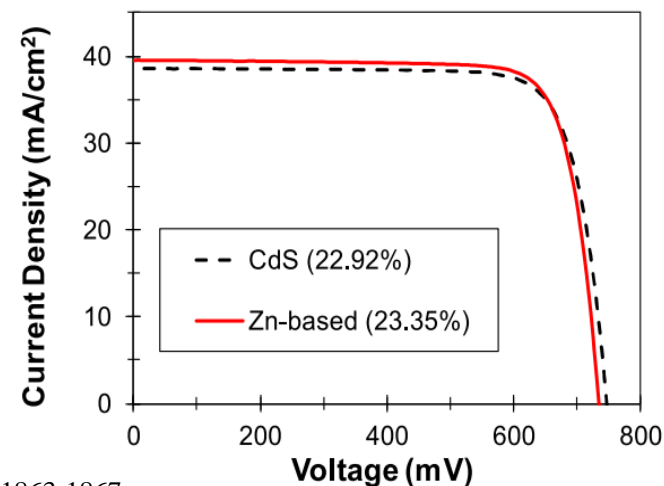
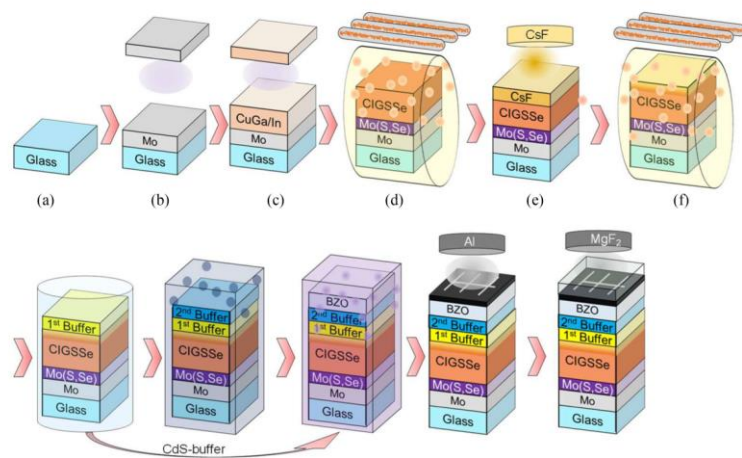
## 2.3. 碱金属后沉积处理 (PDT)

Solar Frontier, 溅射后硒化法制备吸收层, 经CsF PDT处理: 22.9%



IEEE Journal of Photovoltaics, 2017, 9(1):325-330

Solar Frontier, 溅射后硒化法制备吸收层, 经CsF PDT处理, 沉积无镉缓冲层: 23.35%

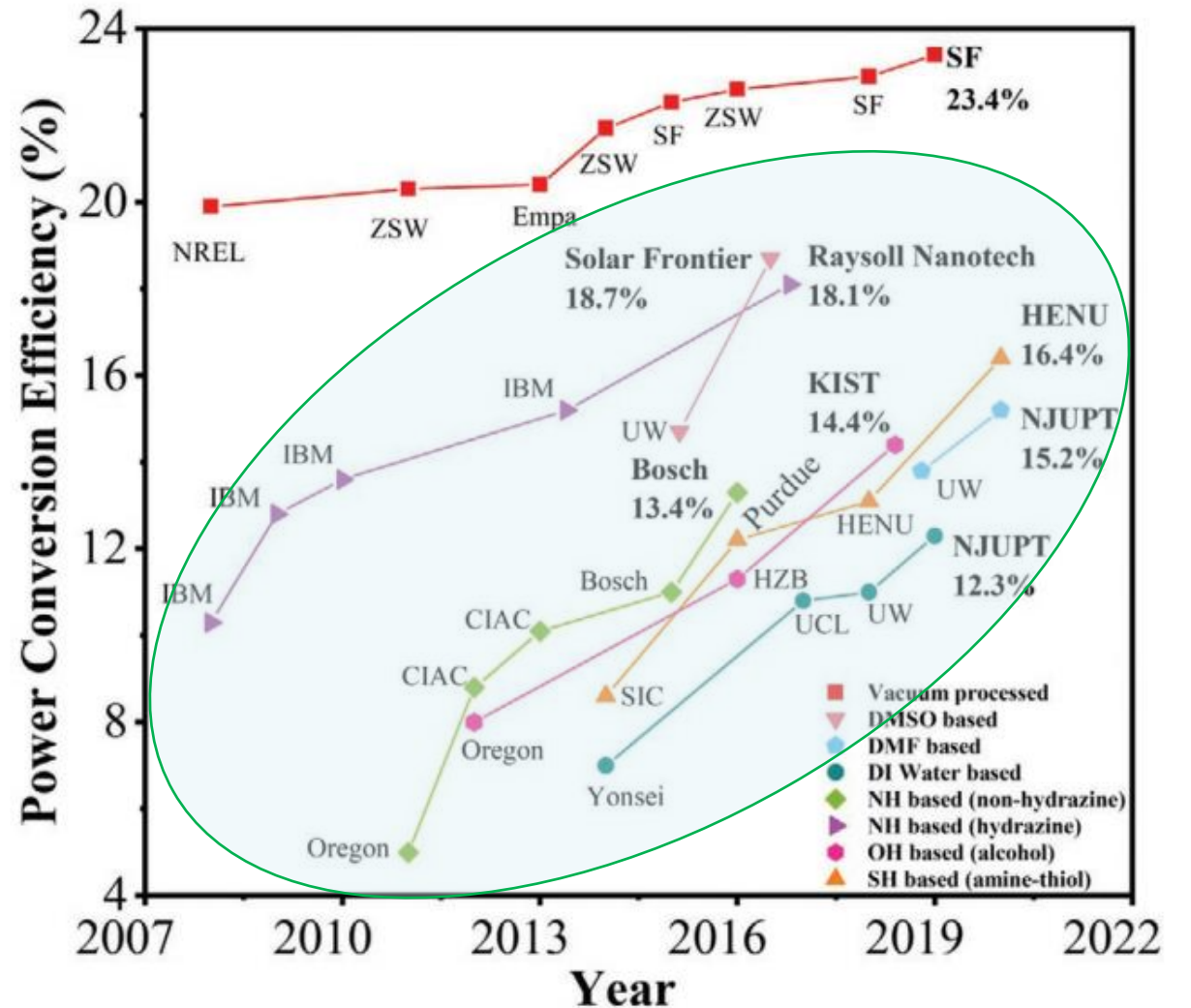
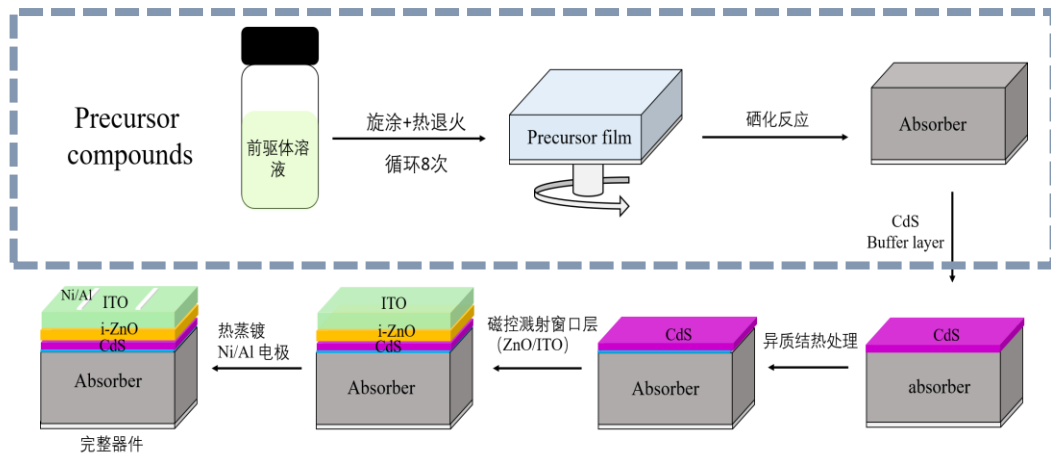


IEEE Journal of Photovoltaics, 2019, 9(6): 1863-1867.

# 3. 溶液法CIS/CIGS电池：材料合成与晶粒生长机制

## New applications

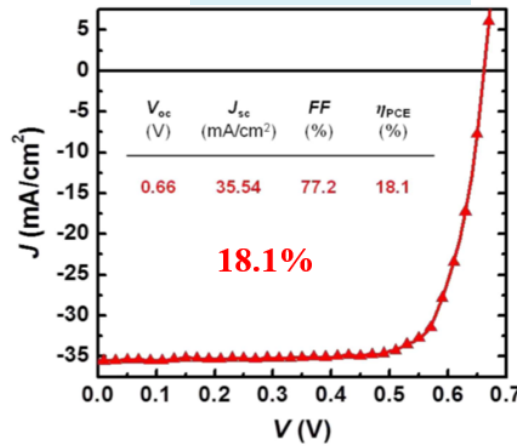
- Adoptable to roll-to-roll processing
- High materials utilization rate
- High throughput
- Property chemical control



S. Suresh and A. R. Uhl, Adv. Energy Mater. 2021, 2003743

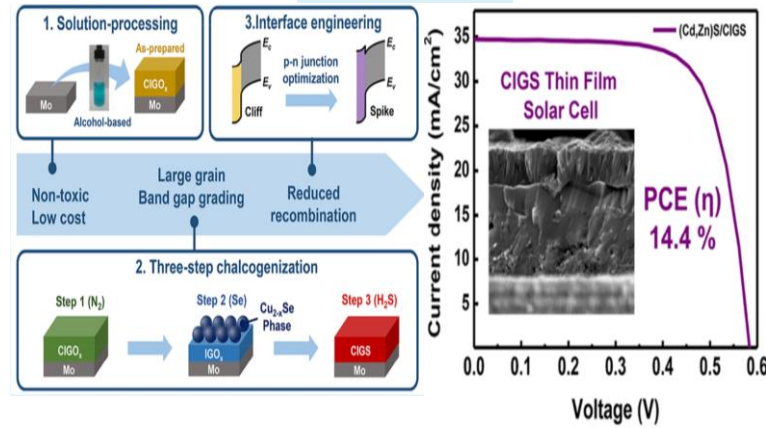
# Solution Processed CIS/CIGS

## Hydrazine



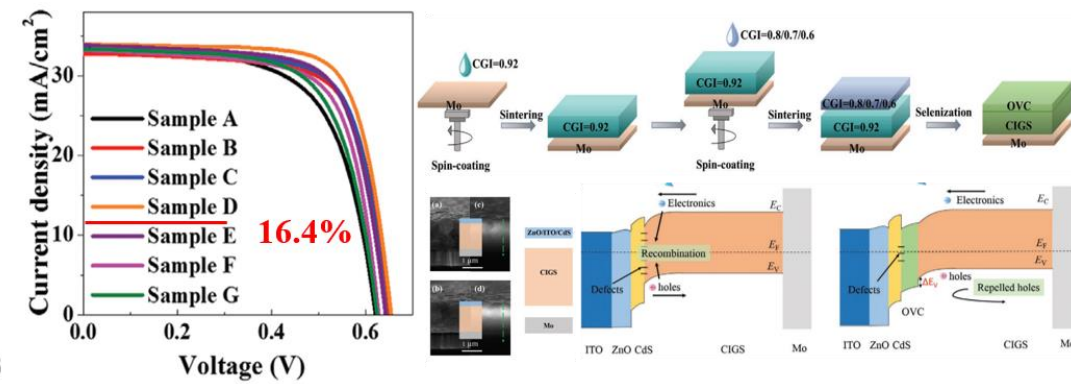
Qian, et al. *Energy Environ. Sci.*, 2016, 9, 3674.

## Alcohol



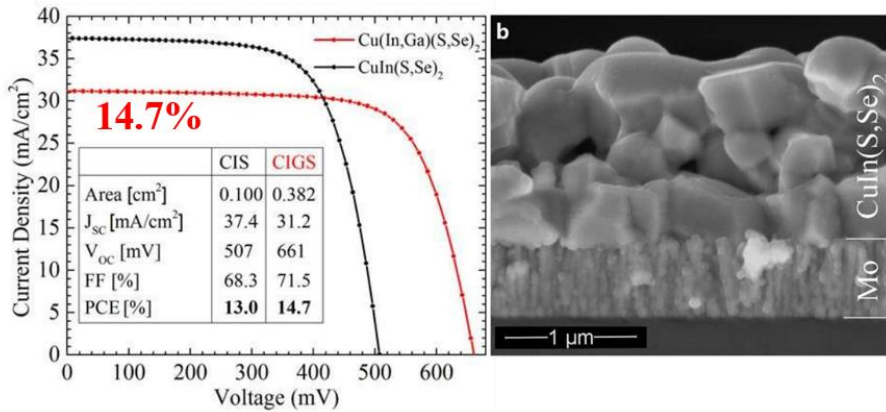
Min, et al. *ACS, AMI*, 2018, 10, 9894.

## Amine-thiol



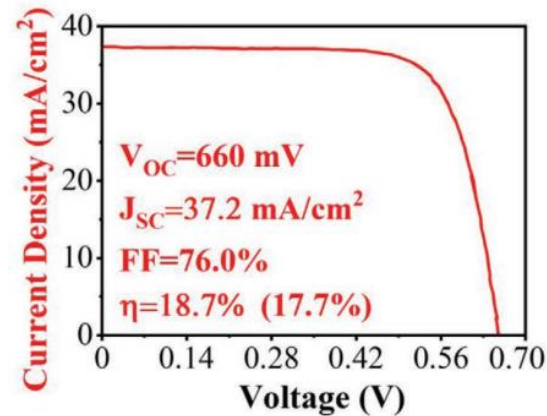
Zhao and Wu, et al. *Adv. Funct. Mater.*, 2020, 31, 2007928.

## DMSO

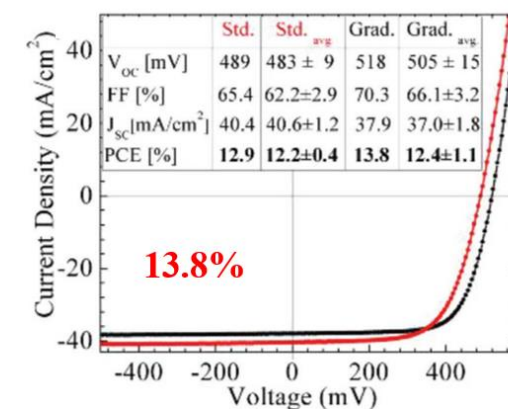


Hillhouse, et al. *Adv. Energy Mater.* 2018, 8, 1801254

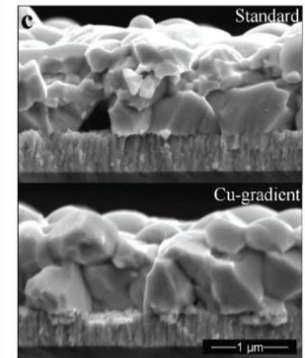
## DMF



Tetsuya Aramoto, et al. *32nd Eur. Photovoltaic Sol. Energy Conf. and Exhibition*, 2016.

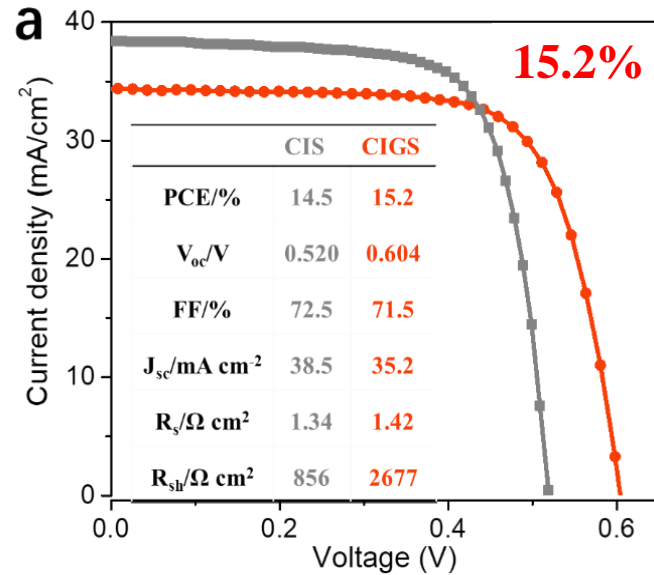


Hillhouse, et al. *Adv. Energy Mater.* 2018, 8, 1801254



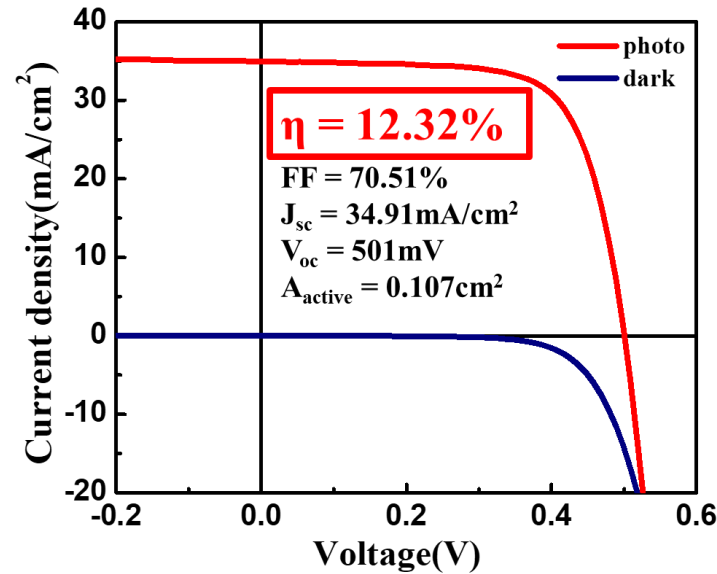
# Three Examples of Solution Processed CIGS Solar Cells

## DMF Solution



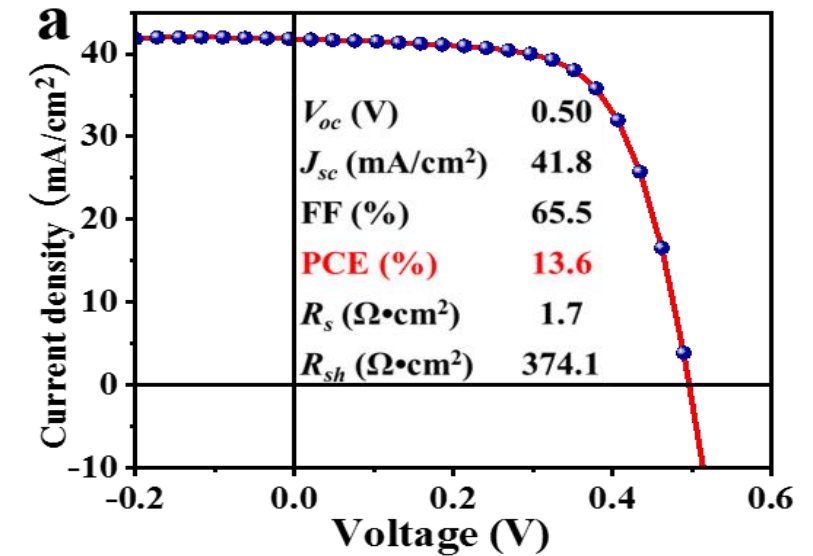
*Solar RRL* 2018.  
*Nano Energy* 2020.

## H<sub>2</sub>O Solution



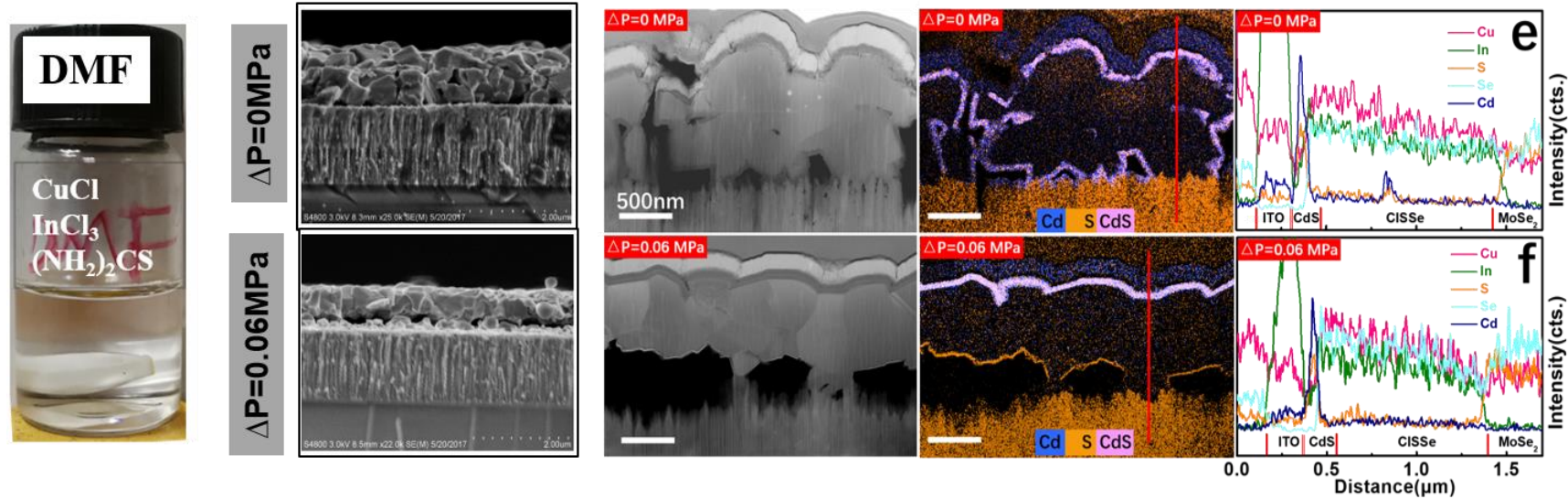
*Nano Energy* 2019.  
*Adv. Energy Sustainability Res.* 2022.

## NMP Solution



*Solar RRL* 2019.  
*Solar Energy* 2021.  
*Adv. Energy Mater.* 2022.

## 2.1 DMF溶液：硒化氛围压力影响

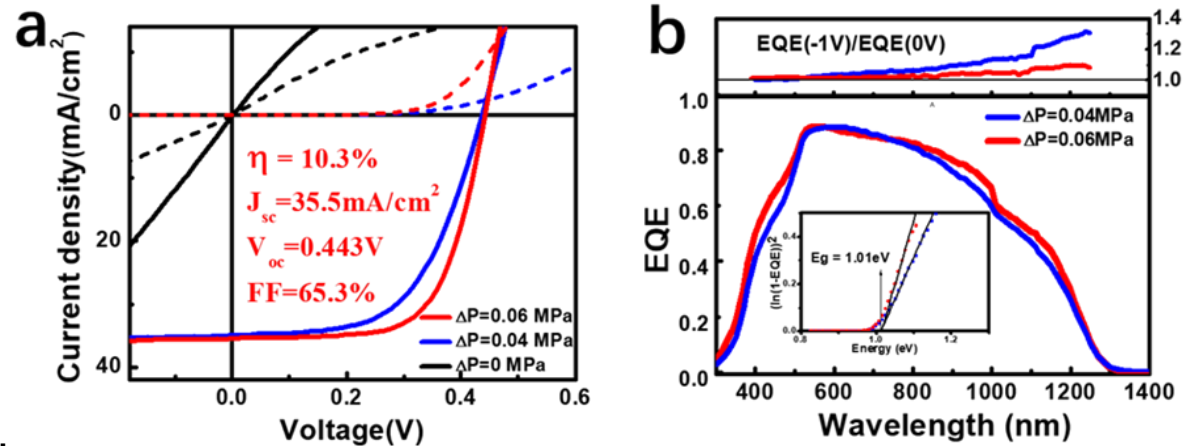


$\Delta P=0\text{ MPa}$ : loose grains, CdS into the film, Cu-rich near surface

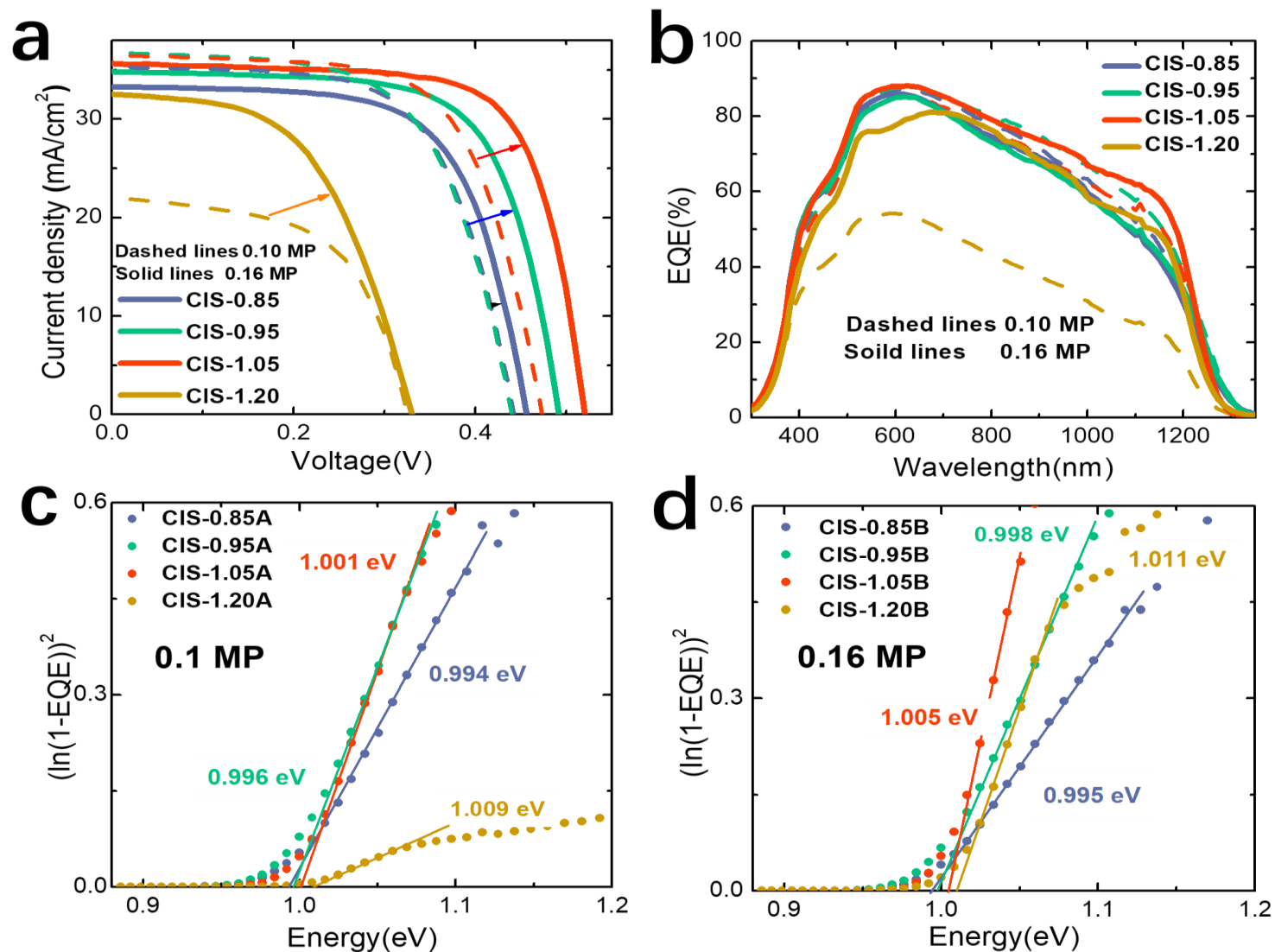
$\Delta P=0.06\text{ MPa}$ : dense top grains, CdS only on surface, uniform composition

**Cu/In=0.85, no etching treatment**

- Dissolve all precursors at room temperature.
- Long-time stability
- PCE=10.3%



## 2.2 DMF溶液: Cu-rich 吸收层



- 常压: Cu/In=1.05 效率最高 PCE=11.3%
- 加压: Cu/In=1.05 效率最高 PCE=13.3%

## Cu-poor (Cu/(In+Ga)<0.9)

- State-of-the-art composition
- Avoid Cu<sub>2-x</sub>Se impurity (KCN etching is still needed)
- Order-defect-compound (ODC) layer

## Cu-rich

- Lower defect
- Potentially High V<sub>oc</sub>
- Cu<sub>2-x</sub>Se impurity
- High performance not achieved yet

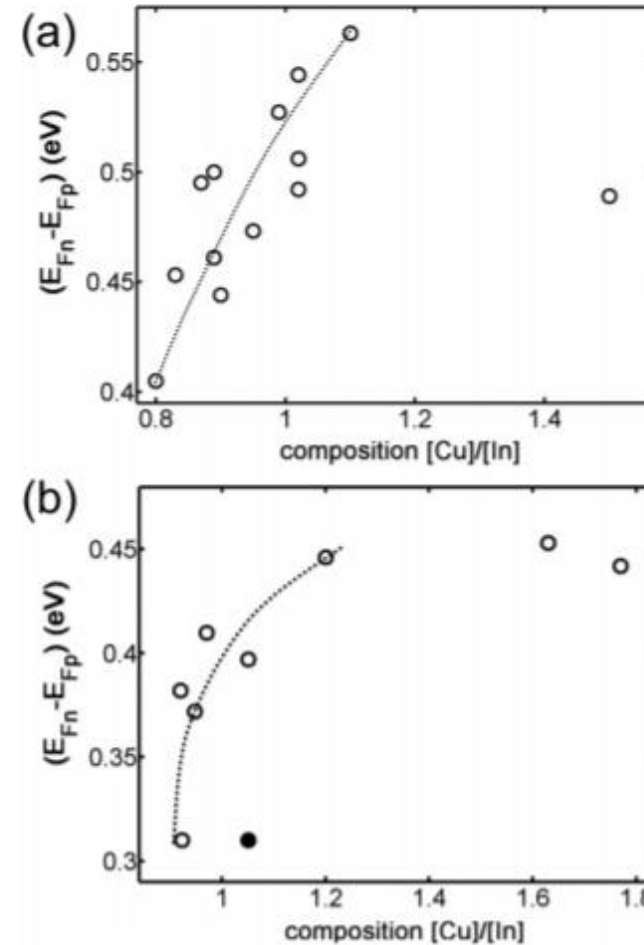


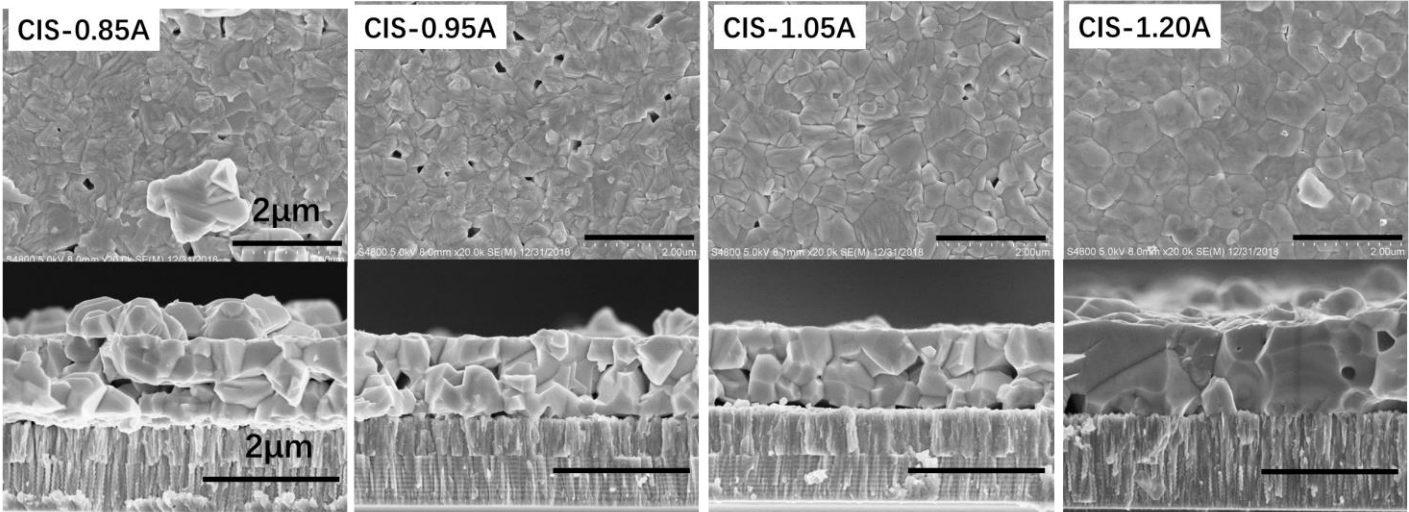
FIG. 1. Splitting of the quasi-Fermi levels as a function of the composition for the epitaxial (a) and the polycrystalline (b) sample series; the lines are a guide to the eye.

S. Siebentritt. et al, *Sol. Energy Mater. Sol. Cells*, 2013.

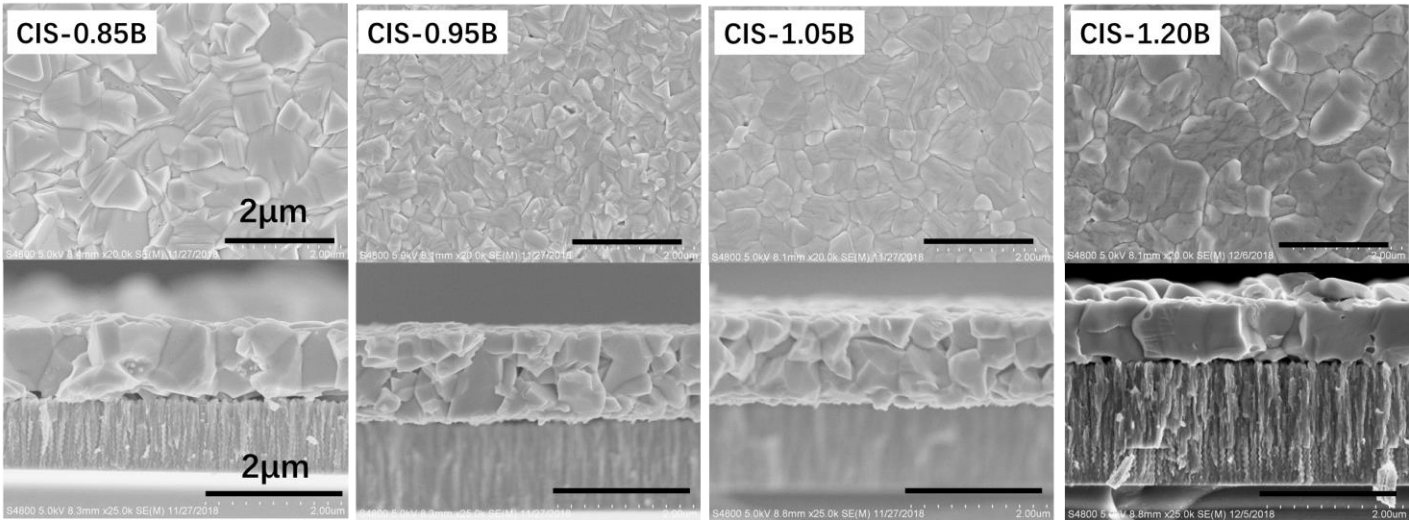


# 薄膜形貌表征

$\Delta P=0 \text{ MPa}$



$\Delta P=0.06 \text{ MPa}$



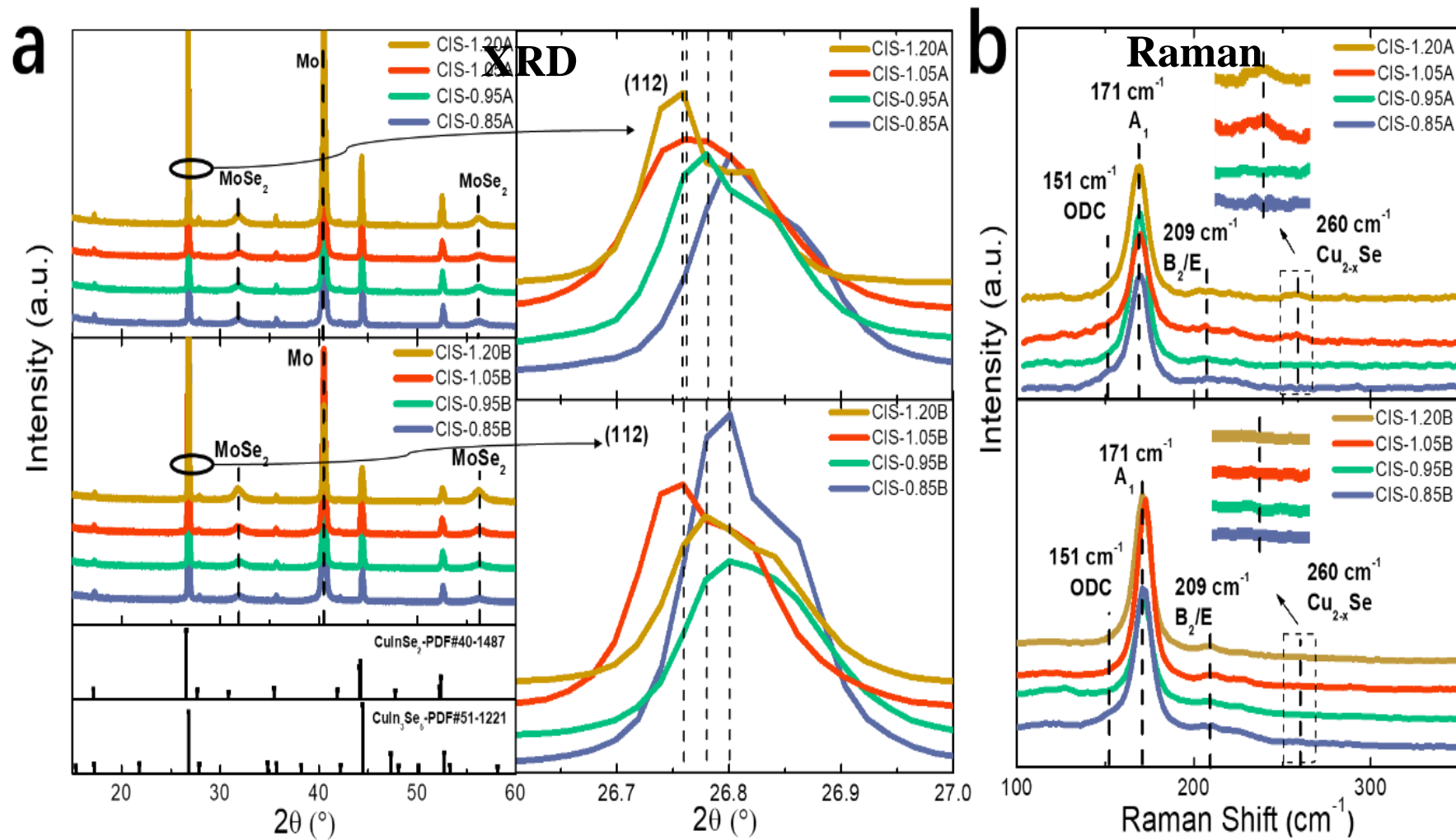
常压：晶粒排布松散

加压：晶粒排布致密

# With $(\text{NH}_4)_2\text{S}$ etching, $\text{Cu}_{2-x}\text{Se}$ on surface can be removed

$\Delta P=0$  MPa

$\Delta P=0.06$  MPa

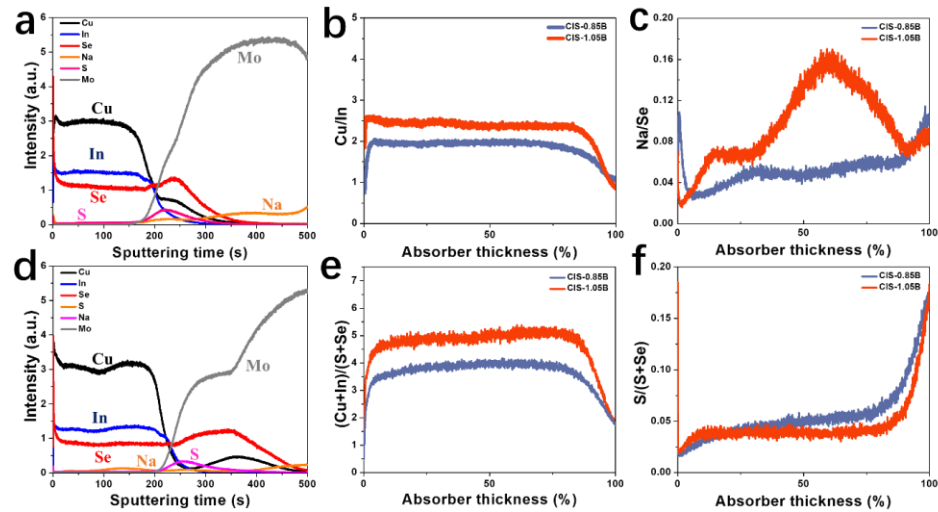


$\text{Cu}_{2-x}\text{Se}$  exists in  
Cu-rich films

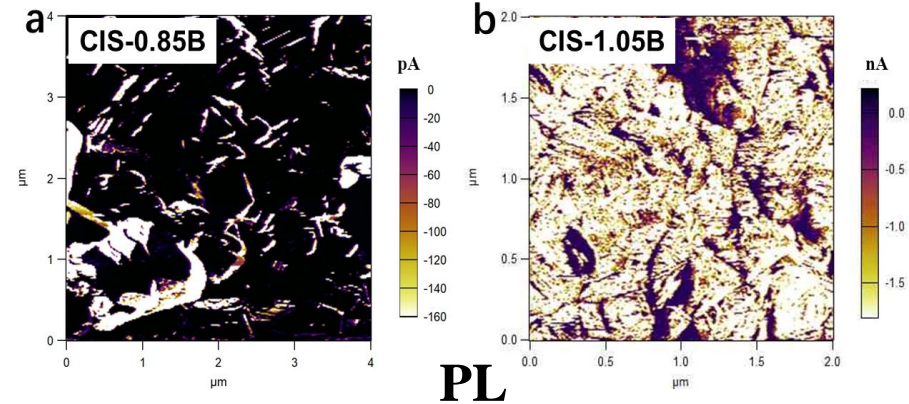
$\text{Cu}_{2-x}\text{Se}$  free

# Cu-rich CIS: Optoelectronic Properties

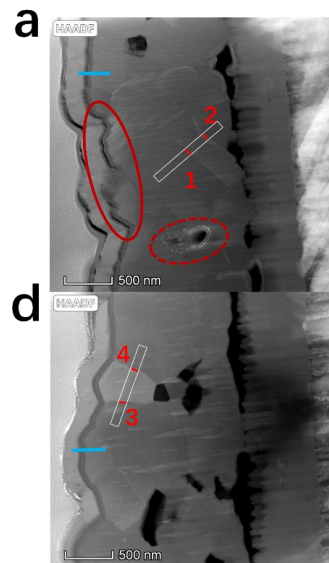
## GDEOS



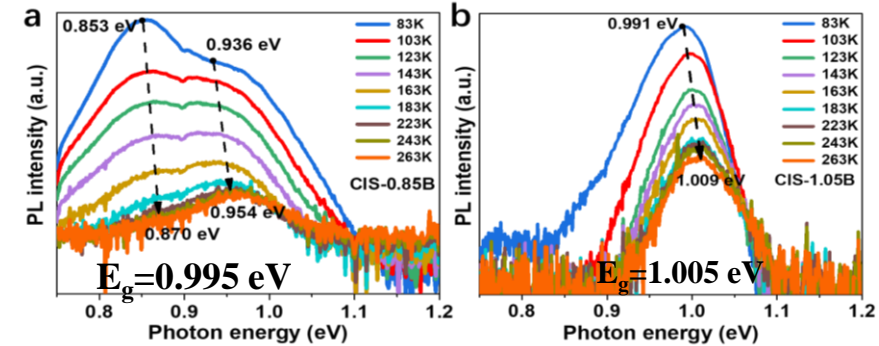
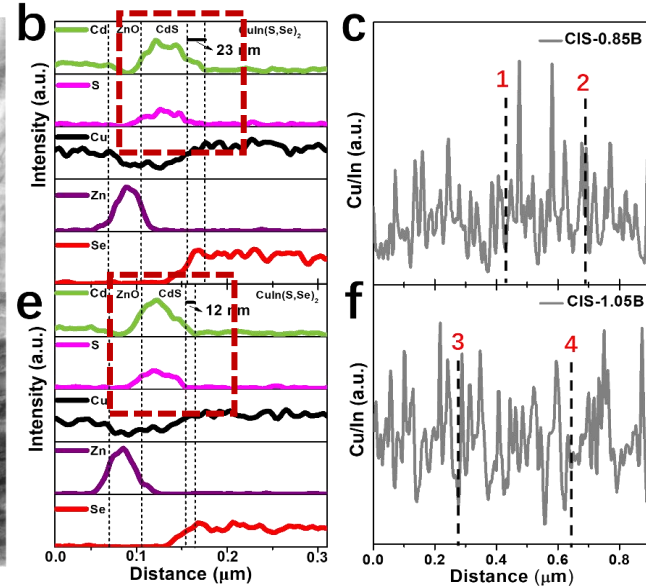
## c-AFM



## TEM

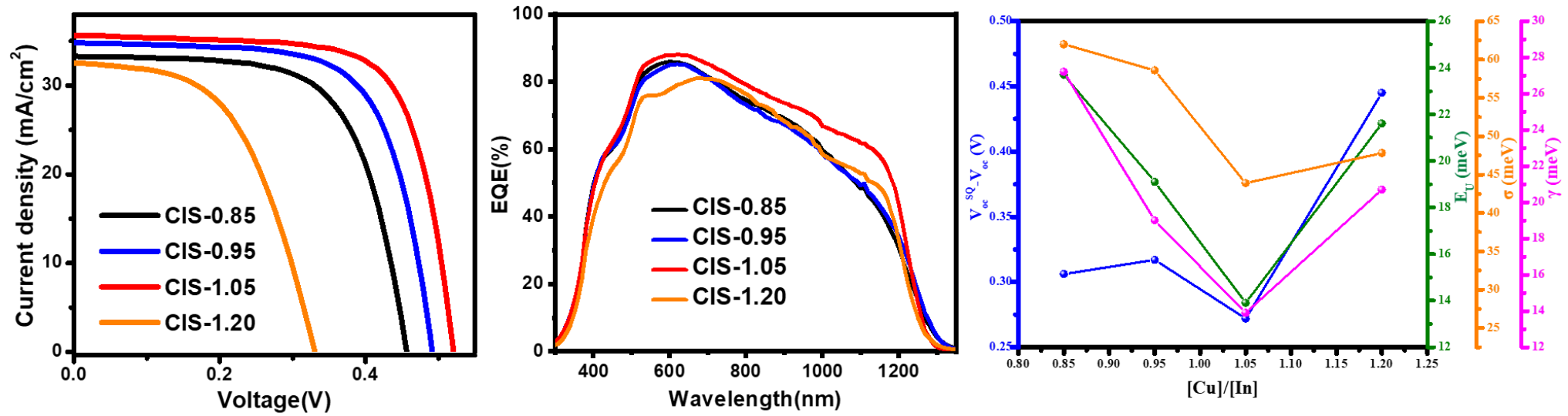


## EDX



- **Cu-rich composition**
- **Shorter Cd diffusion into absorber**
- **Epitaxial like interface**
- **Higher and more uniform conductivity**
- **Higher PL peak position**

# Cu-rich Absorber: Band Tailing



Device	Cu/In	E <sub>g</sub> (eV)	J <sub>sc</sub> (mA/cm <sup>2</sup> )	V <sub>oc</sub> (V)	FF (%)	PCE <sub>ave</sub>	PCE <sub>max</sub>	E <sub>U</sub> (meV)	σ <sub>g</sub> (meV)	Γ <sub>opt</sub> (meV)	J <sub>0</sub> (mA·cm <sup>-2</sup> )	n	R <sub>s</sub> (Ω cm <sup>2</sup> )	R <sub>sh</sub> (Ω cm <sup>2</sup> )
CIS-0.85	0.85	0.995	33.46±1.33	0.453±0.002	65.27±0.64	9.89±0.34	9.96	23.7	62.0	27.2	6.57×10 <sup>-7</sup>	1.58	1.7±0.1	458±274
CIS-0.95	0.95	0.998	34.07±1.78	0.477±0.013	65.56±2.17	10.65±0.60	11.66	19.1	58.6	19.0	1.76×10 <sup>-7</sup>	1.41	1.7±0.1	1357±236
CIS-1.05	1.05	1.005	34.66±1.46	0.516±0.004	70.50±0.60	12.61±0.80	13.29	13.9	43.9	13.9	5.61×10 <sup>-8</sup>	1.44	1.5±0.1	869±386
CIS-1.20	1.06	1.011	29.42±2.33	0.324±0.008	51.06±1.98	4.87±0.59	5.62	21.6	47.8	20.7	8.63×10 <sup>-5</sup>	1.60	3.1±0.6	663±631

Unpublished data.

# Champion Cu-rich CIS/CIGS Device from DMF Solution

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Nanjing University of Posts & Communications  
CIGS Cell

Device ID: NUPT-1

Aug 23, 2018 13:21

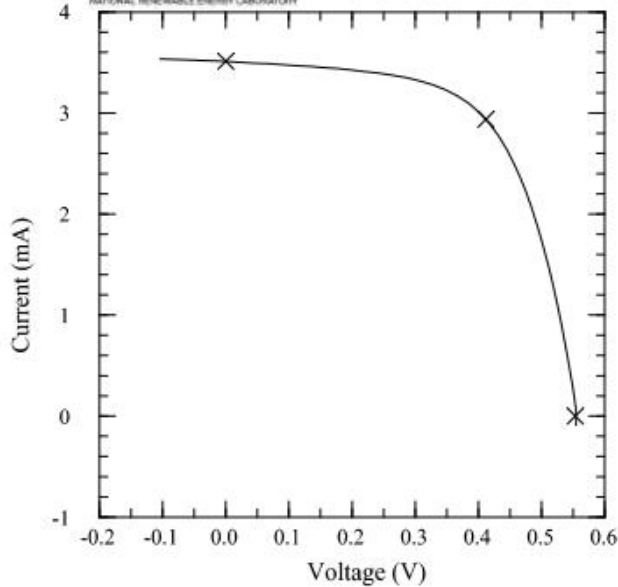
Spectrum: ASTM G173 global

Device Temperature:  $25.0 \pm 0.6$  °C

Device Area:  $0.1055 \text{ cm}^2 \pm 0.8 \%$

Irradiance:  $1000.0 \text{ W/m}^2$

**NREL** X25 IV System  
NATIONAL RENEWABLE ENERGY LABORATORY PV Performance Characterization Team



$V_{oc} = 0.55342 \pm 0.00094 \text{ V}$

$I_{sc} = 3.511 \pm 0.022 \text{ mA}$

$J_{sc} = 33.29 \pm 0.34 \text{ mA/cm}^2$

Fill Factor =  $62.24 \pm 0.22 \%$

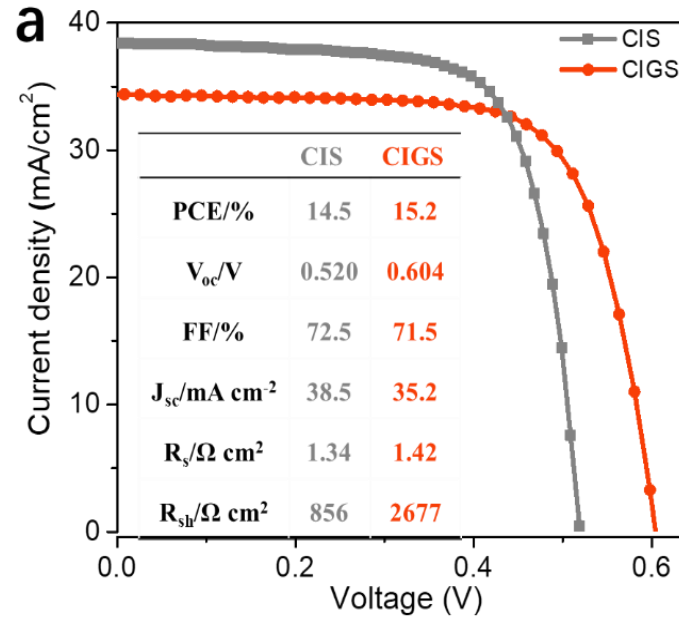
$I_{max} = 2.937 \pm 0.018 \text{ mA}$

$V_{max} = 0.411821 \pm 0.000058 \text{ V}$

$P_{max} = 1.2095 \pm 0.0075 \text{ mW}$

**Efficiency =  $11.47 \pm 0.12 \%$**

10 min light soak; 5 min cool down



**PCE=14.5%**

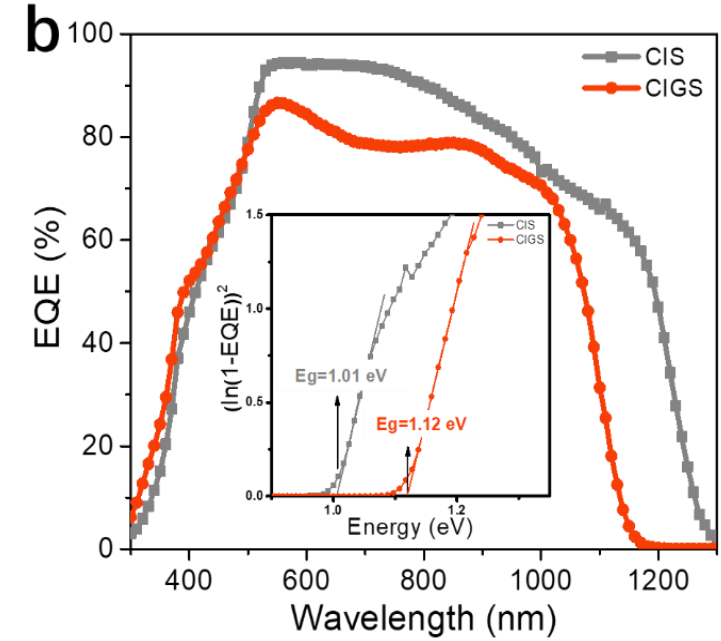
**$V_{oc}=520 \text{ mV}$**

**$J_{sc}=38.5 \text{ mA/cm}^2$**

**FF=72.5%**

**$V_{oc,def}=0.235\text{V}$**

**$V_{oc}/V_{oc}^{SQ}=67\%$**



**PCE=15.2%**

**$V_{oc}=604 \text{ mV}$**

**$J_{sc}=35.2 \text{ mA/cm}^2$**

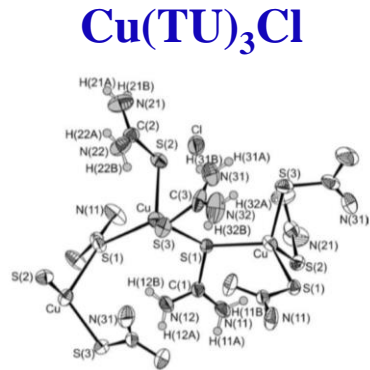
**FF=71.51%**

**$V_{oc,def}=0.273 \text{ V}$**

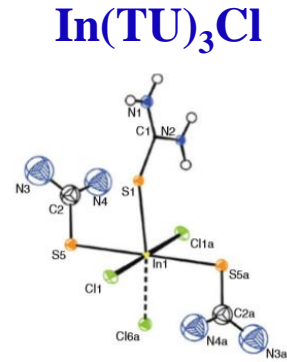
**$V_{oc}/V_{oc}^{SQ}=69\%$**

## 2.3 水溶液：配合物前驱体的使用

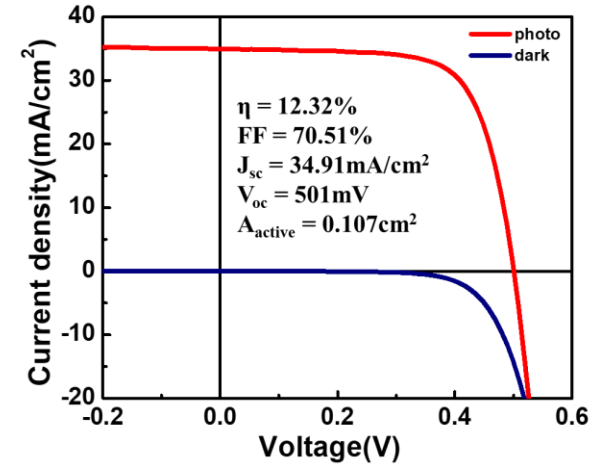
- Challenges: Hydrolysis, Impurities originating from starting materials, Oxidation



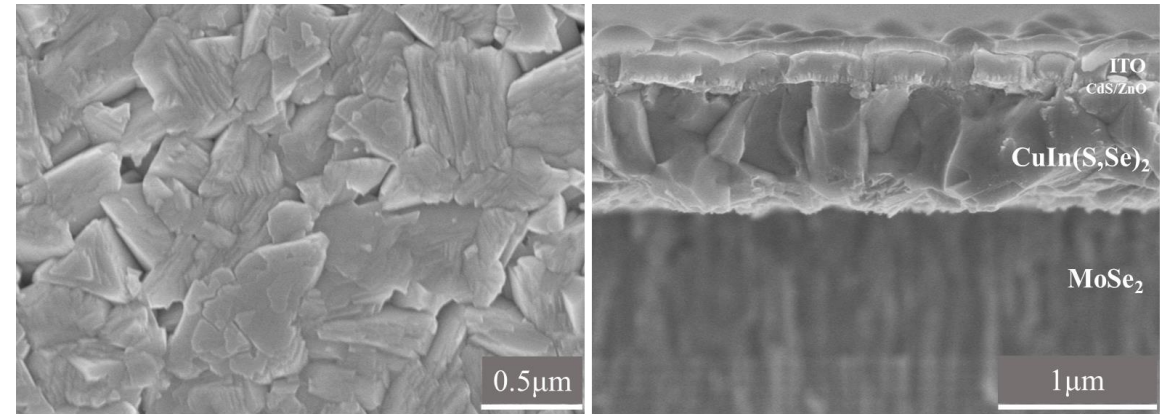
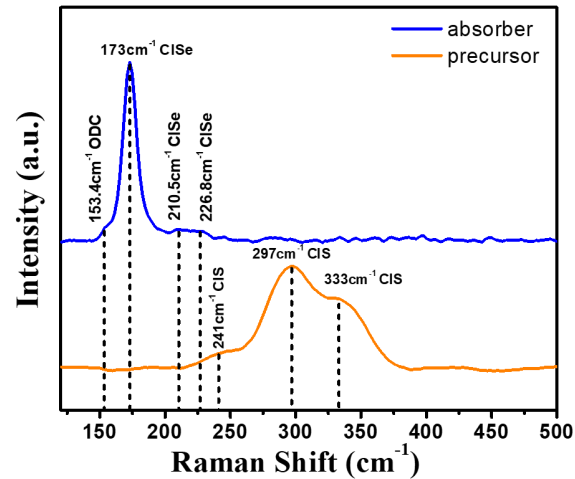
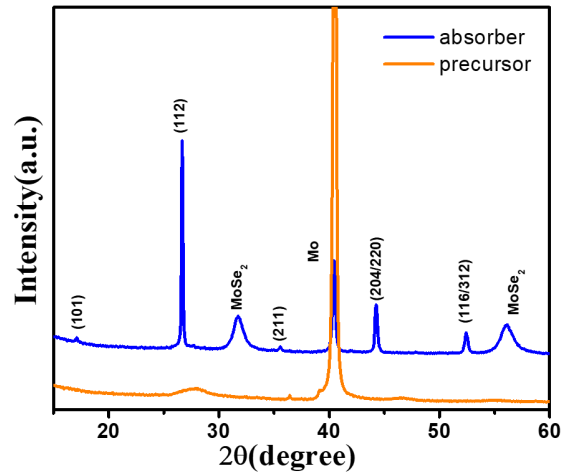
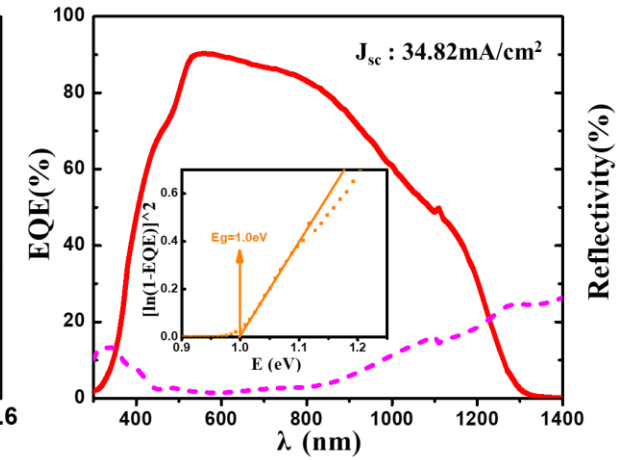
P. Bombicz et al. Inorg.Chim. Acta 357 (2004) 513.



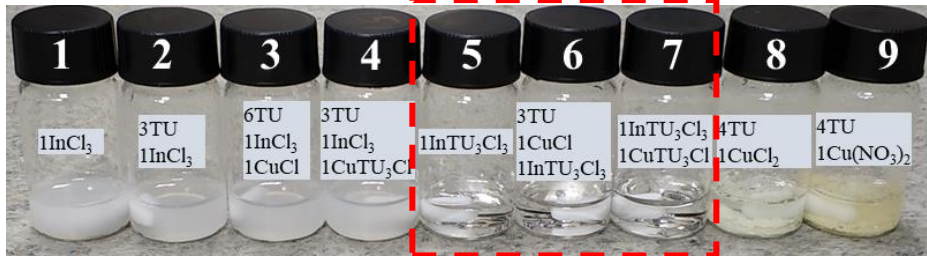
J Therm Anal Calorim (2011) 83.



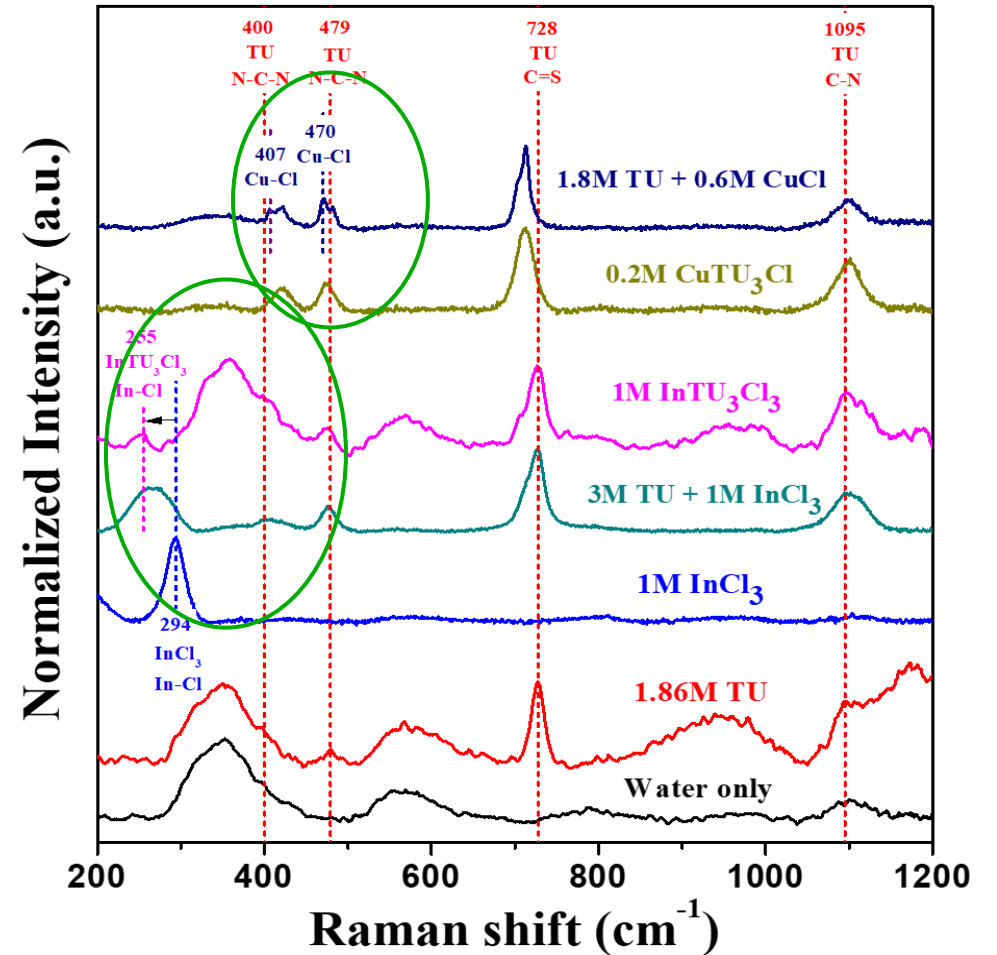
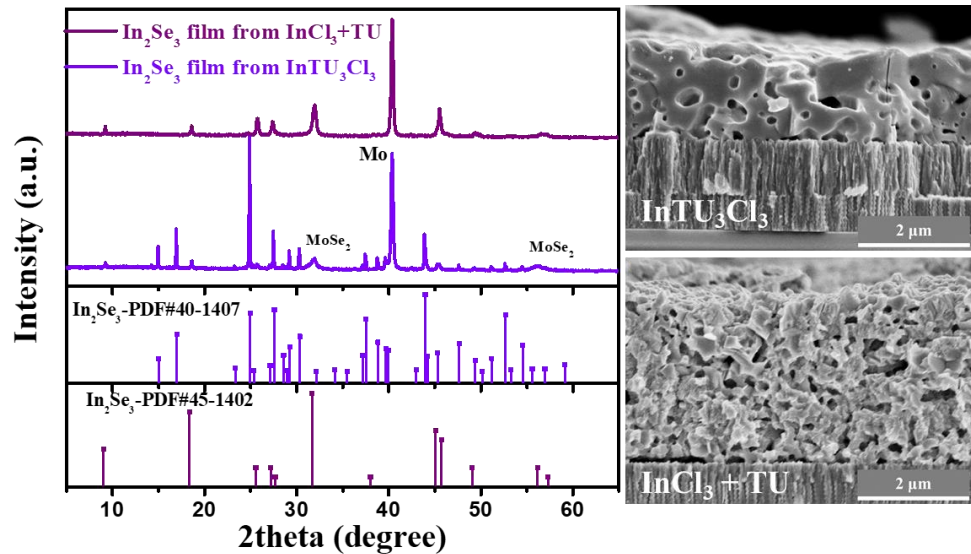
12.3% CIS



# Chemistry in Aqueous Solution

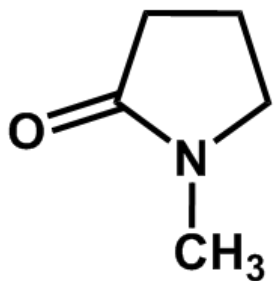


All the solutions prepared by mixing TU and  $\text{InCl}_3$  became unclear.

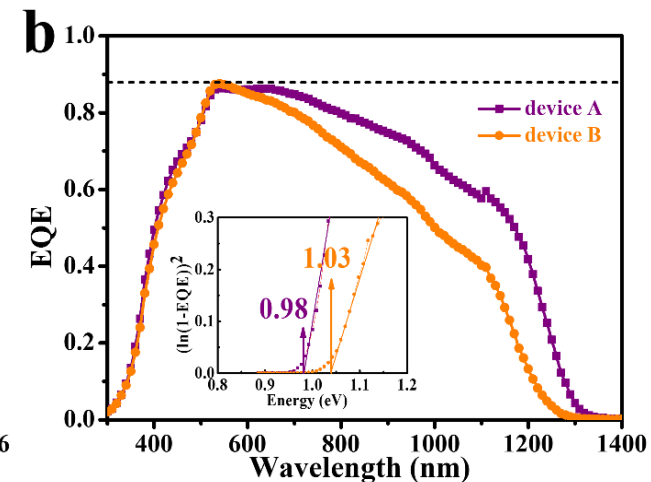
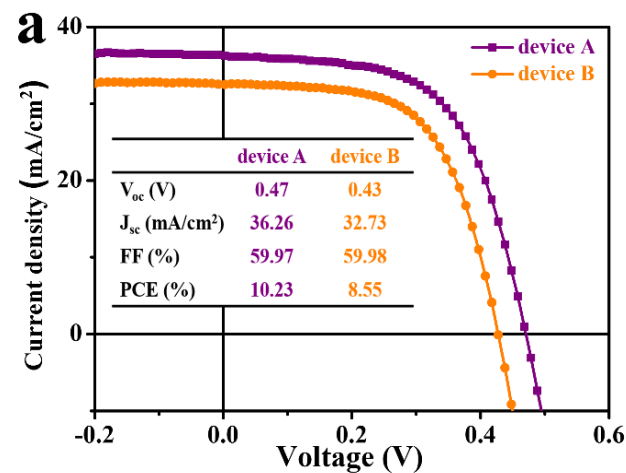
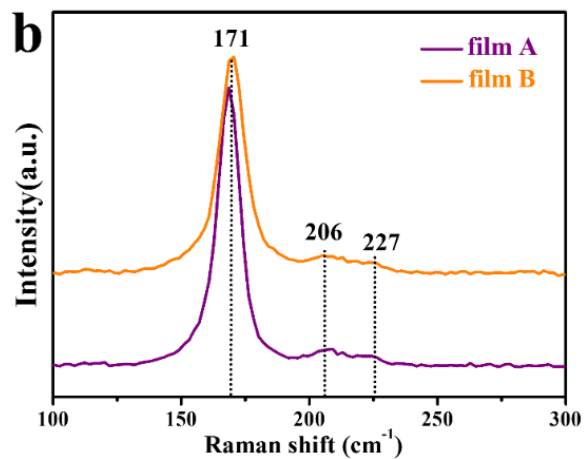
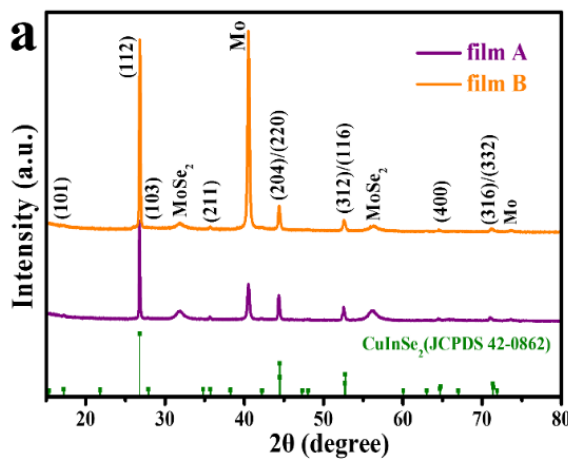
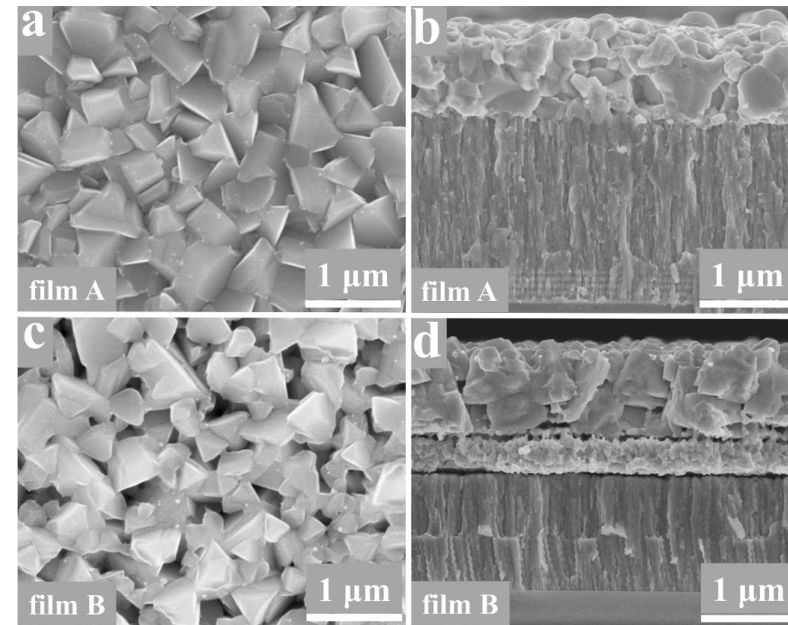
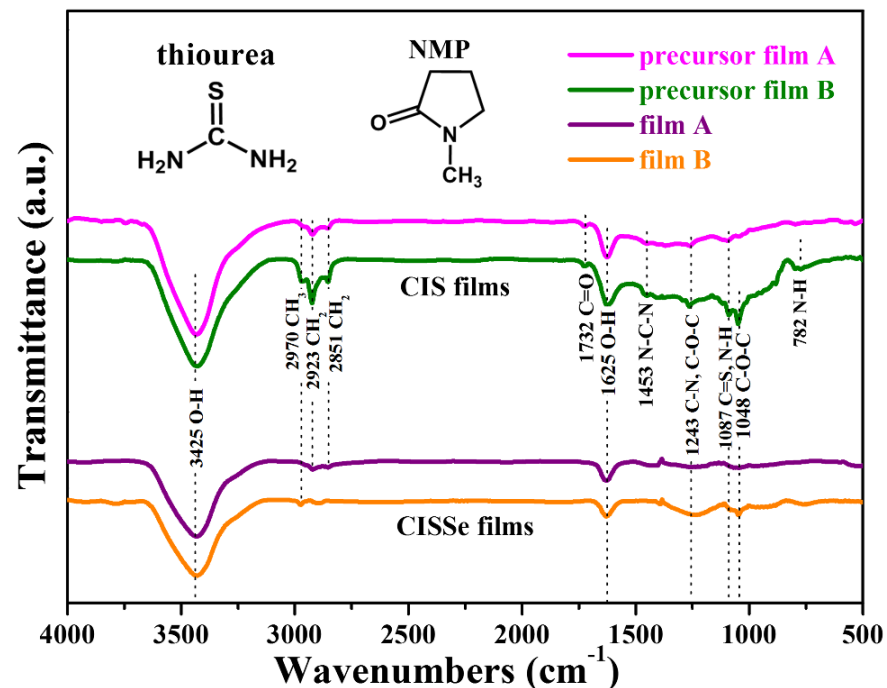


**The direct bonding of all metal ions with sulfur in the precursor solution is the key for high quality absorber film.**

## 2.3 NMP溶液：空气与惰性氛围退火



- 安全、低毒、环境友好
- 来源广、成本低
- 各行业广泛应用
- 溶液稳定，可长期保存
- 在薄膜中残留较少或无残留





# Vacuum Based CIGS: Grain Growth Mechanism

## Three-step evaporation: liquid $\text{Cu}_{2-x}\text{S}$ assisted grain growth

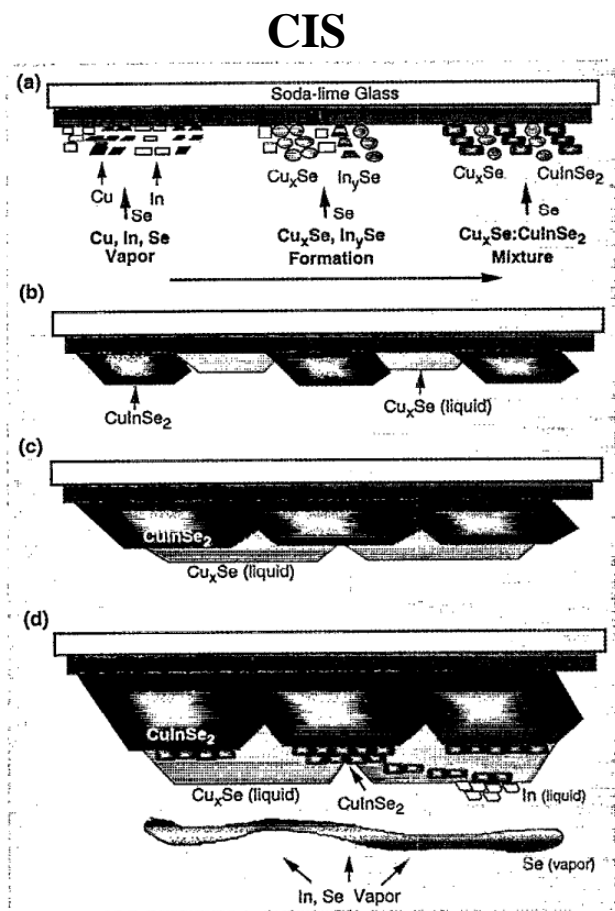
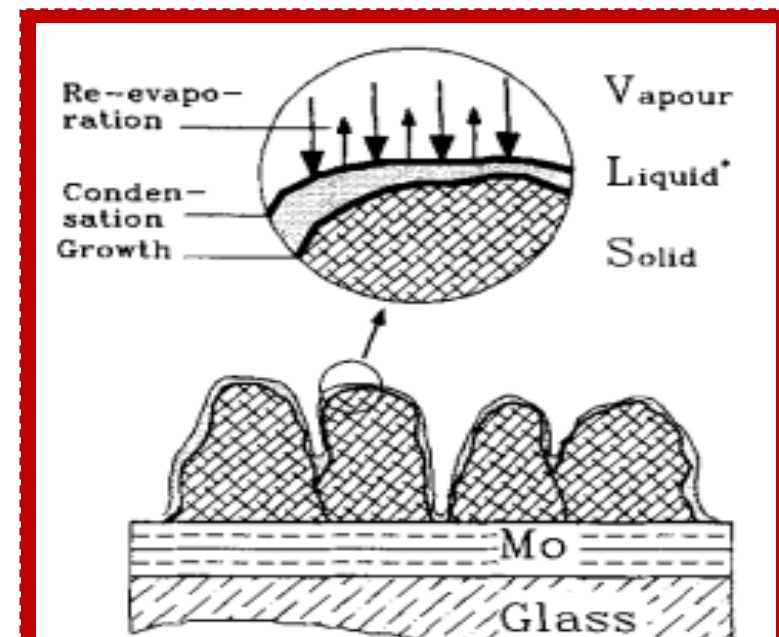


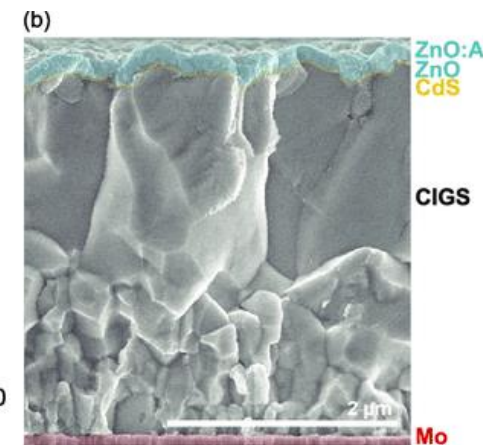
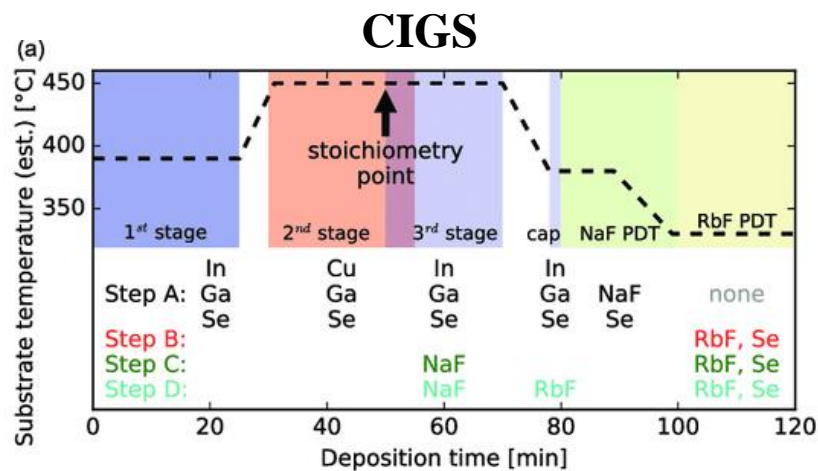
FIG. 11. Pictorial representation of thin-film  $\text{CuInSe}_2$  growth model: (a) Initial atomistic accommodation, reaction, and nucleation, (b)  $\text{CuInSe}_2$  and  $\text{Cu}_x\text{Se}$  island formation, (3)  $\text{CuInSe}_2$  coalescence with vertical phase separation, and (4)  $\text{Cu}_x\text{Se}$  conversion and local epitaxial growth.



**Large grain**  
**Cu-poor composition**  
**KCN etching**



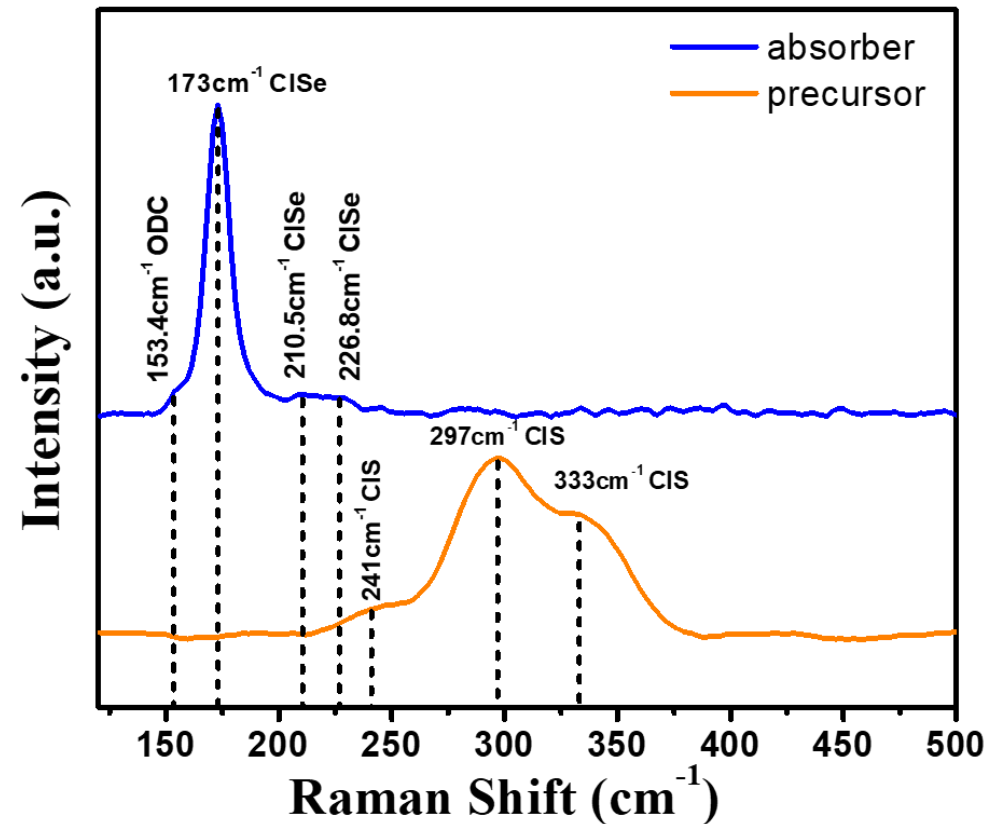
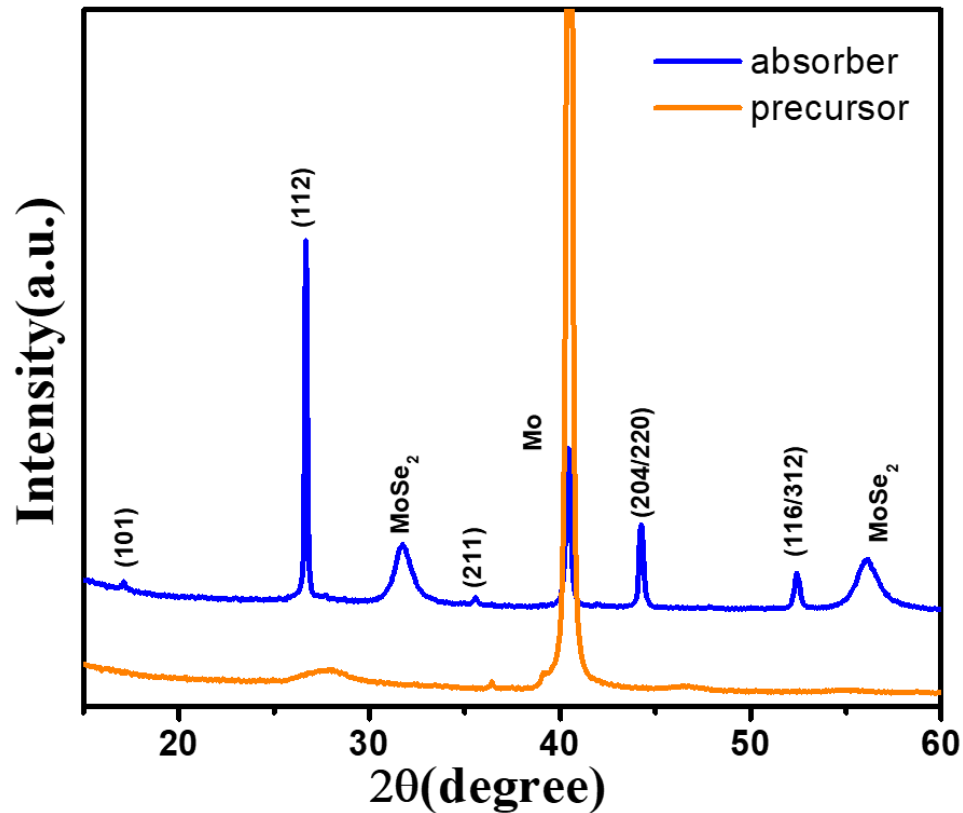
R. Klenk, et al., *Adv. Mater.*, 1993, 5, 114.



R. Carron, *Adv. Energy Mater.* 2019, 9, 1900408.

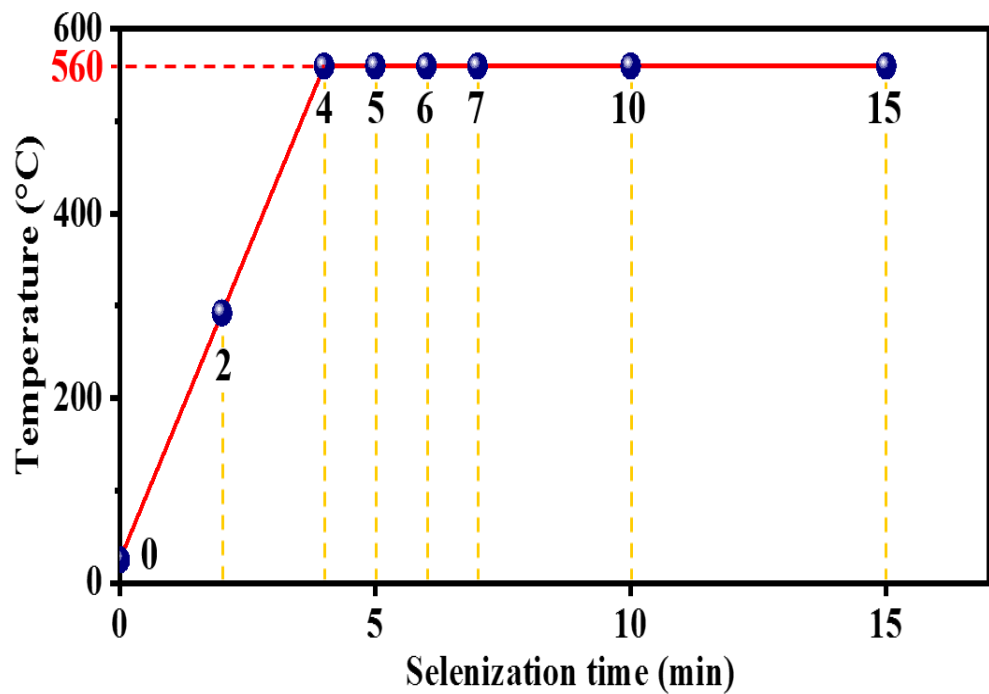
### 3. 溶液法CIS/CIGS晶粒生长机制

$\text{Cu(Tu)Cl}_3 + \text{In(TU)}_3\text{Cl} \rightarrow \text{CuInS}_2$  (precursor film)  
Cu-rich absorber (CGI = ~1) better performance

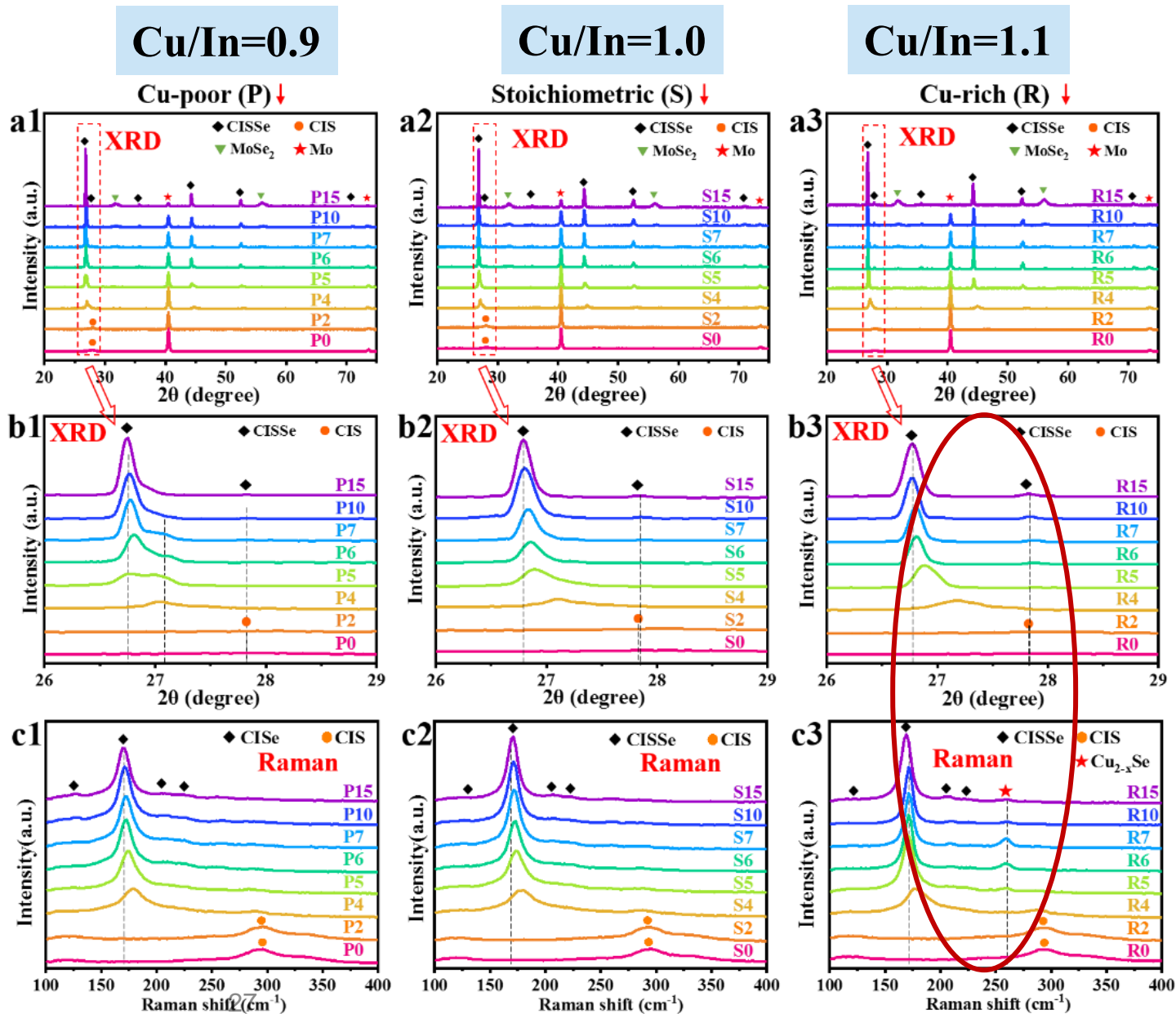


# Grain Growth of Solution Processed CIS absorber

## Selenization profile

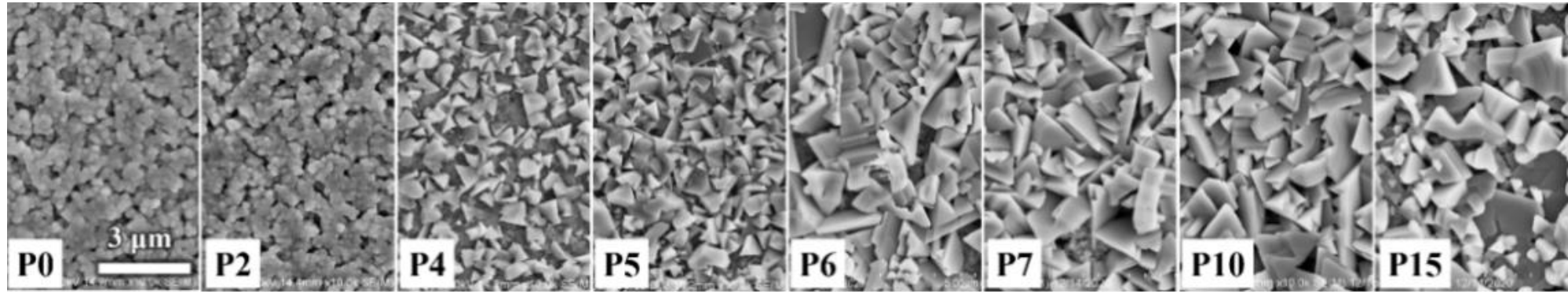


- $\text{CuInS}_2 + \text{Se} \rightarrow \text{CuIn}(\text{S,Se})_2$
- 贫铜、化学计量比均无  $\text{Cu}_{2-x}\text{Se}$
- 富铜存在  $\text{Cu}_{2-x}\text{Se}$

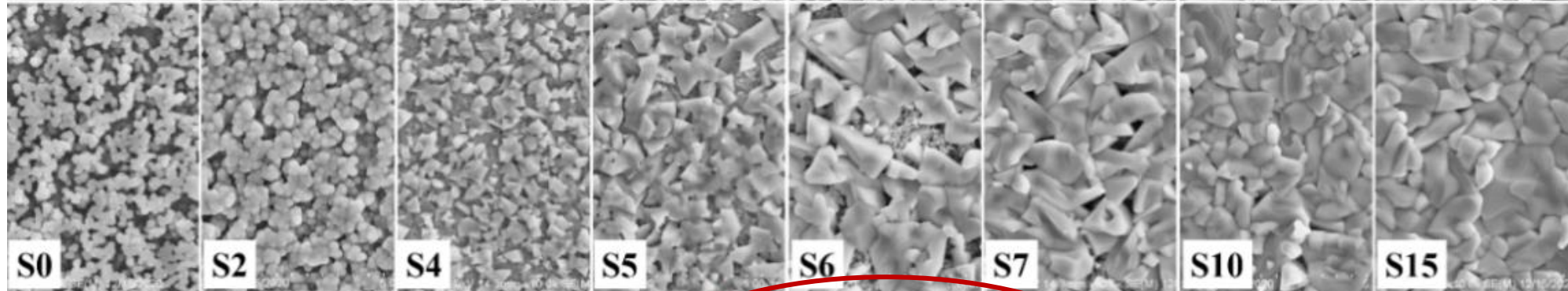


# Grain Growth of Solution Processed CIS absorber

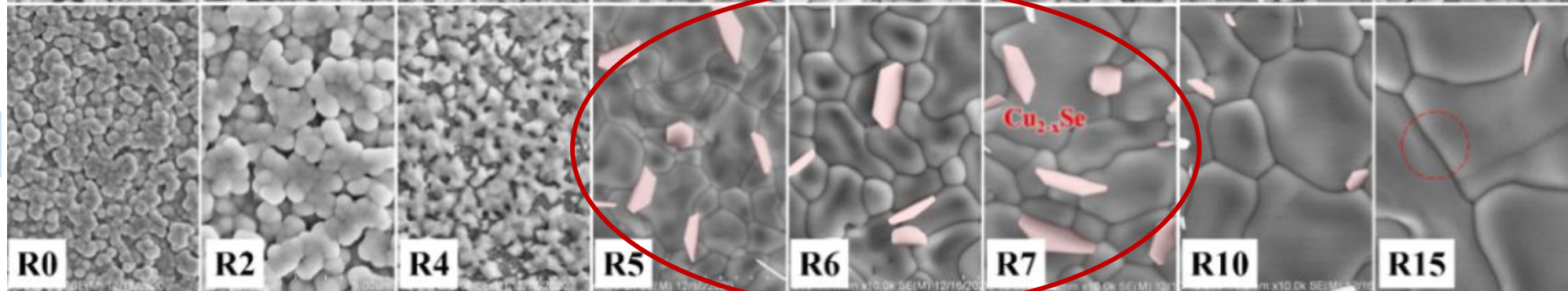
Cu/In=0.9



Cu/In=1.0

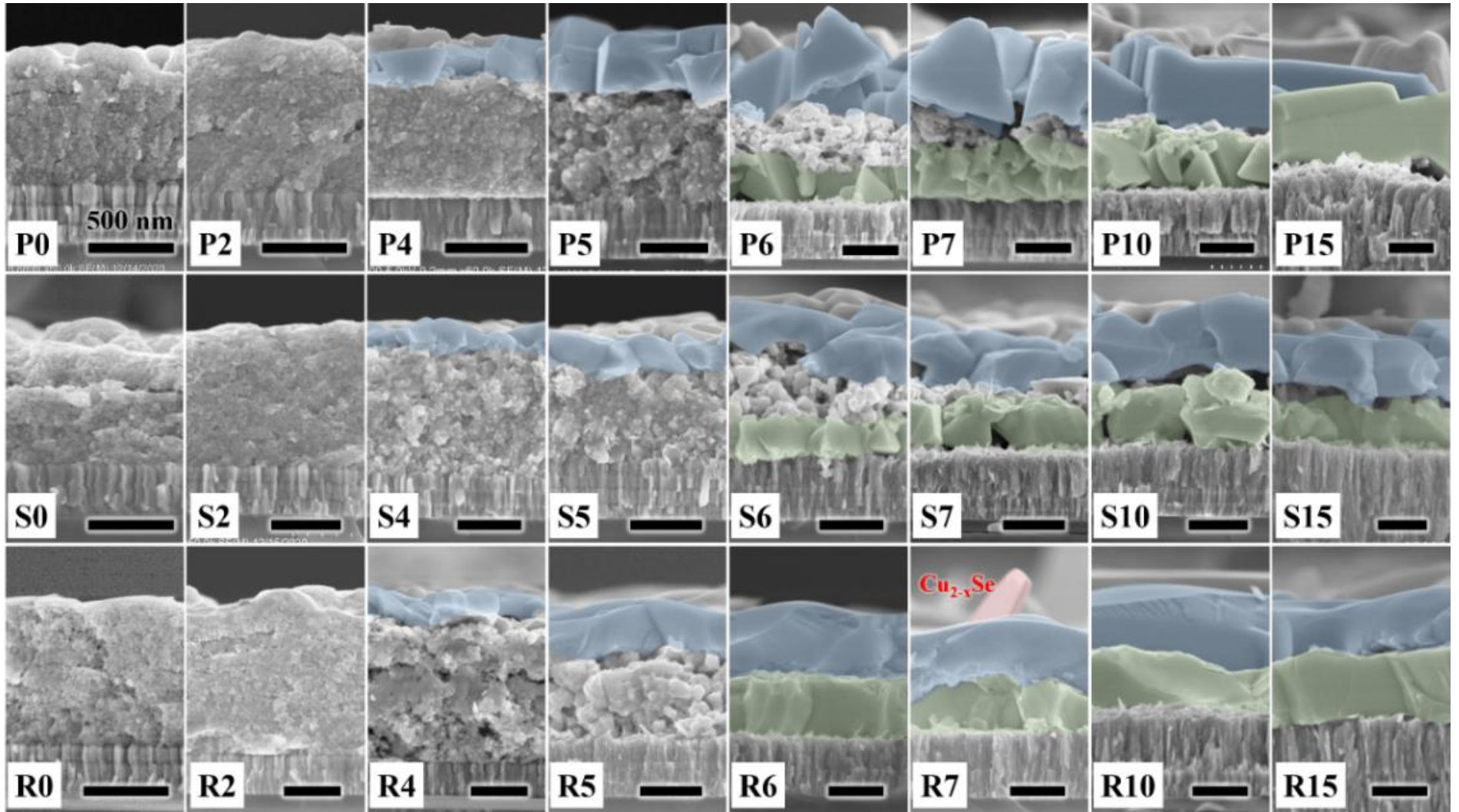


Cu/In=1.1



# Grain Growth of Solution Processed CIS absorber

Cu/In=0.9



Cu/In=1.0

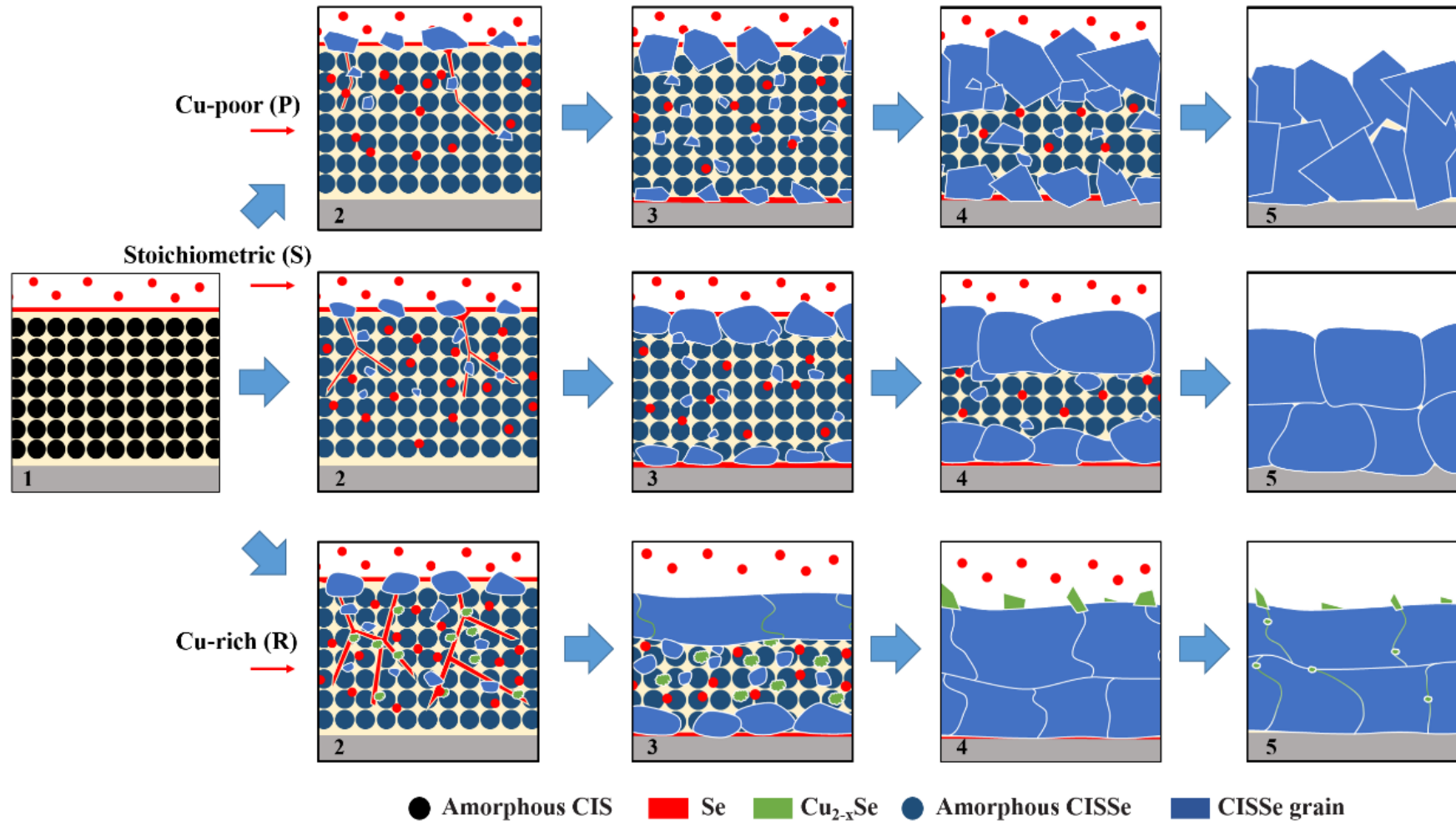
Cu/In=1.1

➤ 双向生长（双层结构）；

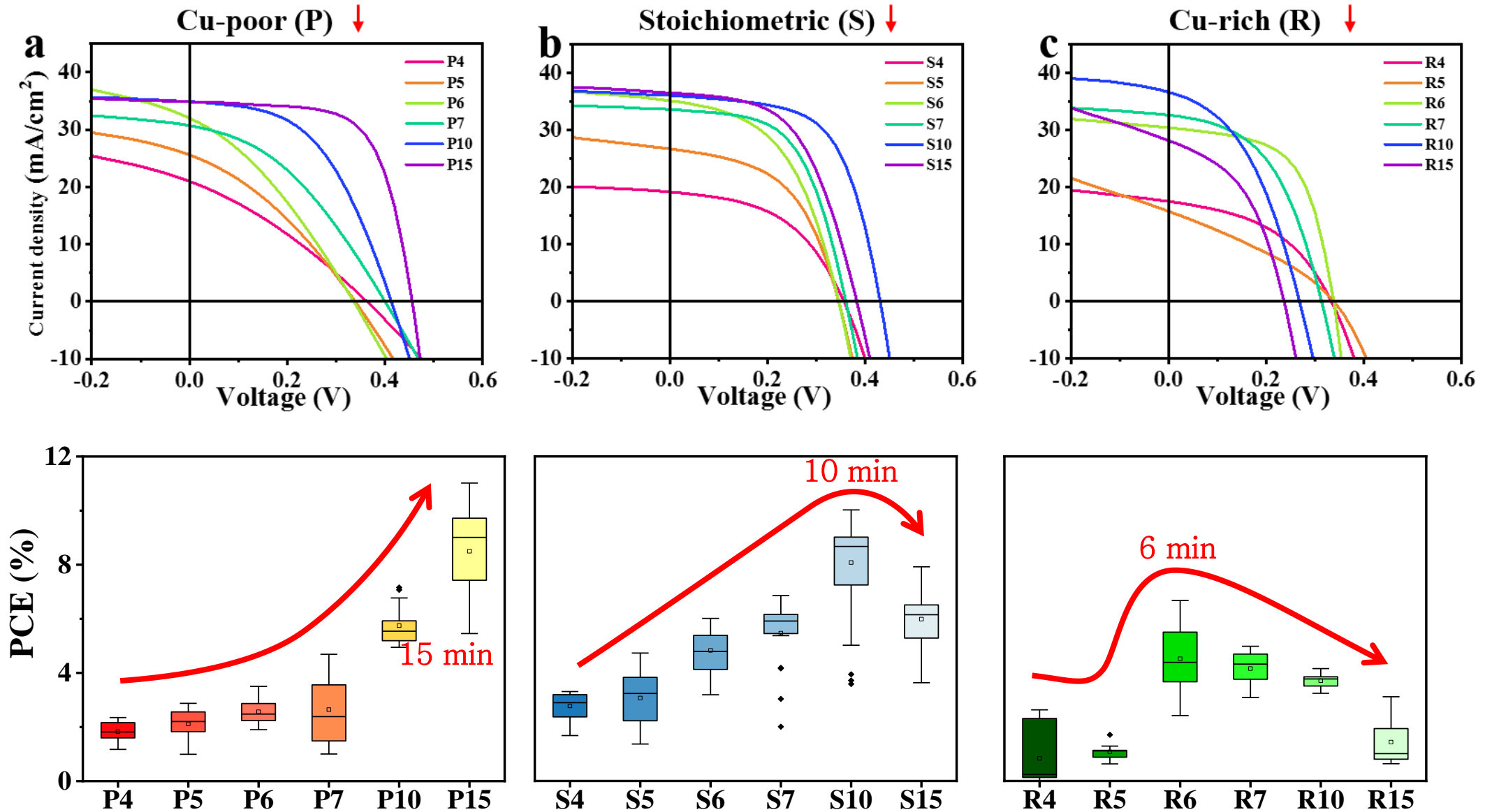
➤ 薄膜生长速度：富铜 > 化学计量比 > 贫铜。

# Grain Growth of Solution Processed CIS absorber

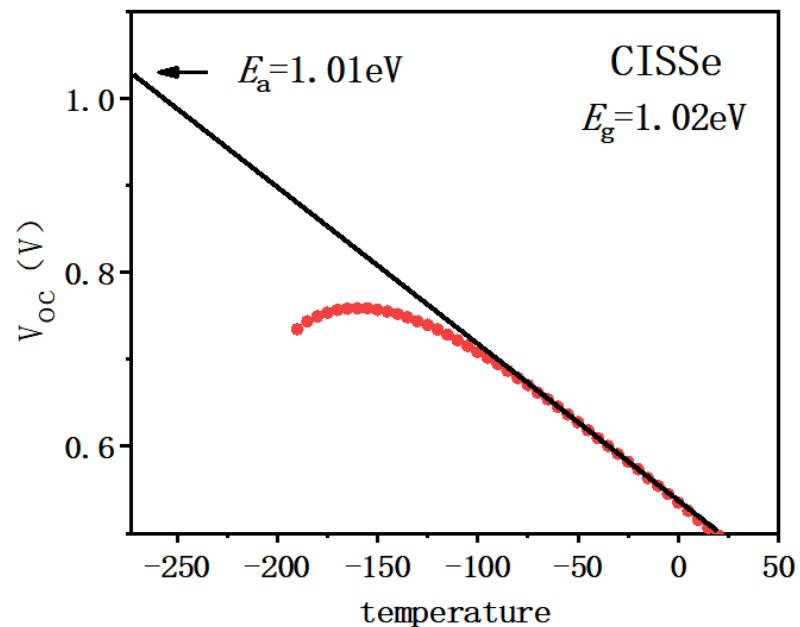
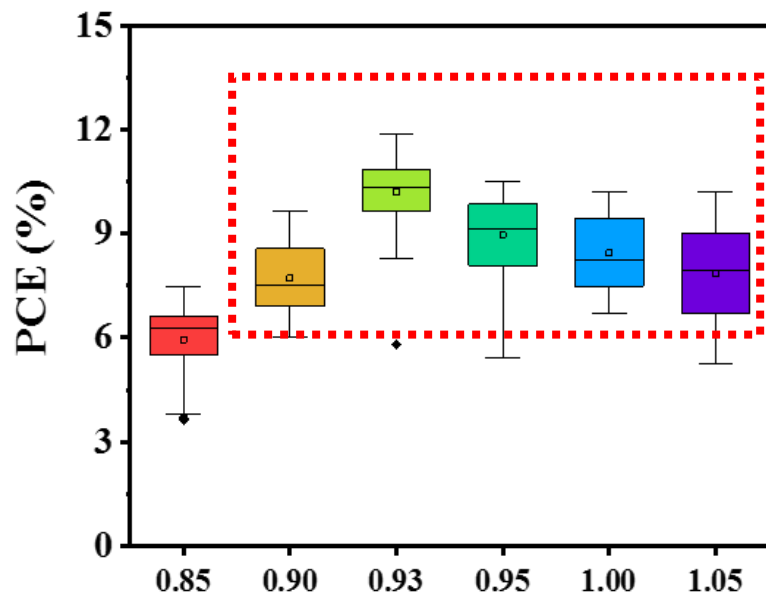
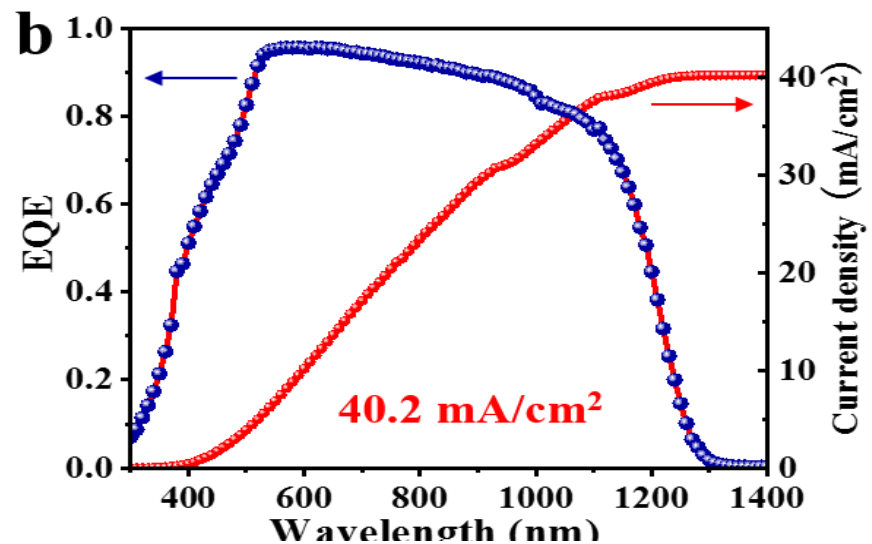
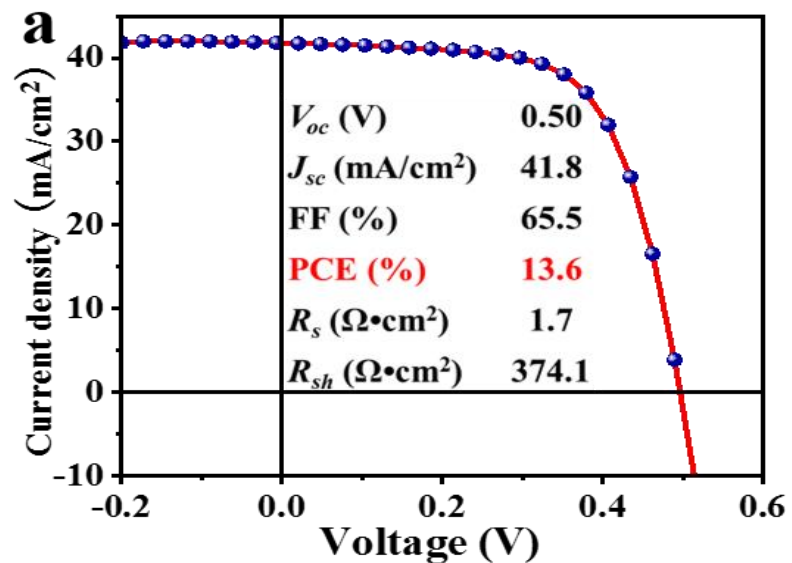
Direct phase transformation grain growth:  $\text{CuInS}_2 + \text{Se} \rightarrow \text{CuIn}(\text{S}, \text{Se})_2$



# Device Performance: the Effect of Cu/In Ratios



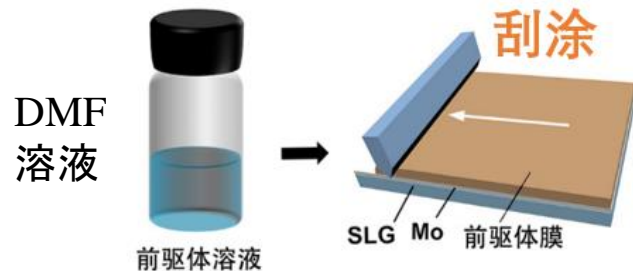
# High Tolerance to Composition Near Stoichiometry



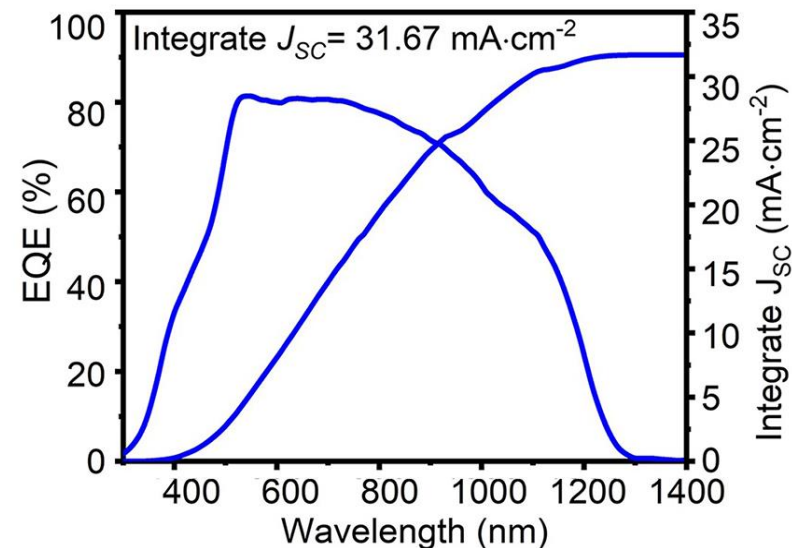
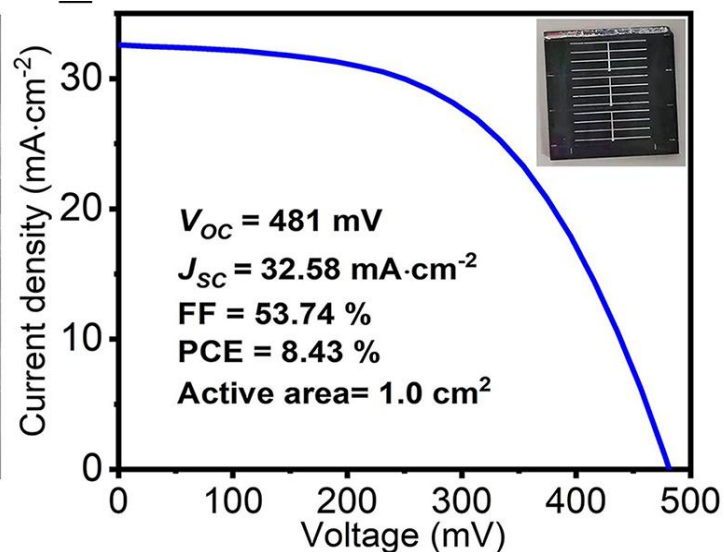
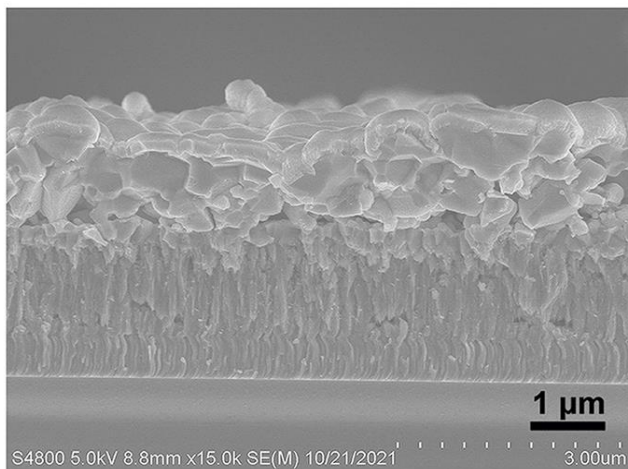
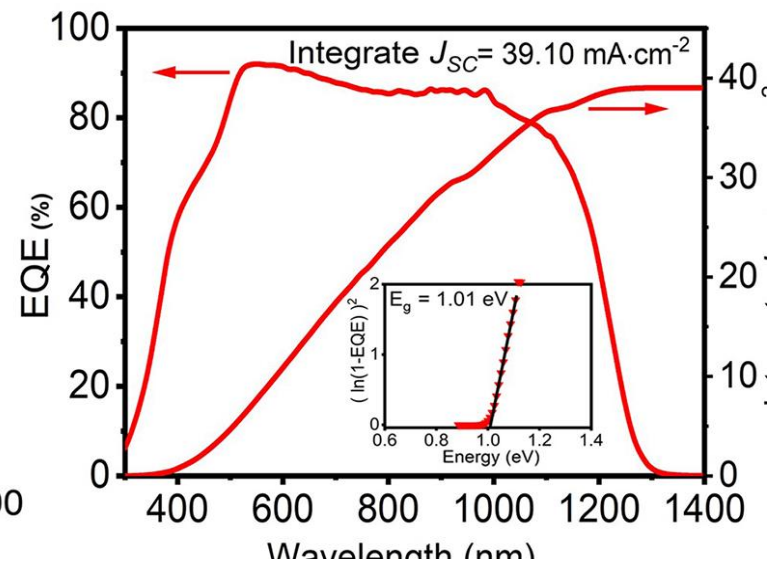
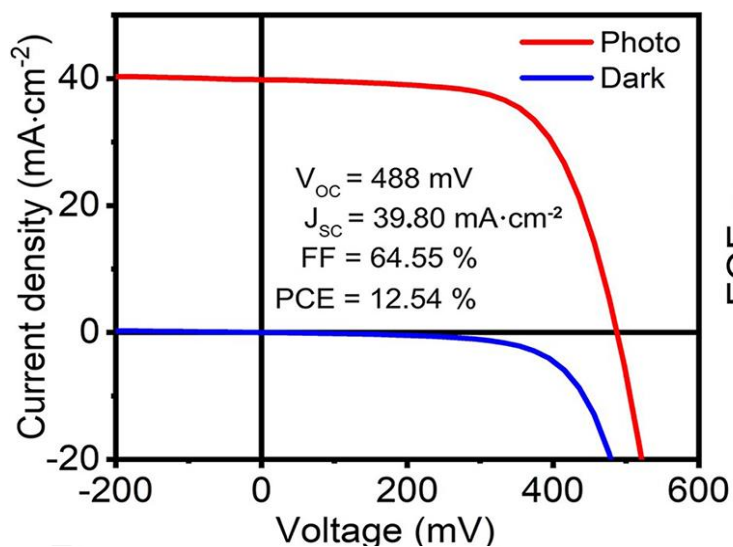
直接相变机制：组分有较宽的缓冲范围



# CIS Solar Cell via Doctor-blading



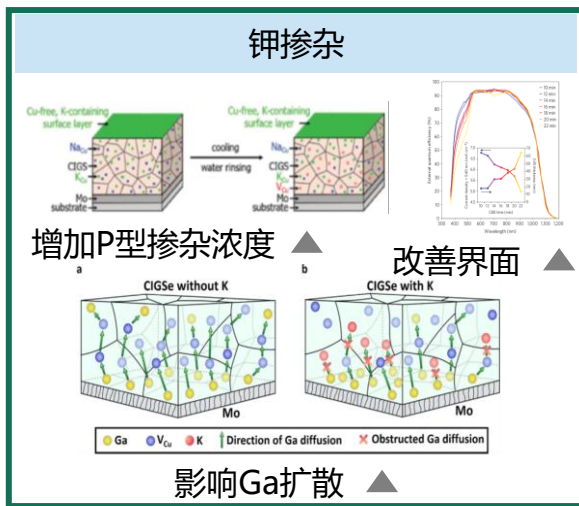
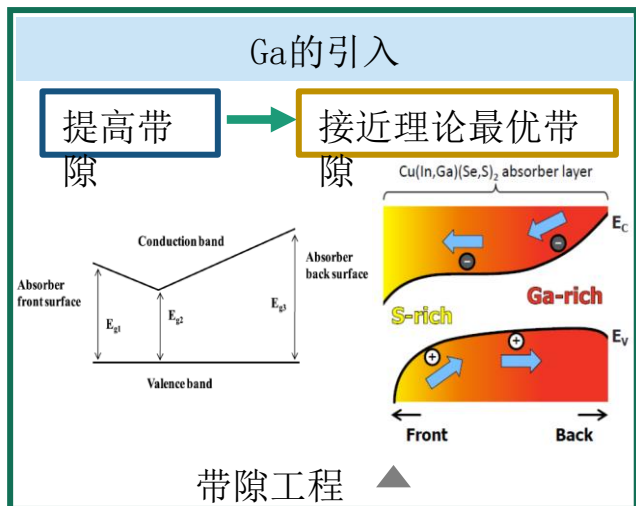
$C_{\text{Cu+In}} = 0.9/1.3/1.7 \text{ mol/L}$



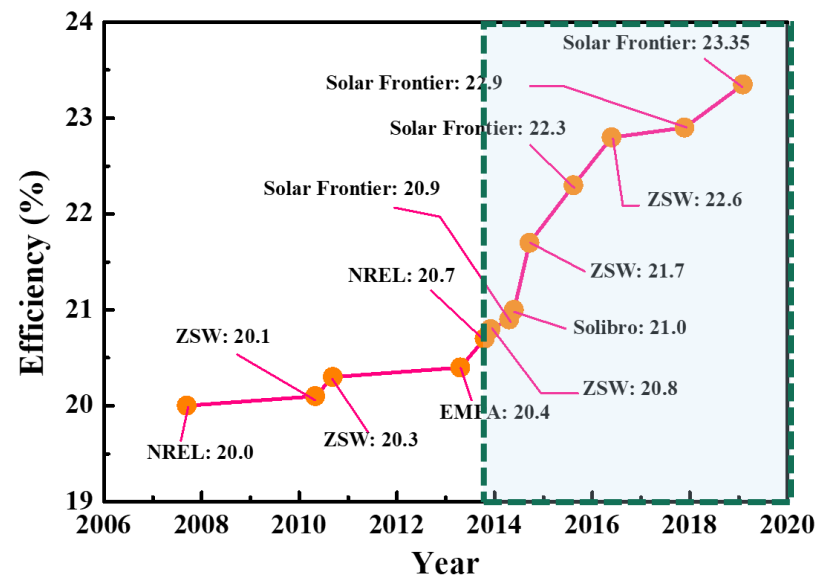
器件的效率: 12.54% ( $0.1 \text{ cm}^2$ ), 8.43% ( $1 \text{ cm}^2$ )

# 4. 总结与展望

- 前驱体溶液路径直接生成黄铜矿结构薄膜，**直接相变薄膜生长机制**
- 实现高效富铜CIGS电池效率 (15.5%)
- 硒化条件的优化是提高溶液法CIGS电池效率关键
- 高质量体相和异质结性质 ( $n=1.44$ ,  $J_0=5.61 \times 10^{-8} \text{mA} \cdot \text{cm}^{-2}$ ,  $E_U < 14 \text{meV}$ ,  $E_a \approx E_g$ )
- **溶液法效率提高策略：背界面，组分梯度和碱金属等**



带隙工程+碱金属离子掺杂/后处理



## I. 铜铟镓硒薄膜太阳能电池

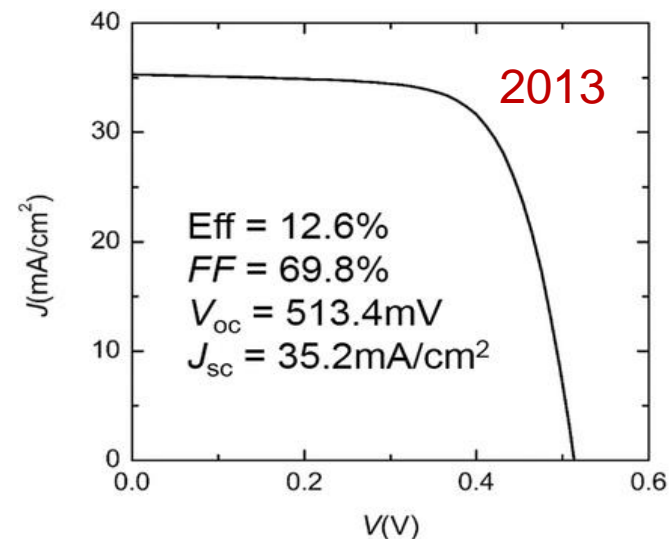
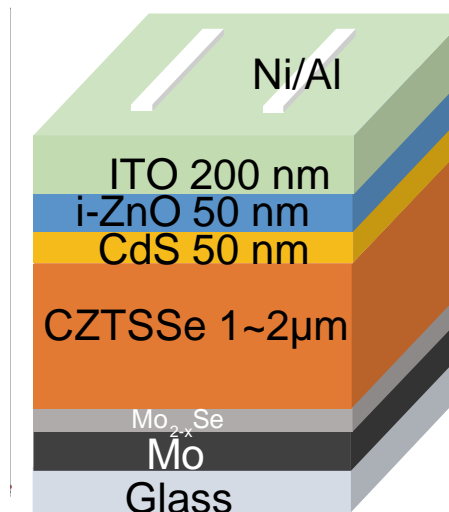
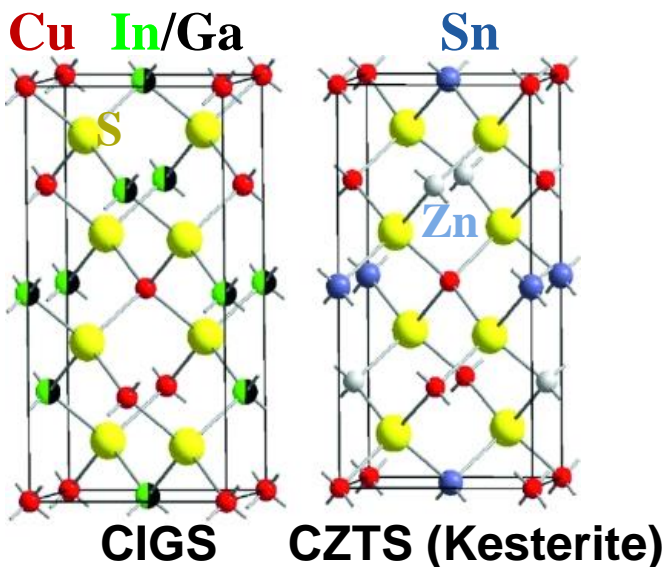
1. CIGS薄膜太阳能电池简介
2. 真空法CIGS薄膜太阳能电池
3. 溶液法CIGS薄膜太阳能电池
4. 总结与展望

## II. 铜锌锡硫薄膜太阳能电池

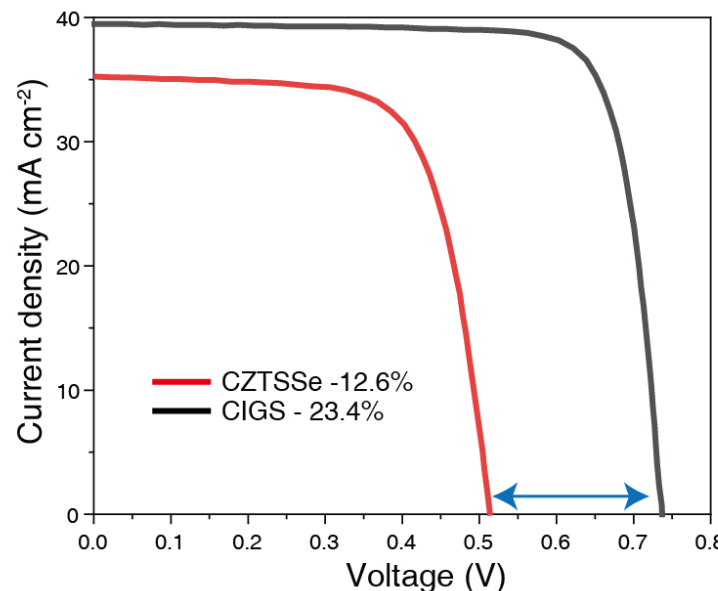
1. CZTS薄膜太阳能电池优势及挑战
2. 吸收层缺陷与调控
3. 异质结界面缺陷与调控
4. 总结与展望

## III. 致谢

# 1. CZTS的优势与挑战



- Similar crystal structure to CIGS
- High theoretical efficiency (32-33%)
- Direct band gap materials, high absorption coefficient, less materials required (0.5-2µm)
- Ideal and tunable band gap: 0.95-1.5 eV (from pure Se to pure S)
- Use earth abundant materials
- Less toxic than CdTe
- Might be the solution for low cost and green thin film PV



**Large  $V_{oc}$  deficit**

$$V_{oc,def} = V_{oc}^{SQ} - V_{oc}$$

$$\frac{V_{oc,def}}{V_{oc}^{SQ}}$$

**CZTS CIGS**

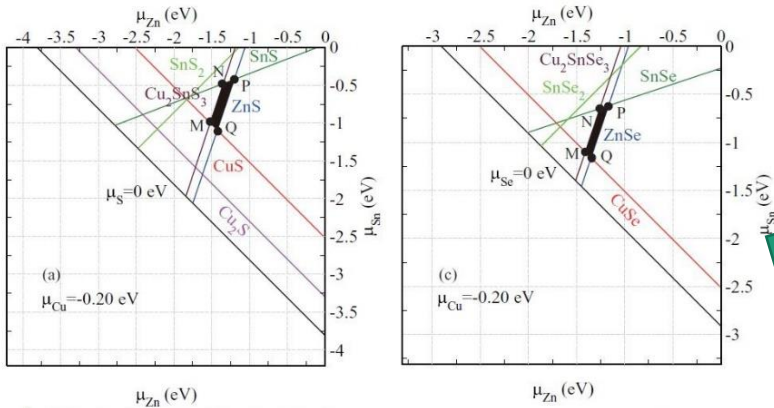
$V_{oc,def}$ : **0.373 V, 0.106 V**

$V_{oc}/V_{oc}^{SQ}$ : **0.57, 0.87**

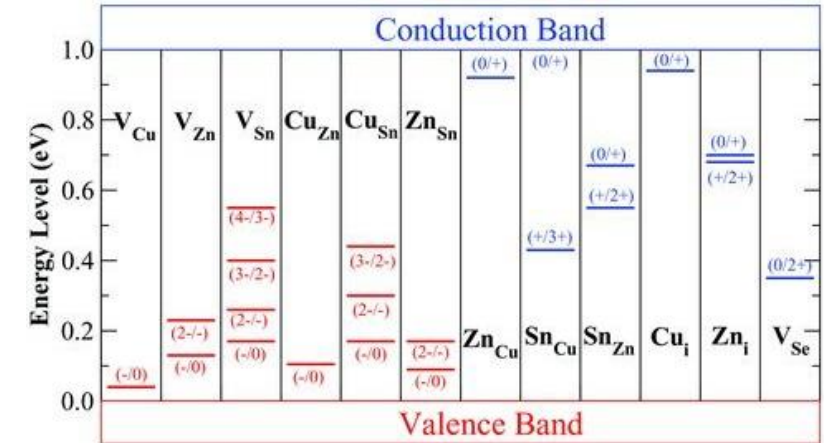
# Possible Reasons for Large $V_{oc-def}$

Absorber Fabrication  
precursor film  $\rightarrow$  absorber film

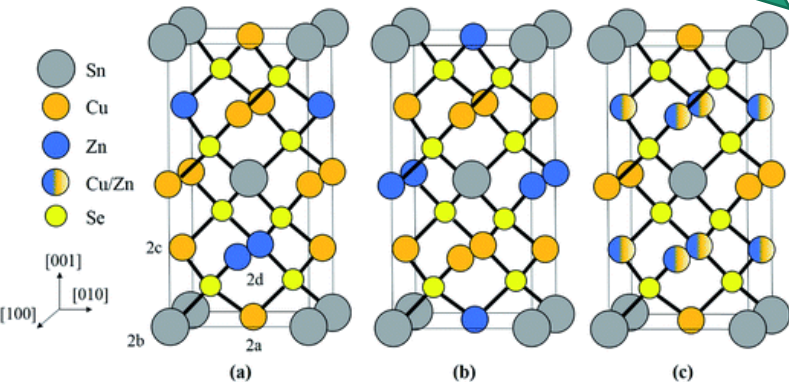
Secondary phases



Deep defects



Cu-Zn disorder

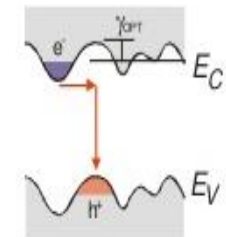
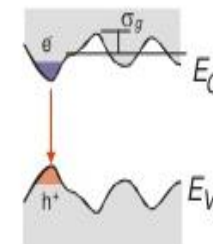


Sn: two oxidation state

Band tailing

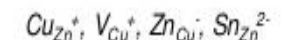
Band gap Fluctuations

Electrostatic Potential Fluctuations

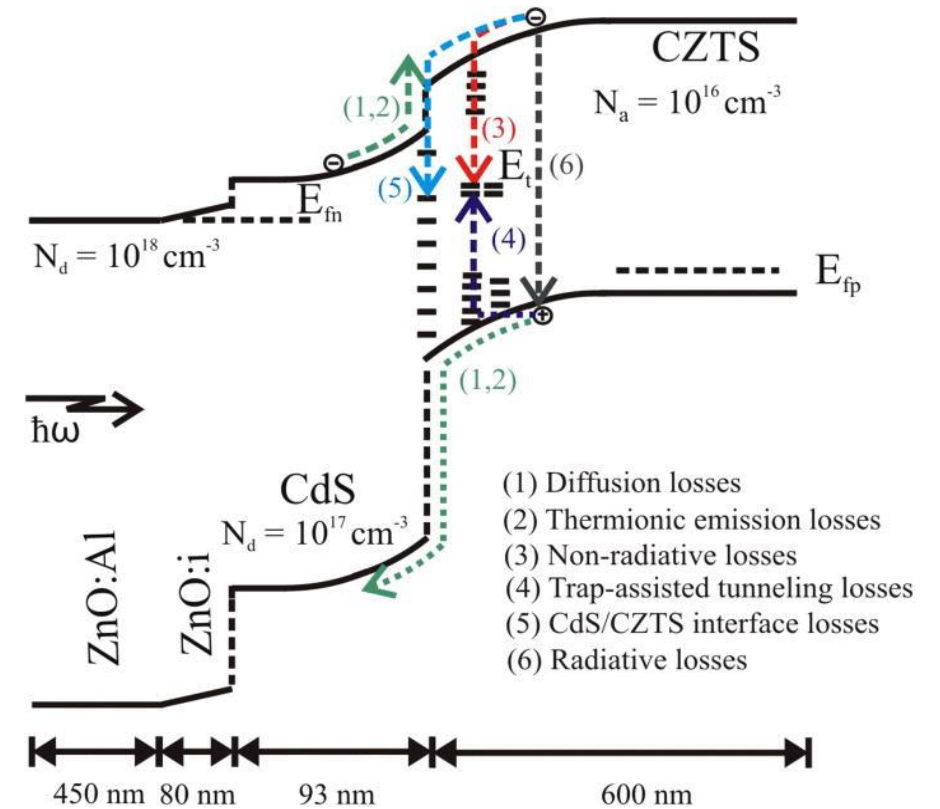
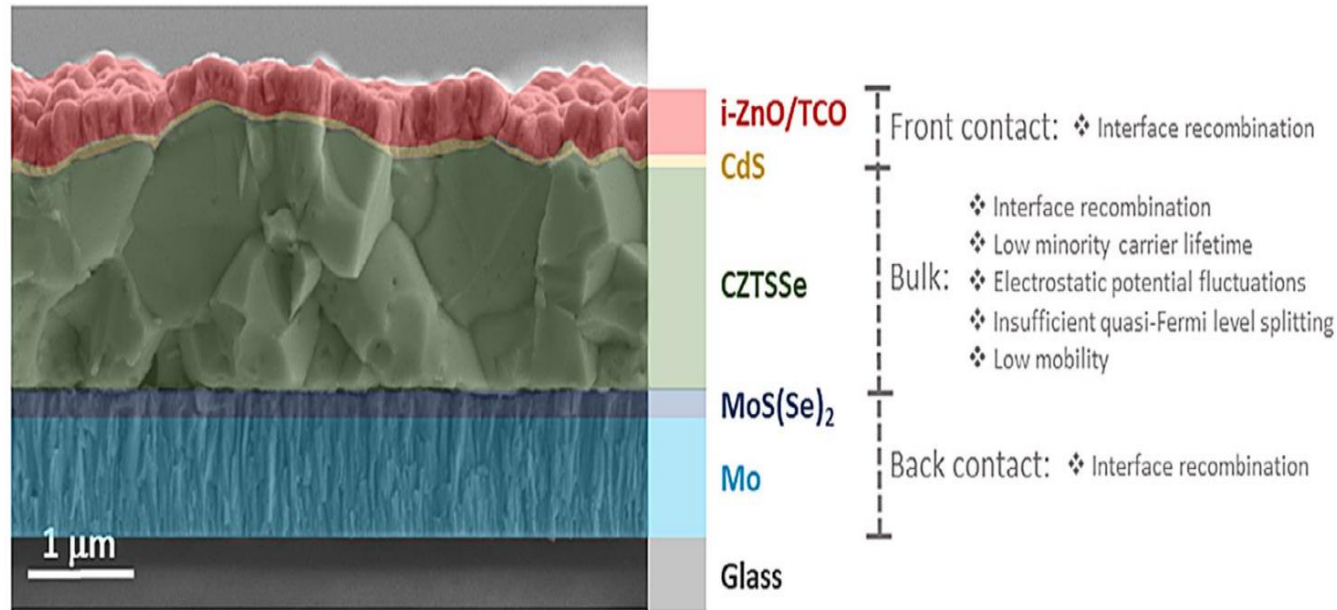


Causes : Competition between kesterite and stannite phase, secondary phases, non-uniform S/(S+Se), non-uniform strain

Causes : Charged defects



# Recombination Locations: Absorber and Interface

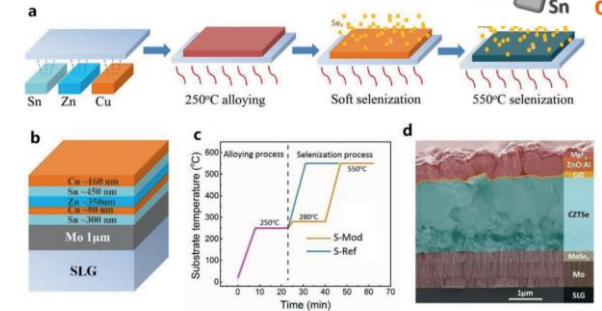
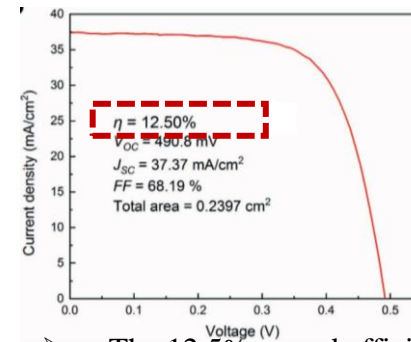
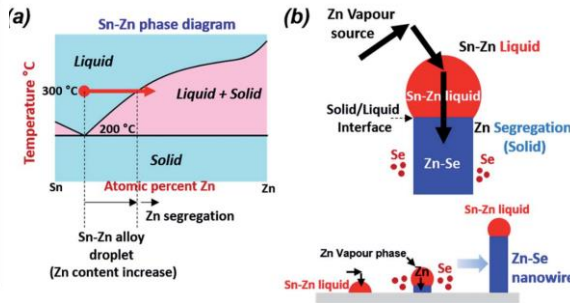
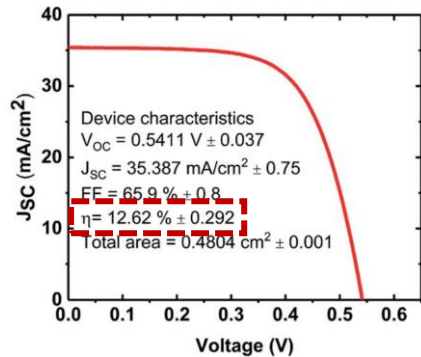
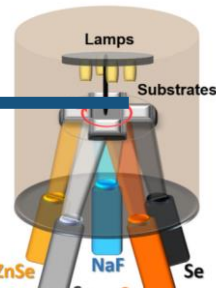


Giraldo, et al, Advanced Micro- and Nanomaterials for Photovoltaics. Elsevier. 2019: 93-120.

Chen, et al, *Adv. Mater.* 2013, 25, 1522

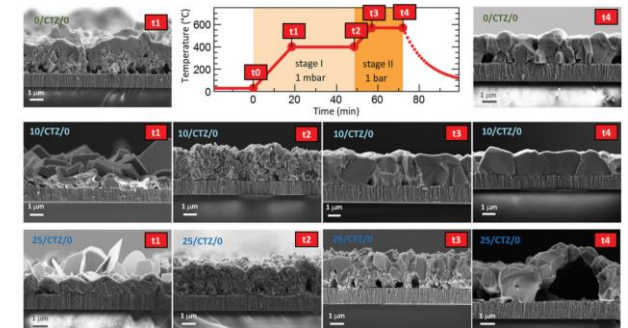
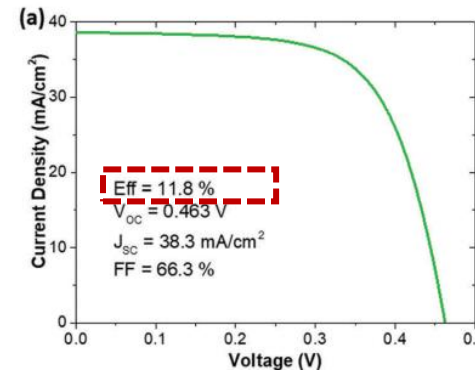
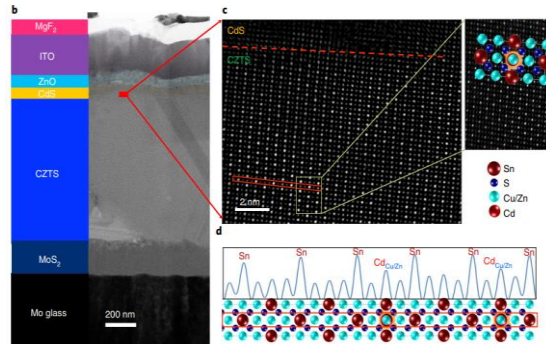
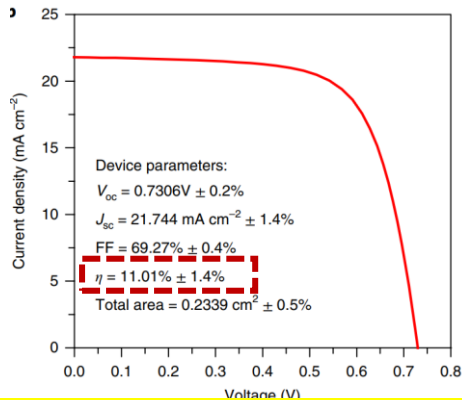
# Vacuum Approach-Physical Deposition

## Precursors: Metal (Cu/Zn/Sn), sulfide/selenide (SnS, ZnS)



- The 12.62% record efficiency by vacuum process.<sup>[1]</sup>
- H<sub>2</sub>S gas is introduced into selenization to suppress the volatilization of Zn.
- Precise **optimization of the selenization process**

- The 12.5% record efficiency of pure-selenide Cu<sub>2</sub>ZnSnSe<sub>4</sub> cells.<sup>[2]</sup>
- The **soft-selenization process** employed to prepare a local chemical environment for the formation of CZTSe.



- The 11.0% record efficiency of pure-sulfide Cu<sub>2</sub>ZnSnS<sub>4</sub> cells.<sup>[3]</sup>
- By employing **post-heat treatment for the heterojunction**.

- **Introduce Ge layer to avoid Sn loss**.<sup>[4]</sup>
- Ge change the evolution of phases during selenization.

[1] Son D H, Kim S H, Kim S Y, et al. Journal of Materials Chemistry A, 2019, 7, 25279.

[2] Li J, Huang Y, Huang J, et al. Advanced Materials, 2020, 32, 2005268.

[3] Yan C, Huang J, Sun K, et al. Nature Energy, 2018, 3, 764.

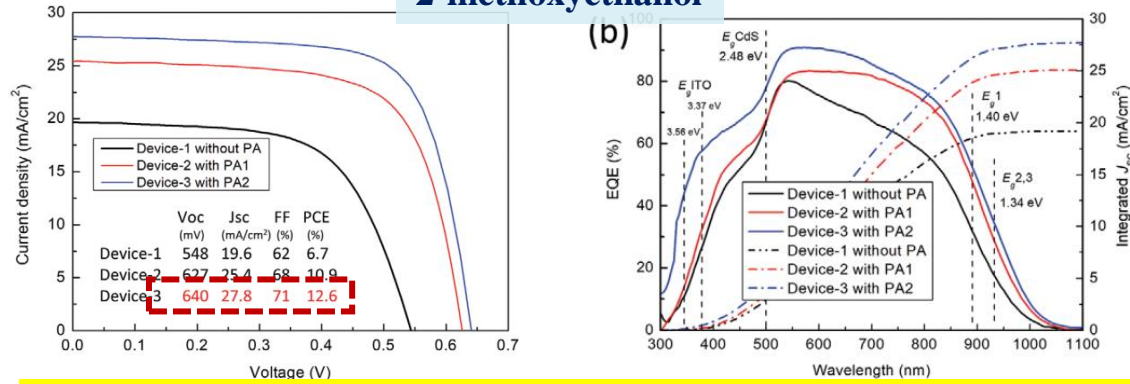
[4] Giraldo S, Saucedo E, Neuschitzer M, et al. Energy & Environmental Science, 2018, 11, 582.

# Solution Approach-Molecular Level Mixture

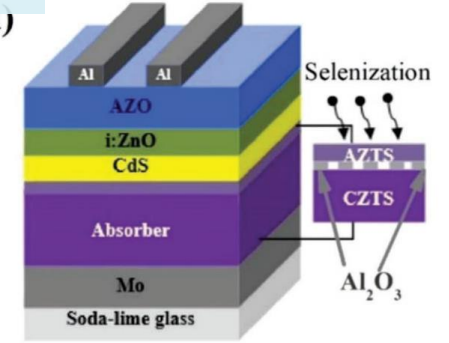
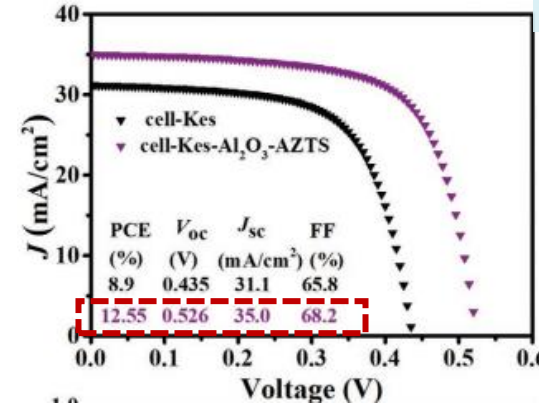
Precursors: metal, metal oxides, metal salts + S source (thiourea)



2-methoxyethanol

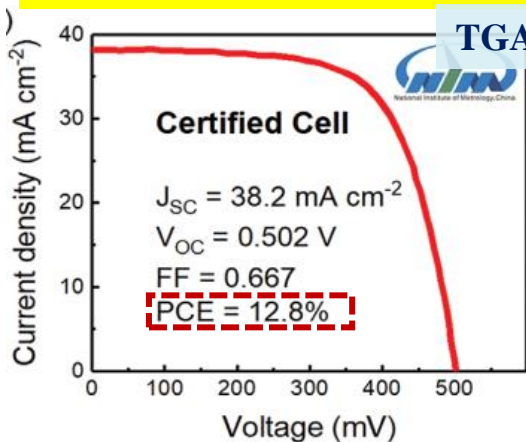


DMSO

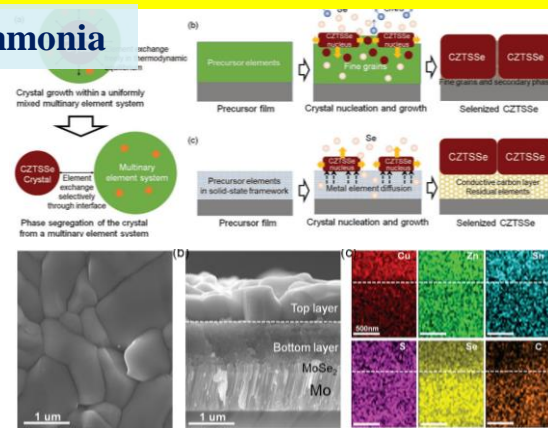


- Over 12% efficient solution processed Cd-alloyed CZTS cell.<sup>[1]</sup>
- A post annealing procedure is proposed to complete device to decreased non-radiative recombination.

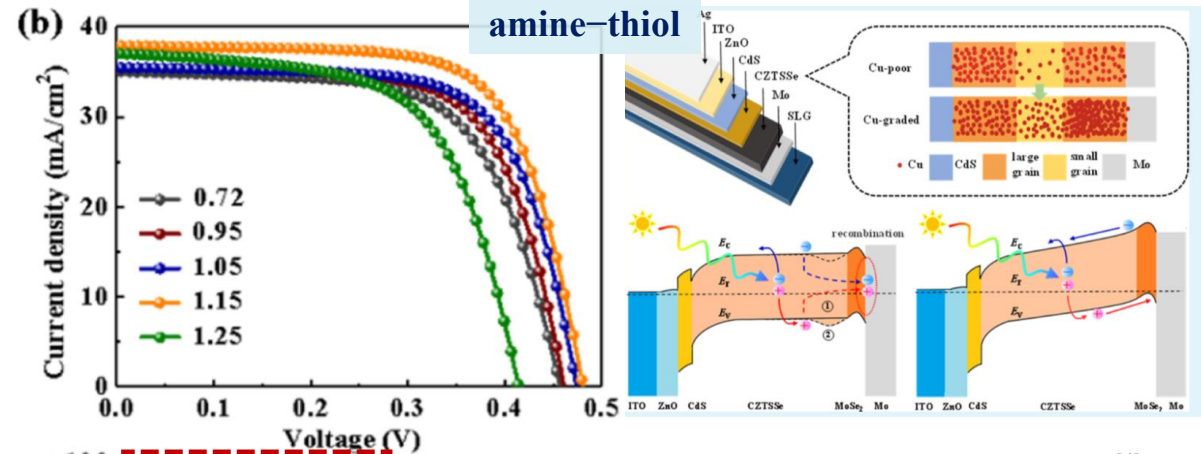
- N-type surface design for p-type CZTSSe Thin Film with 12.55% efficiency.<sup>[2]</sup>



TGA-ammonia



amine-thiol



- A certified active-area PCE of 12.8% for CZTSSe cell.<sup>[3]</sup>
- The device efficiency has a high tolerance to composition due a conductive carbon framework.

- **12.54% efficiency CZTSSe solar cells by local Cu component engineering.**<sup>[4]</sup>

[1] Su Z, Liang G, Fan P, et al. Advanced Materials, 2020, 32(32): 2000121.

[3] Xu X, Guo L, Zhou J, et al. Advanced Energy Materials, 2021, 11(40): 2102298.

[2] Sun Y, Qiu P, Yu W, et al. Advanced Materials, 2021: 2104330.

[4] Zhao Y, Zhao X, Kou D, et al. ACS Applied Materials & Interfaces, 2021, 13(1): 795-805.



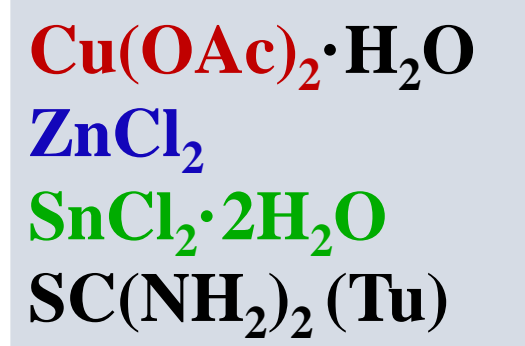
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## 2. 吸收层缺陷与调控

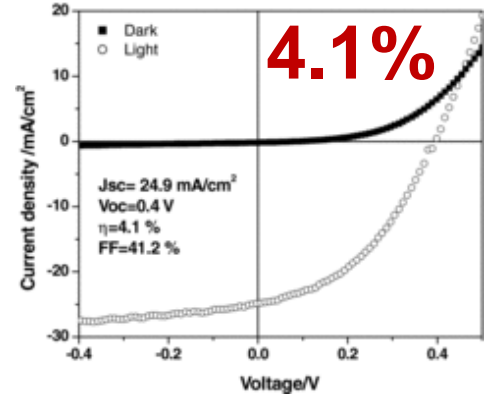
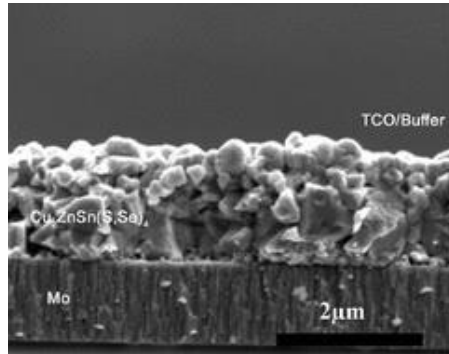
- 2.1 缺陷与前驱体化合物锡的价态 ( $\text{Sn}^{2+}$  vs  $\text{Sn}^{4+}$ )
- 2.2  $V_{\text{OC}}$  损失与晶粒生长机制
- 2.3 Cu-Zn无序与带尾态及银合金化

# 2.1 缺陷与前驱体化合物锡的价态 (Sn<sup>2+</sup> vs Sn<sup>4+</sup>)

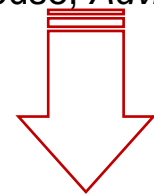
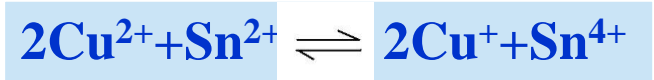
## DMSO Molecular Precursor Solution Approach



DMSO

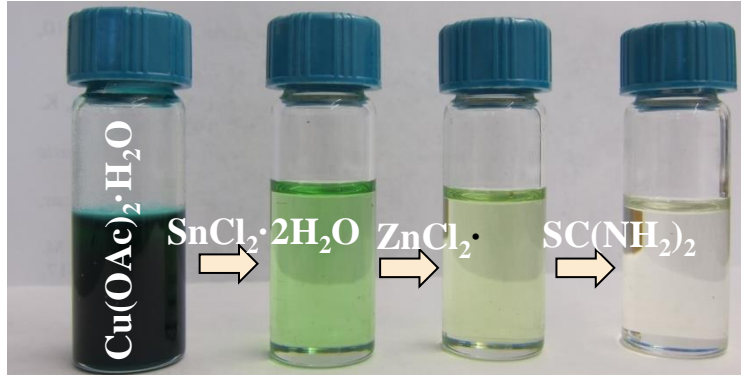


Ki and Hillhouse, *Adv. Energy Mater.* 2011, 732.

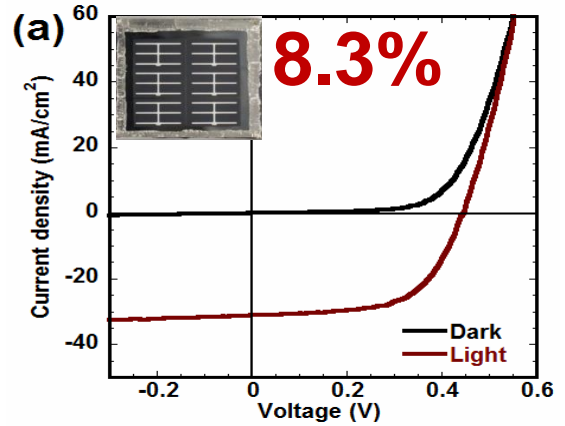
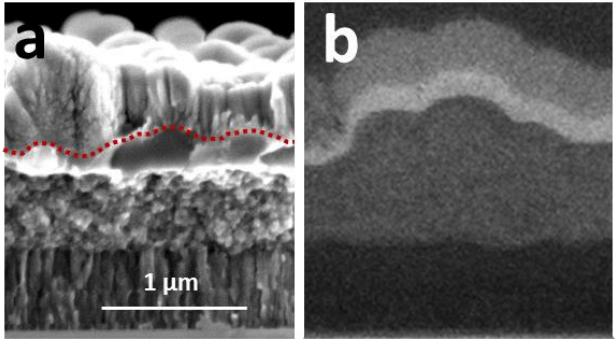


Control the redox reaction

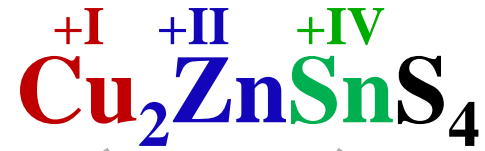
$V_{oc,def} : 0.424 \text{ V}$   
 $V_{oc}/V_{oc}^{SQ} : 0.51$



*Adv. Energy Mater.* 2014, 1301823



# Sn<sup>2+</sup> vs Sn<sup>4+</sup> Precursor



CuCl, ZnCl<sub>2</sub>, SnCl<sub>2</sub>·2H<sub>2</sub>O, Tu

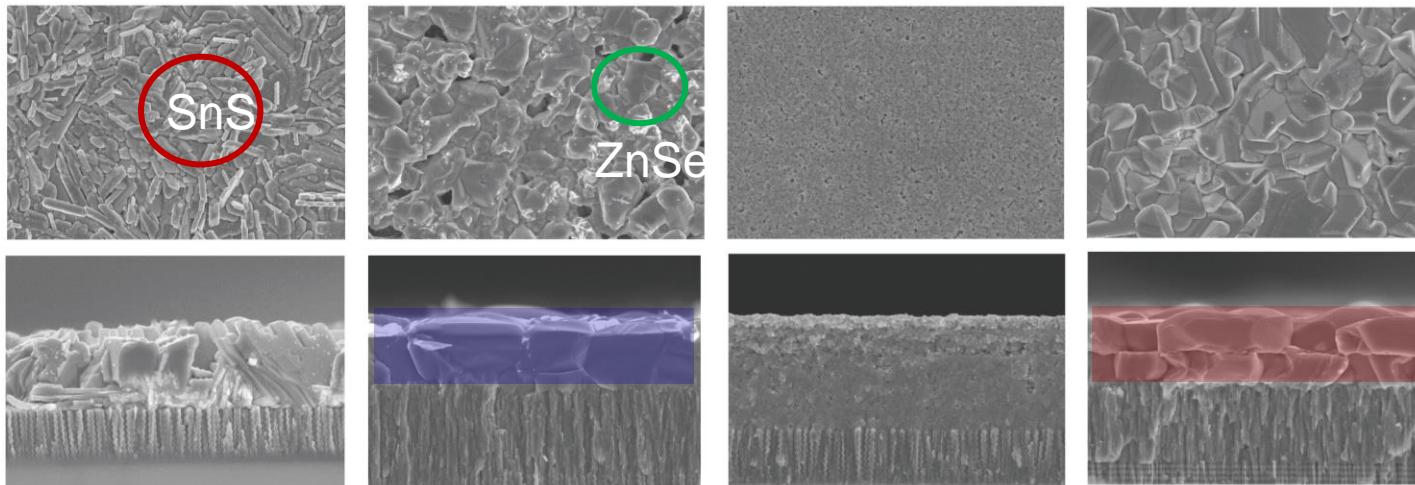
CuCl, Zn(OAc)<sub>2</sub>, SnCl<sub>4</sub>, Tu



# Sn<sup>2+</sup> vs Sn<sup>4+</sup>: Effect on V<sub>oc</sub>

Sn<sup>2+</sup>

Sn<sup>4+</sup>



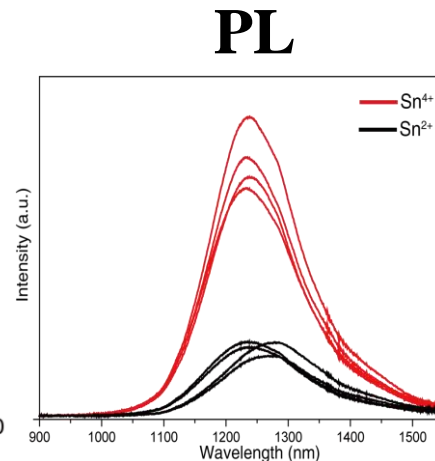
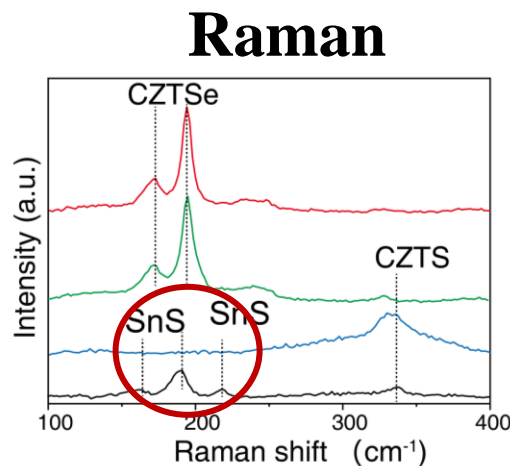
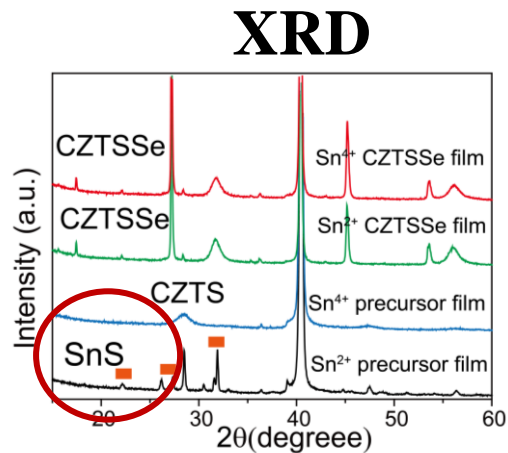
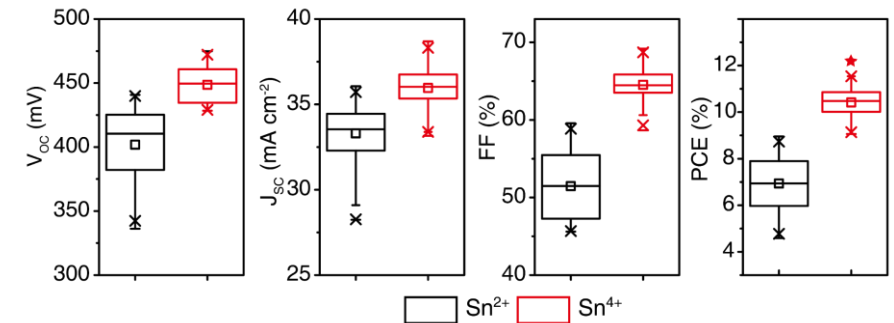
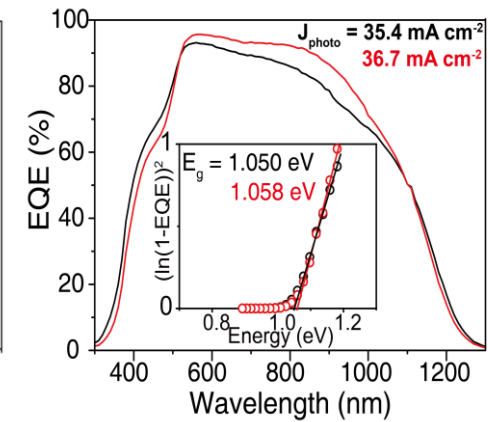
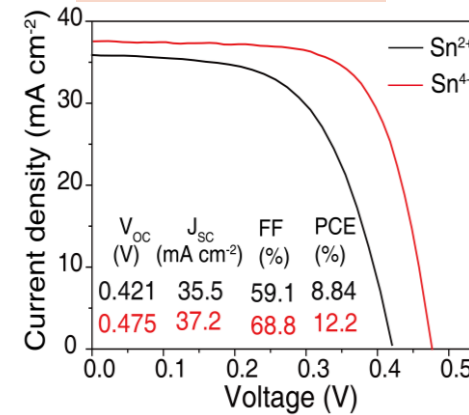
Sn<sup>2+</sup> precursor film

Sn<sup>2+</sup> CZTSSe film

Sn<sup>4+</sup> precursor film

Sn<sup>4+</sup> CZTSSe film

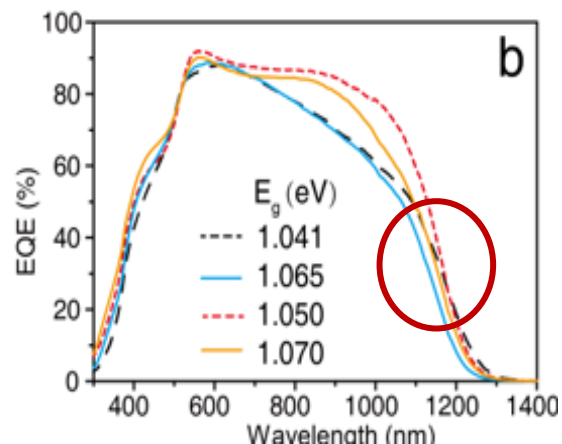
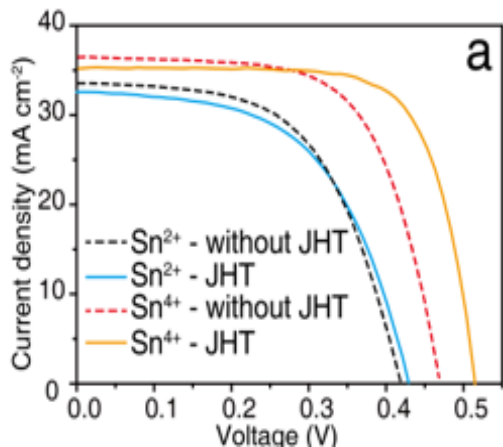
$\Delta V_{oc} = 54 \text{ mV}$



- Dramatic difference in composition and morphology of the precursor films
- Sn<sup>4+</sup> shows high uniformity
- Sn<sup>4+</sup> device has much high V<sub>oc</sub> and FF

# Sn<sup>2+</sup> vs Sn<sup>4+</sup>: Response to Junction Heat Treatment (JHT)

**JHT (200°C/20 h, vaccum)**



Sn<sup>2+</sup>

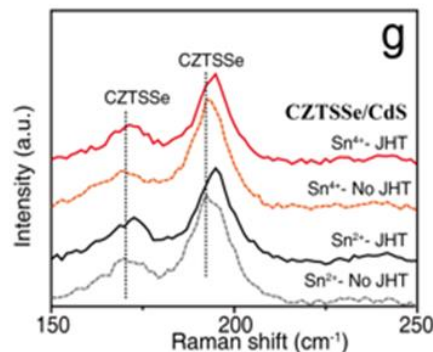
**E<sub>g</sub>**: increase 24 meV  
**J<sub>sc</sub>**: decrease  
**V<sub>oc</sub>**: no obvious change  
**FF**: no obvious change

Sn<sup>4+</sup>

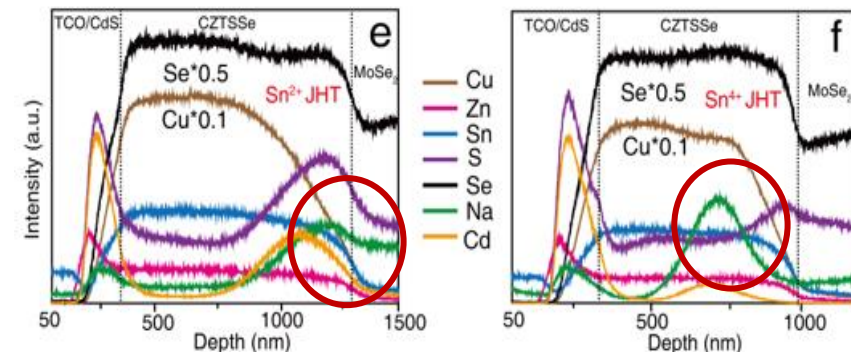
**E<sub>g</sub>**: increase 20 meV  
**J<sub>sc</sub>**: decrease  
**V<sub>oc</sub>**: enhance 50 mV  
**FF**: increase

**V<sub>oc</sub> directly related to the oxidation state of the Sn precursor**

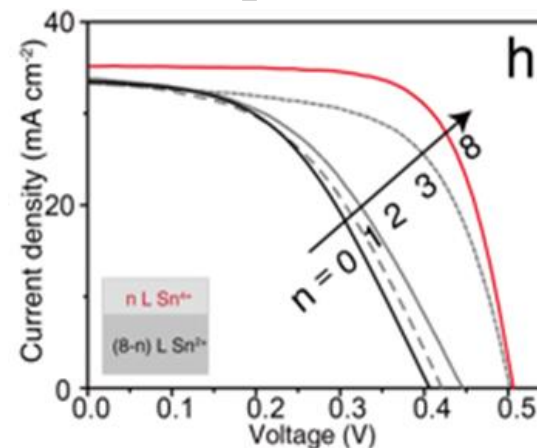
Raman



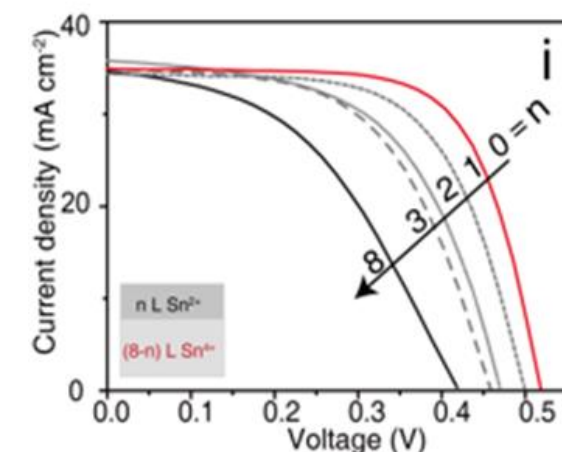
GDOES



Top Sn<sup>4+</sup>



Top Sn<sup>2+</sup>



- Order level similarly improved upon JHT
- Large Cd and S diffuse into film
- Surface property is more important

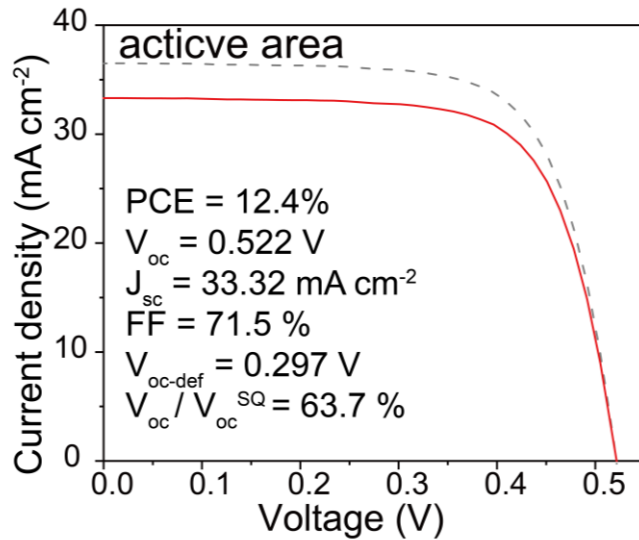
# Champion CZTSSe Device from Sn<sup>4+</sup> DMSO Solution

SCIENCE CHINA Materials

ARTICLES

[mater.scichina.com](http://mater.scichina.com) [link.springer.com](http://link.springer.com)

Published online 29 July 2020 | <https://doi.org/10.1007/s40843-020-1408-x>

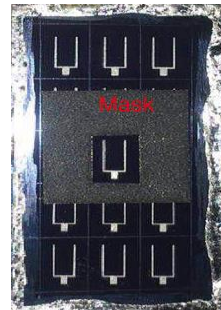
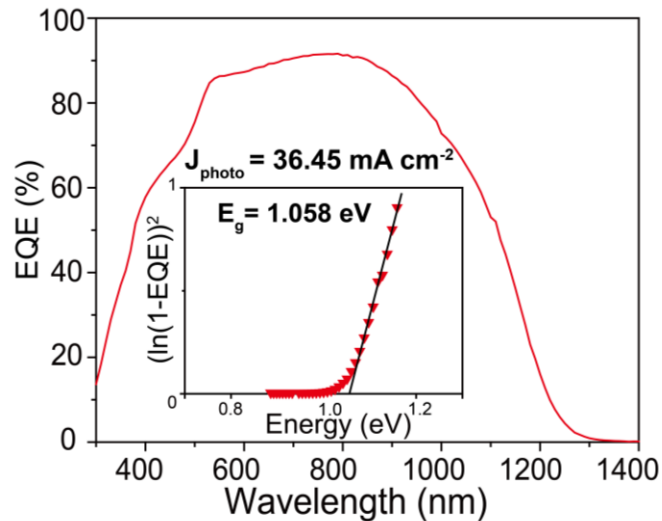


**Total area: 12.4%**  
**Active area: 13.6%**

**$V_{oc,def} : 0.297 V$**   
 **$V_{oc}/V_{oc}^{SQ} : 63.7\%$**

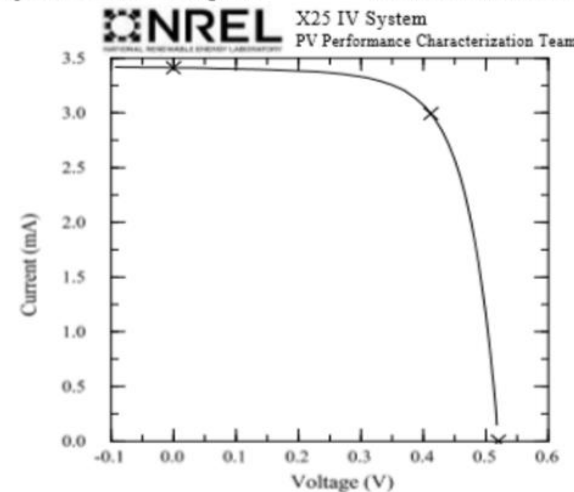
**Sn<sup>4+</sup> precursor enables 12.4% efficient kesterite solar cell from DMSO solution with open circuit voltage deficit below 0.30 V**

Yuancai Gong<sup>1</sup>, Yifan Zhang<sup>1</sup>, Erin Jedlicka<sup>2</sup>, Rajiv Giridharagopal<sup>2</sup>, James A. Clark<sup>3</sup>, Weibo Yan<sup>1</sup>, Chuanyou Niu<sup>1</sup>, Ruichan Qiu<sup>1</sup>, Jingjing Jiang<sup>1</sup>, Shaotang Yu<sup>1</sup>, Sanping Wu<sup>1</sup>, Hugh W. Hillhouse<sup>3</sup>, David S. Ginger<sup>2</sup>, Wei Huang<sup>1</sup> and Hao Xin<sup>1</sup>



Nanjing University of Posts & Communication  
CZTSSe Cell

Device ID: NUPT-1 Device Temperature: 24.5 ± 0.6 °C  
Nov 01, 2018 16:29 Device Area: 0.1066 cm<sup>2</sup> ± 0.4 %  
Spectrum: ASTM G173 global Irradiance: 1000.0 W/m<sup>2</sup>



**Total area: 11.56%**  
**Active area: 13.22%**

## 2.2 $V_{oc}$ 损失与晶粒生长机制

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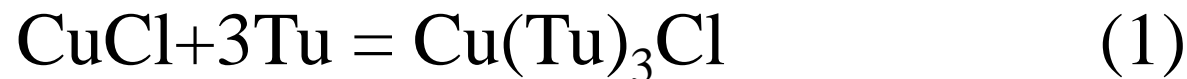
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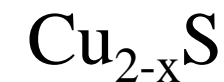
Cite this: *Energy Environ. Sci.*,  
2021, 14, 2369

Identifying the origin of the  $V_{oc}$  deficit of kesterite solar cells from the two grain growth mechanisms induced by  $\text{Sn}^{2+}$  and  $\text{Sn}^{4+}$  precursors in DMSO solution†

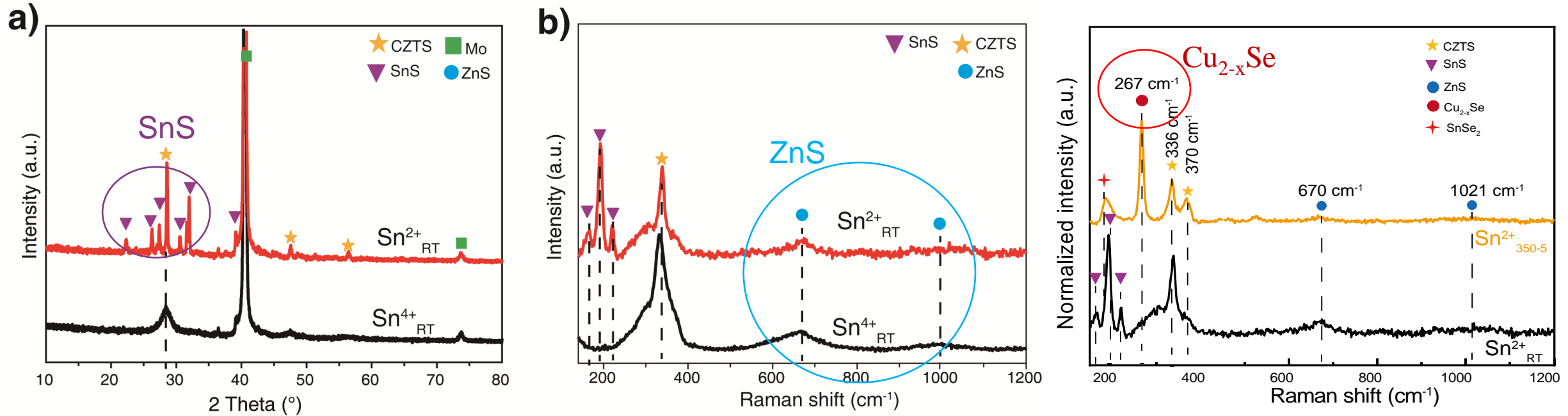
Reaction of each precursor in the DMSO solution with Tu



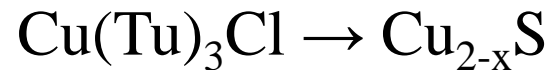
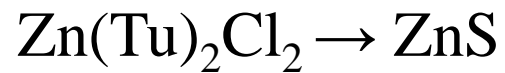
Reaction from solution to solid film



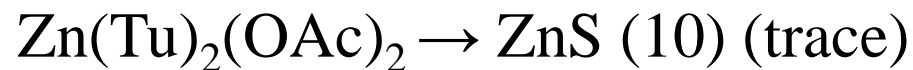
# Reaction Path from Solution to Precursor film



**Sn<sup>2+</sup> solution**



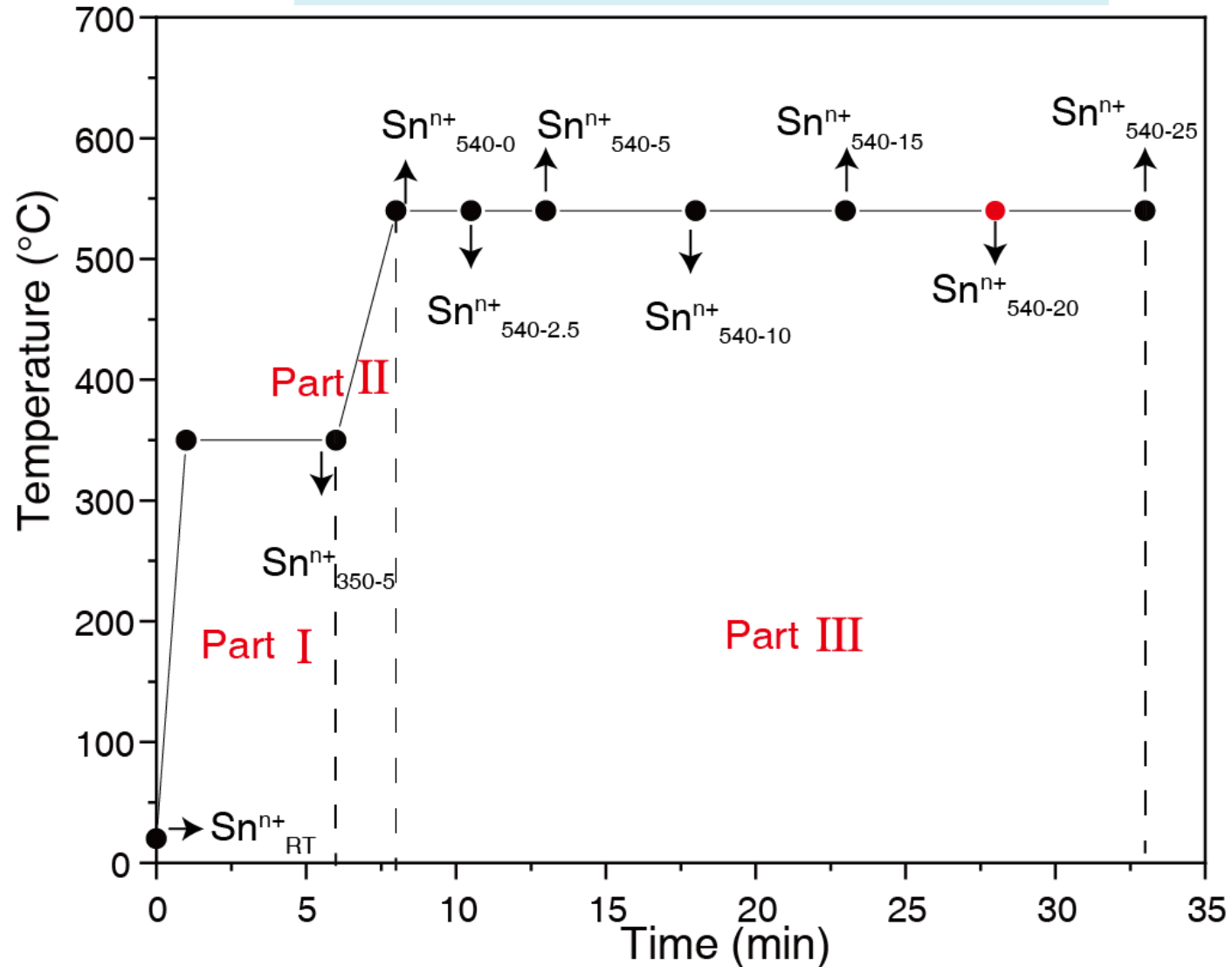
**Sn<sup>4+</sup> solution**





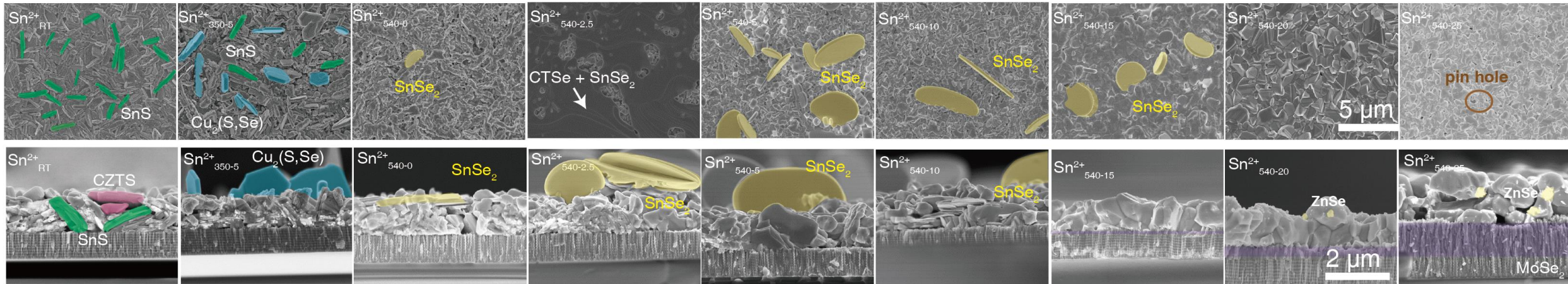
# Grain Growth from Precursor Film to Absorber

## Selenization profile

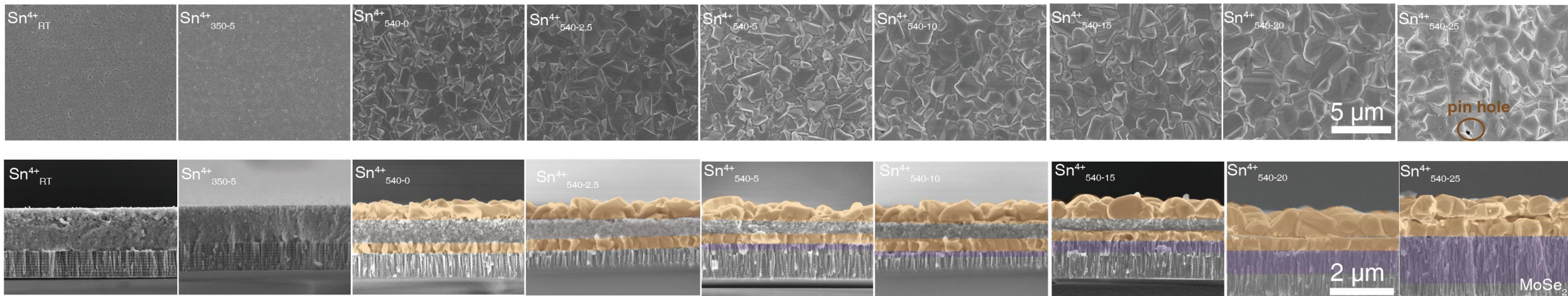


# Grain Growth from Precursor Film to Absorber

$\text{Sn}^{2+}$

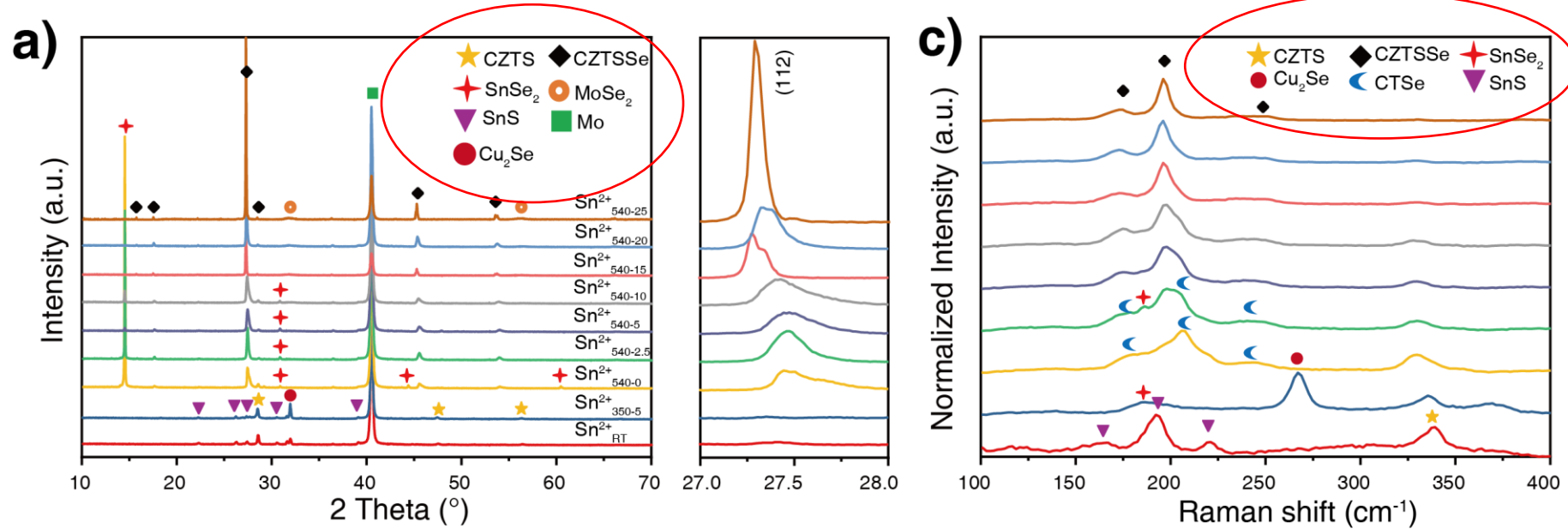


$\text{Sn}^{4+}$

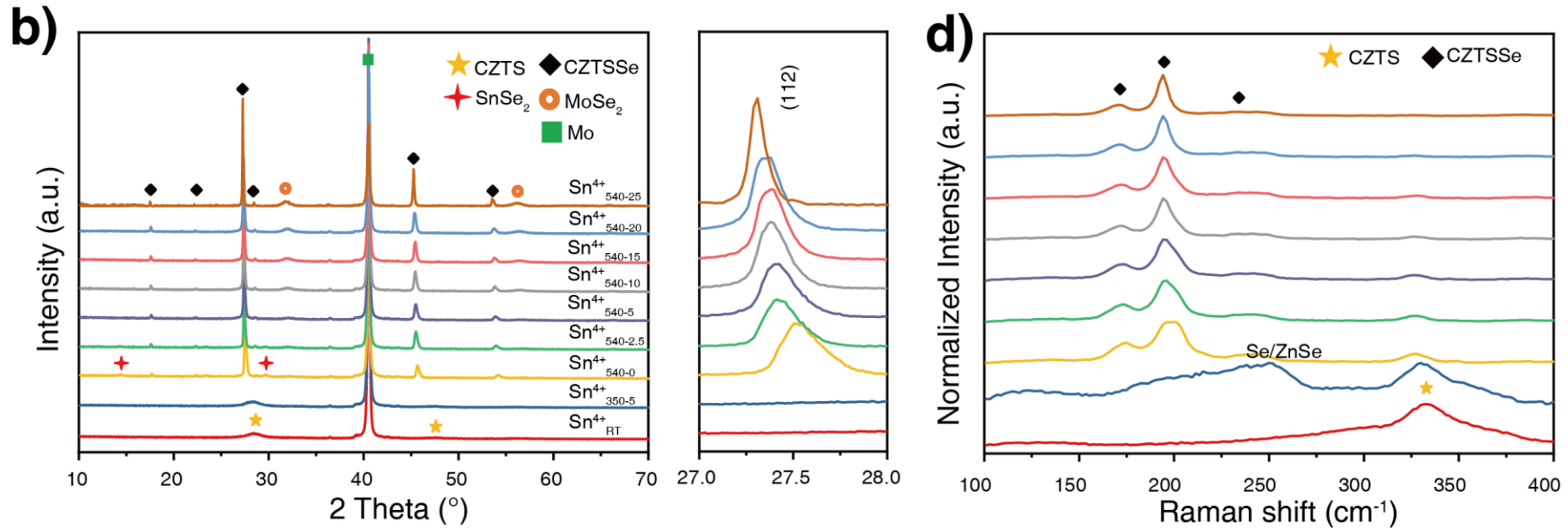


# Grain Growth from Precursor Film to Absorber

$\text{Sn}^{2+}$

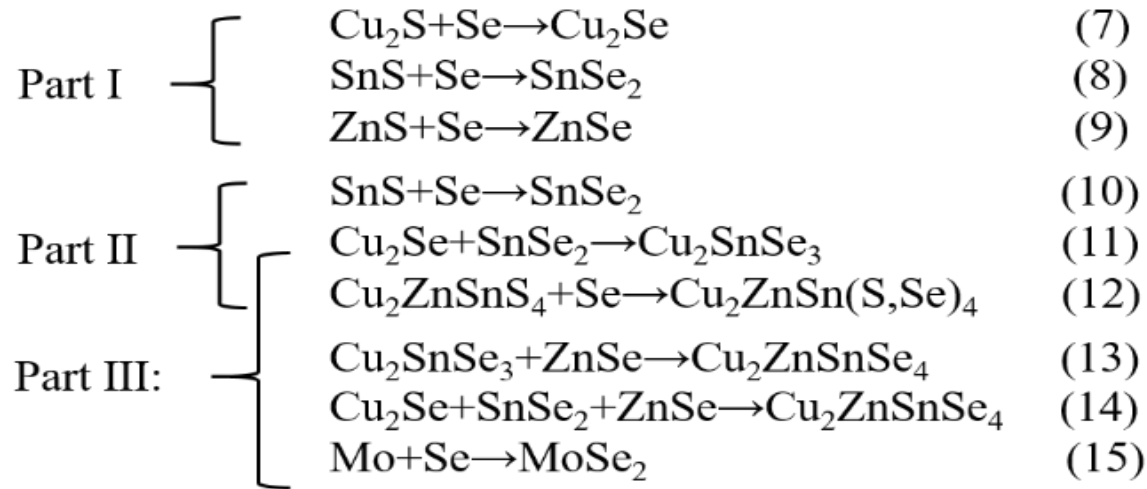


$\text{Sn}^{4+}$

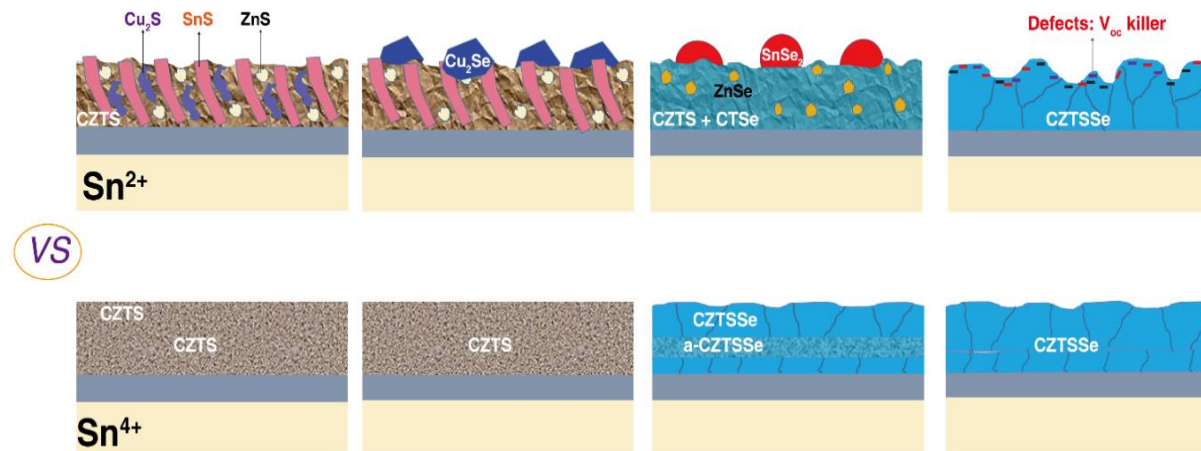
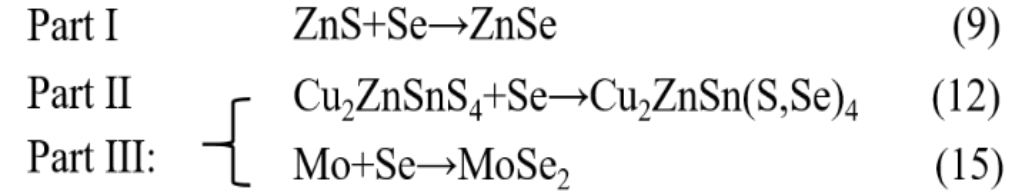


# Reaction Path to Absorber

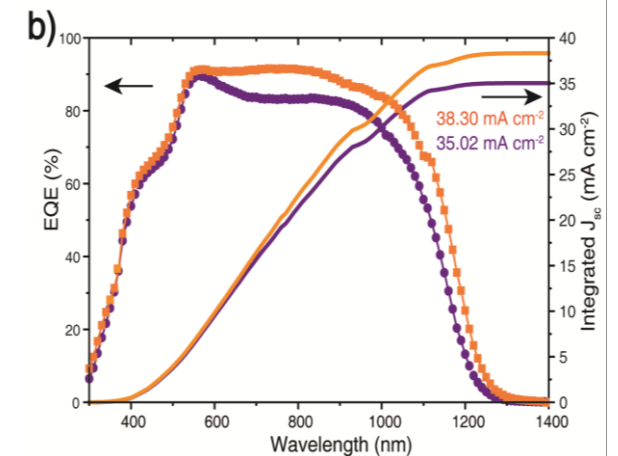
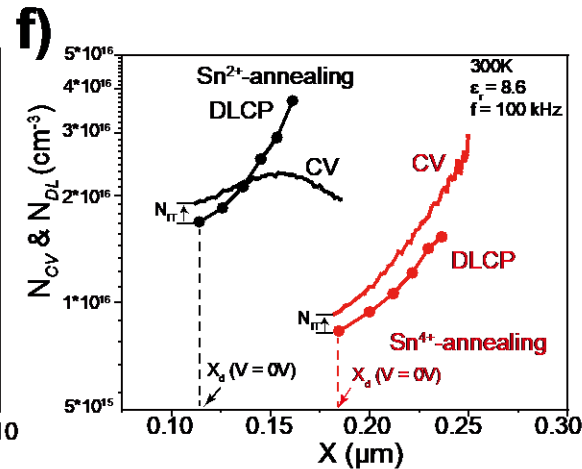
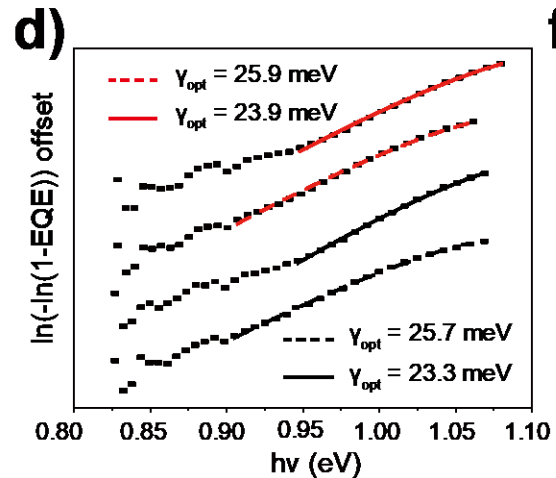
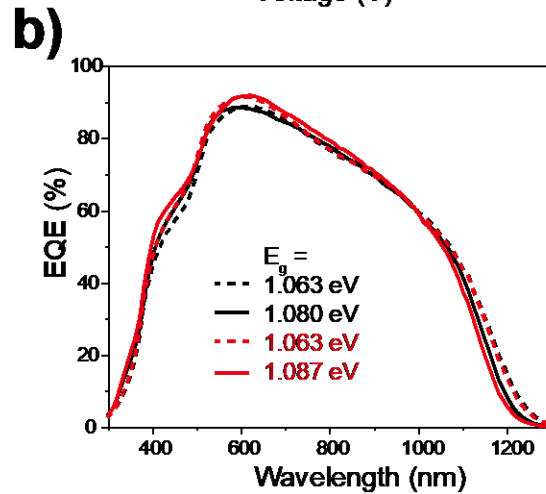
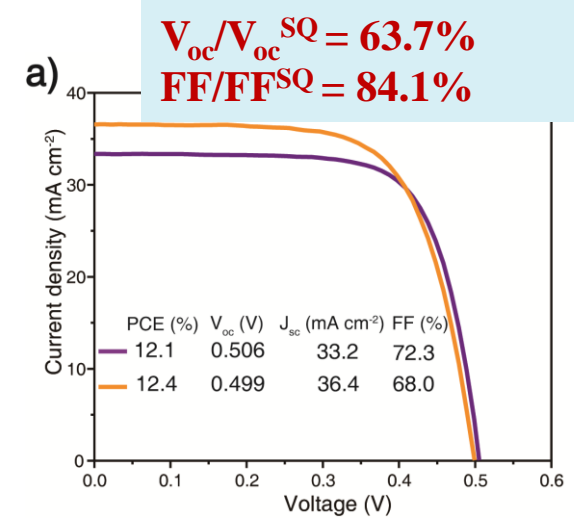
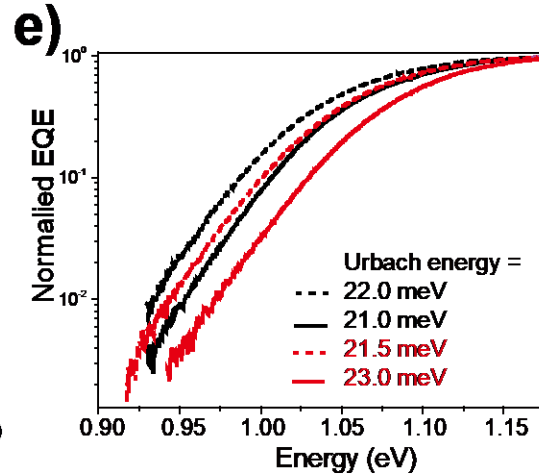
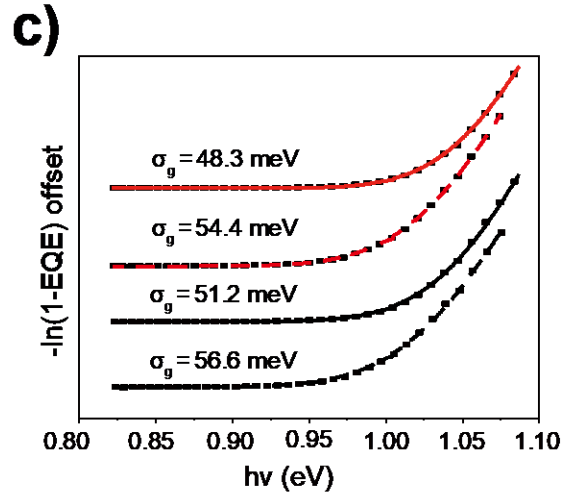
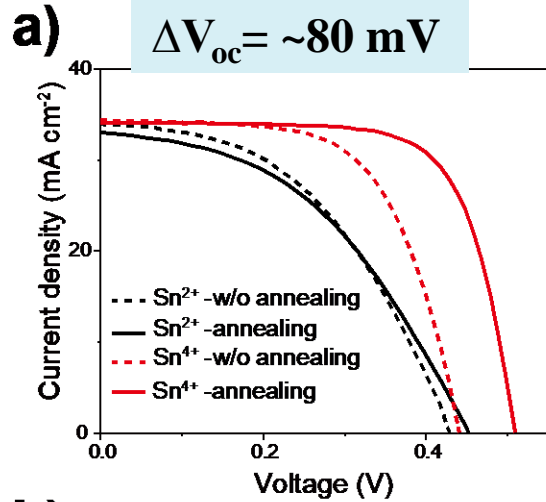
## Sn<sup>2+</sup>: multi-phase fusion



## Sn<sup>4+</sup>: direct phase transformation

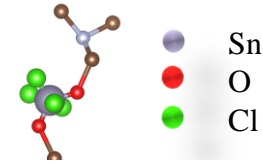
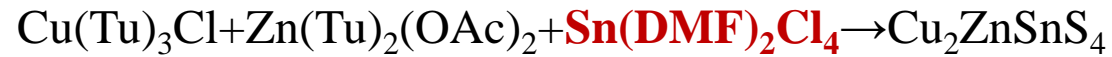
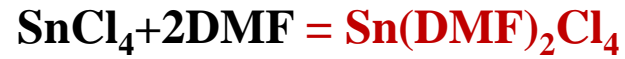


# JHT on the Electronic Property of the Absorbers



- Band gap (order level) similarly improved upon JHT
- Band tailing ( $E_U$ ) does not show correlation to  $V_{oc}$
- Charge carrier concentration (especially surface defects) significantly reduced

# Same Reaction Path from DMF Solution



Journal of  
Materials Chemistry A



COMMUNICATION



Cite this: *J. Mater. Chem. A*, 2021, 9, 12981

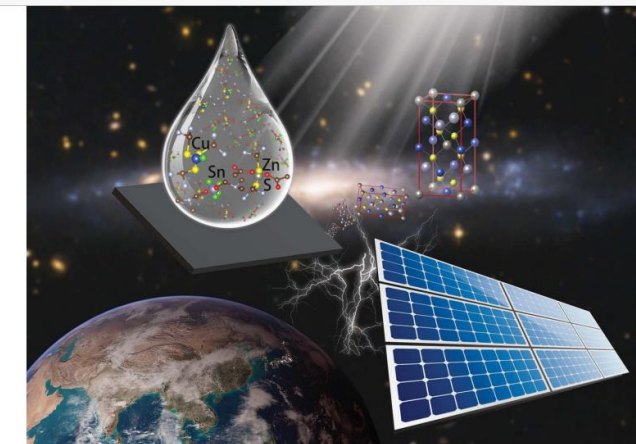
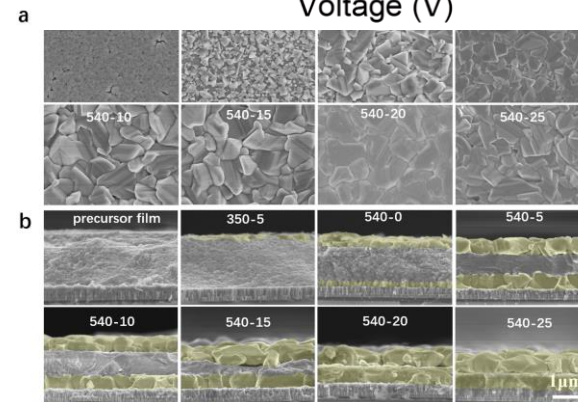
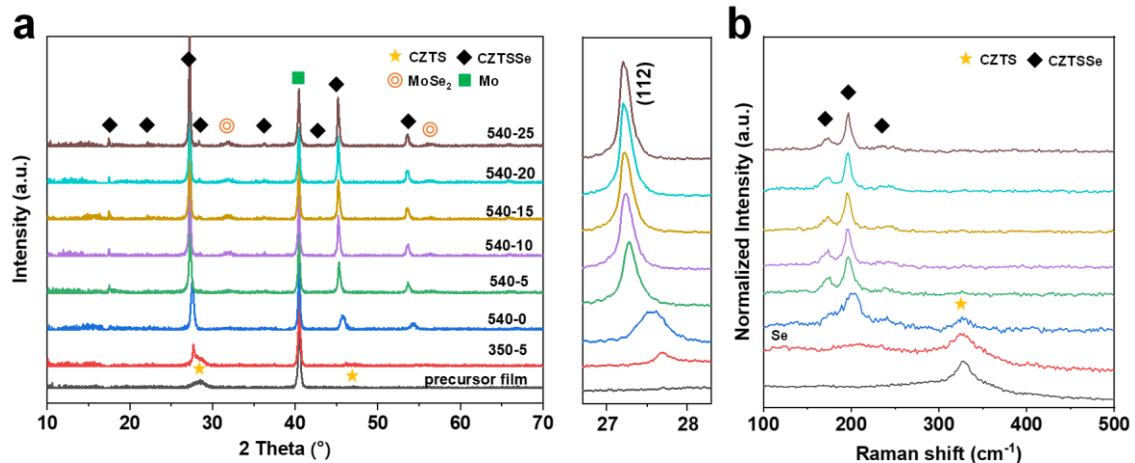
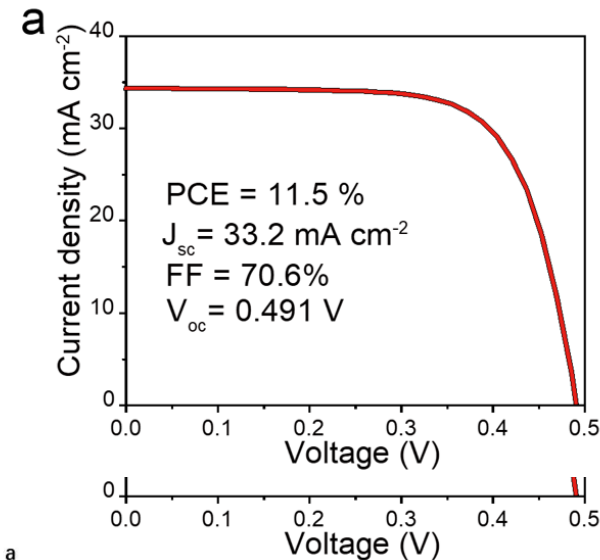
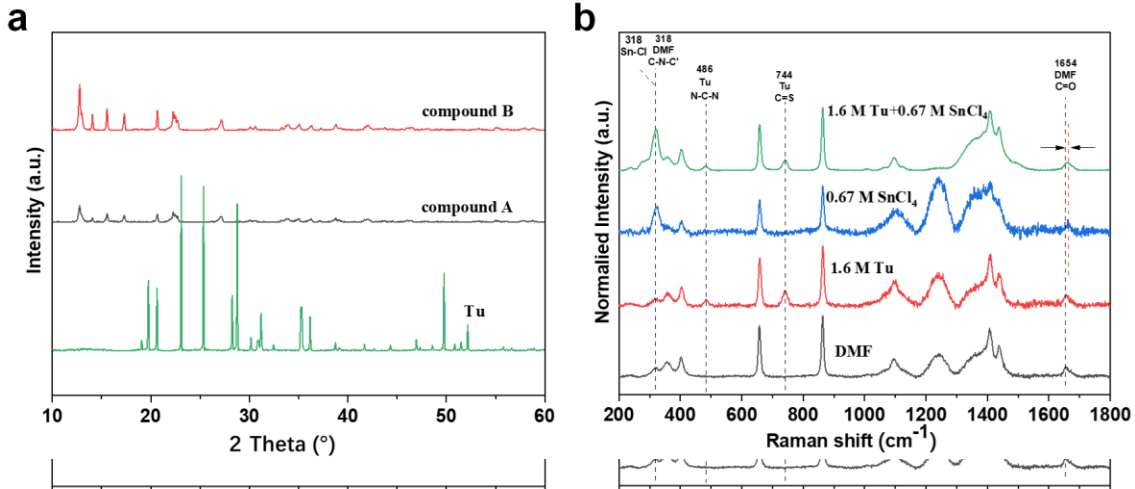
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Accepted 29th April 2021

DOI: 10.1039/d1ta01877j

rsc.li/materials-a

**11.5% efficient  $\text{Cu}_2\text{ZnSn}(\text{S,Se})_4$  solar cell fabricated from DMF molecular solution†**

Chuangyou Niu,† Yuancai Gong,† Ruichan Qiu, Qiang Zhu, Yage Zhou, Shasha Hao, Weibo Yan,\* Wei Huang and Hao Xin\*†

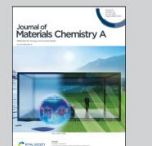


Highlighting a study on a solution processed kesterite solar cell by Prof. Hao Xin's group from Nanjing University of Posts and Telecommunications.

11.5% efficient  $\text{Cu}_2\text{ZnSn}(\text{S,Se})_4$  solar cell fabricated from DMF molecular solution

Efficient CZTSSe thin film solar cells are fabricated from N,N-dimethylformamide (DMF) solution. Studies of chemical reactions of precursors  $\text{CuCl}_2\text{Zn}(\text{OAc})_2$ ,  $\text{SnCl}_4$ , and Thiourea (Tu) in the DMF solution and the reaction path from solution to CZTSSe absorber material show a kesterite structured CZTS precursor film was formed due to the coordination of  $\text{SnCl}_4$  with DMF, which enables direct phase transformation grain growth mechanism and thus high quality CZTSSe absorber materials. A champion device with an efficiency of 11.5%, a  $V_{oc}$  of 0.491 V, and a FF of 70.6% has been achieved, the highest performance of CZTSSe solar cells fabricated from DMF molecular solution.

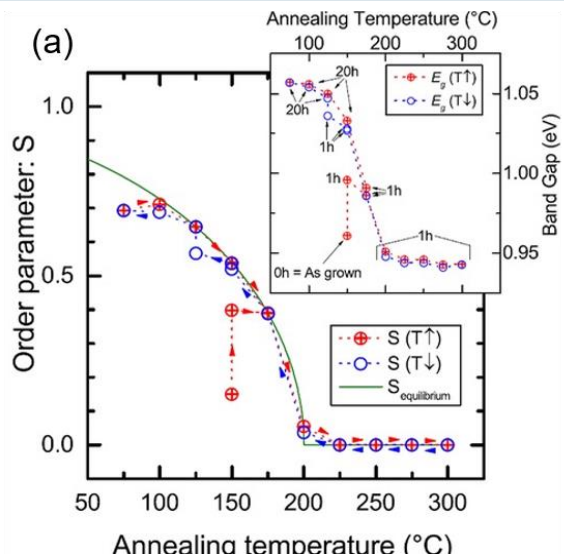
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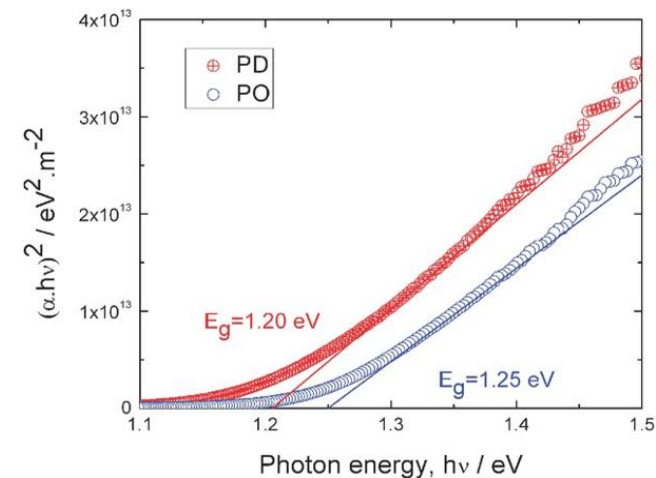
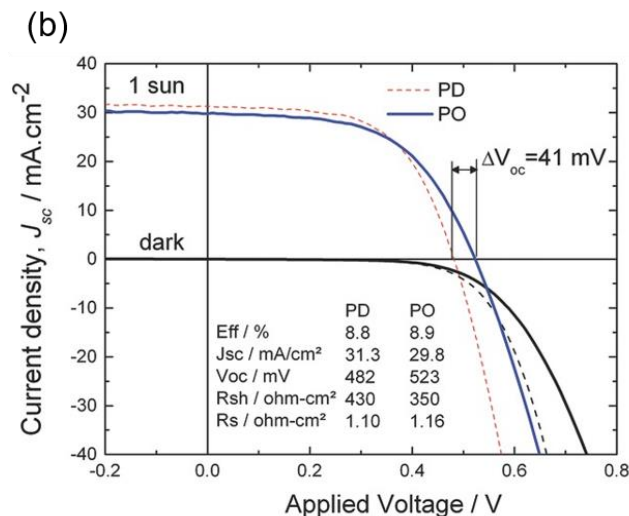
See Weibo Yan, Hao Xin et al., *J. Mater. Chem. A*, 2021, 9, 12981.

**Direct phase transformation grain growth is a universal strategy for achieving high quality kesterite absorber.**

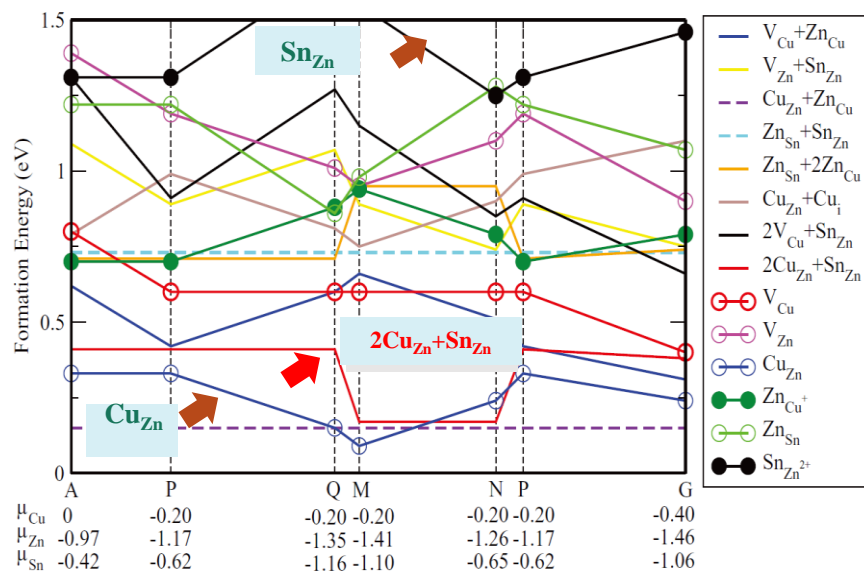
## 2.3 Cu-Zn无序与带尾态及银合金化



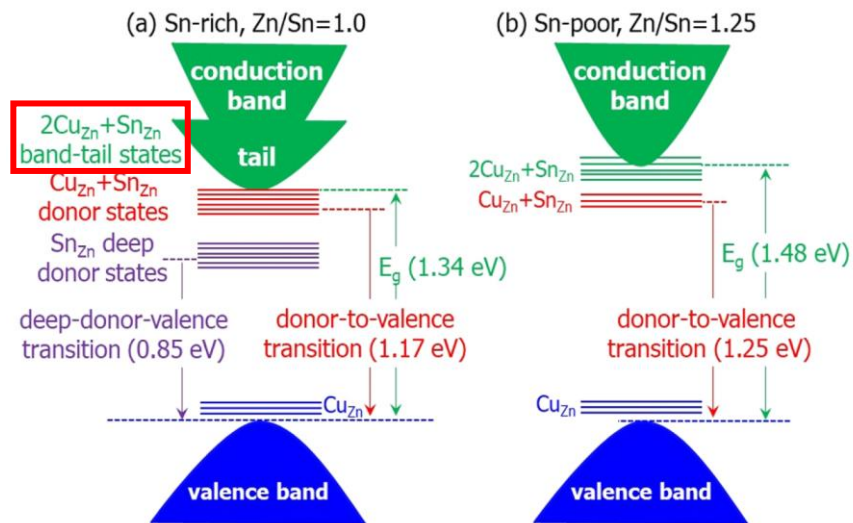
Rey et al. *Appl. Phys. Lett.* **2014**, *105*, 112106.



Bourdais, et al. *Adv. Energy Mater.* **2016**, *6*, 1502276.



Chen et al. *Adv. Mater.* **2013**, *25*, 1522.



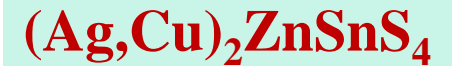
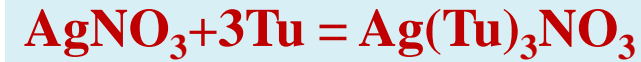
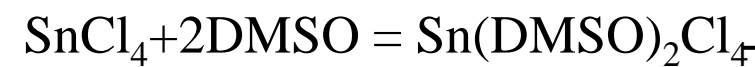
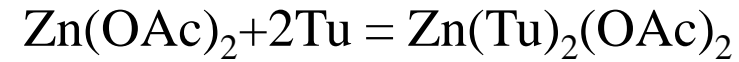
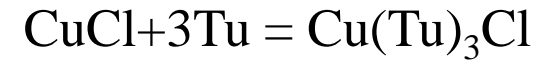
# Ag Alloying via Direct Phase Transformation Grain Growth

RESEARCH ARTICLE

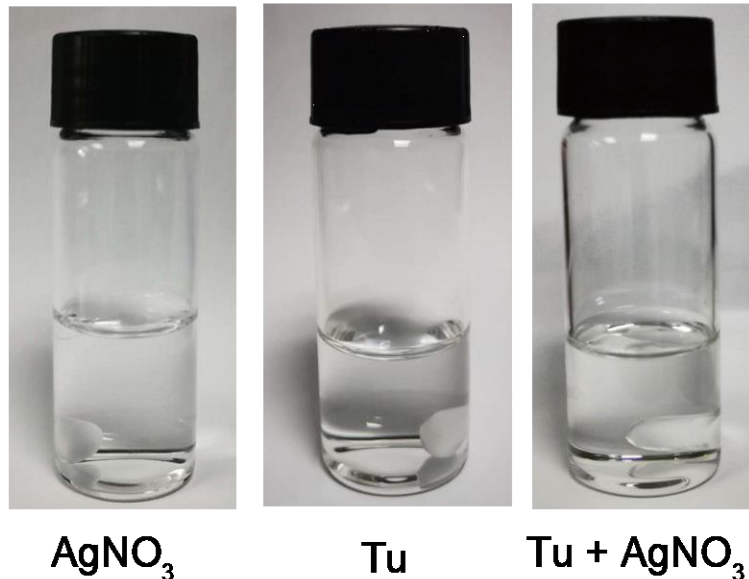
ADVANCED  
FUNCTIONAL  
MATERIALS  
www.afm-journal.org

Ag Incorporation with Controlled Grain Growth Enables 12.5% Efficient Kesterite Solar Cell with Open Circuit Voltage Reached 64.2% Shockley–Queisser Limit

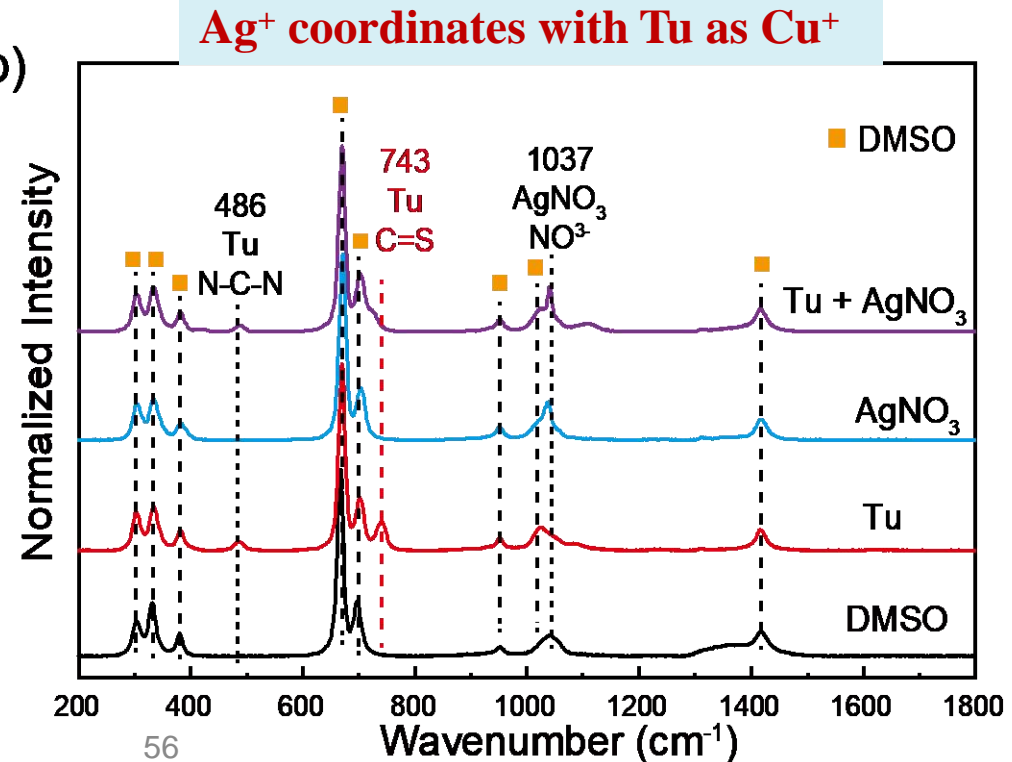
Yuancai Gong, Ruichan Qiu, Chuanyou Niu, Junjie Fu, Erin Jedlicka, Rajiv Giridharagopal, Qiang Zhu, Yage Zhou, Weibo Yan, Shaotang Yu, Jingjing Jiang, Sixin Wu,\* David S. Ginger,\* Wei Huang,\* and Hao Xin\*



(a)

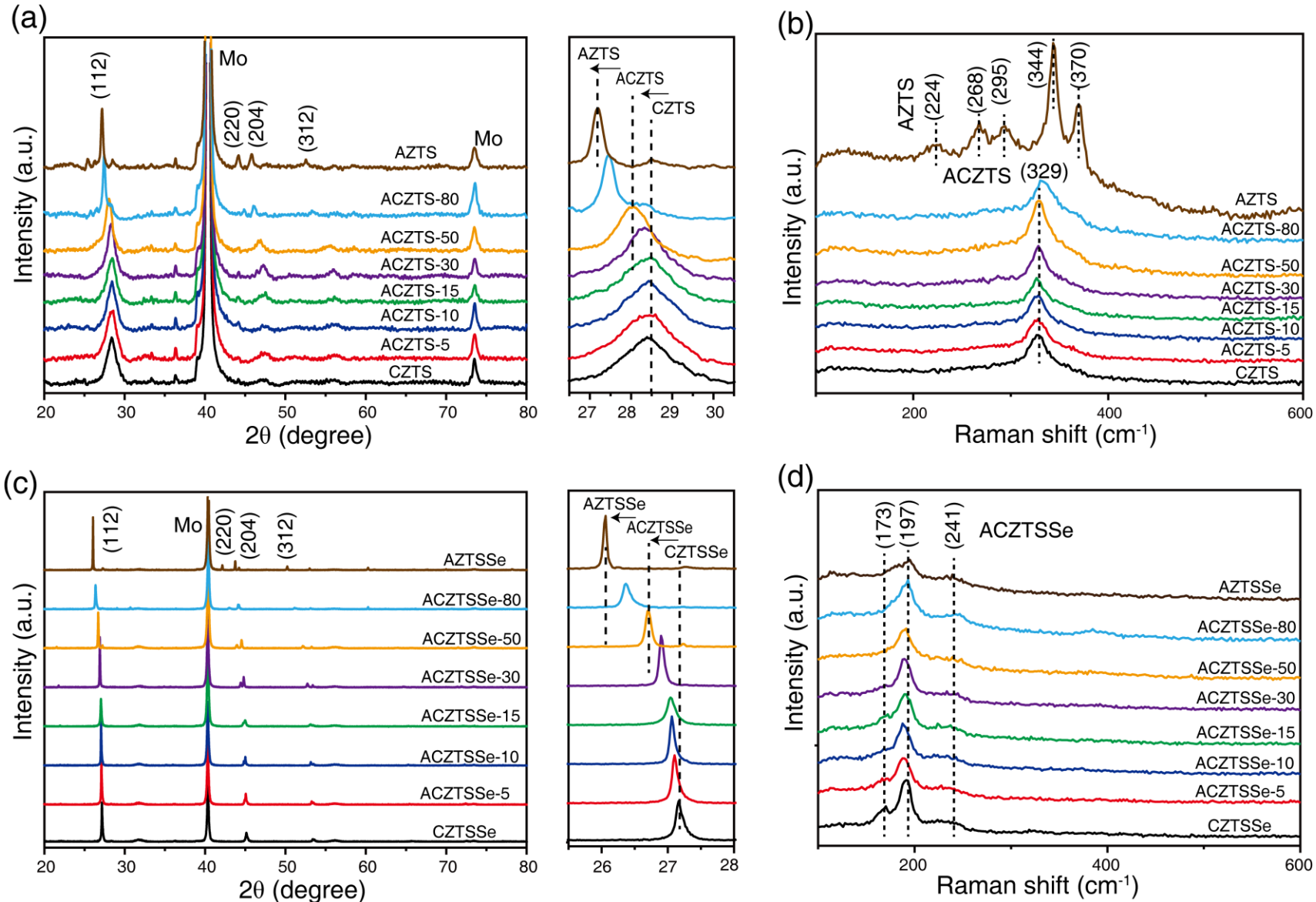


(b)





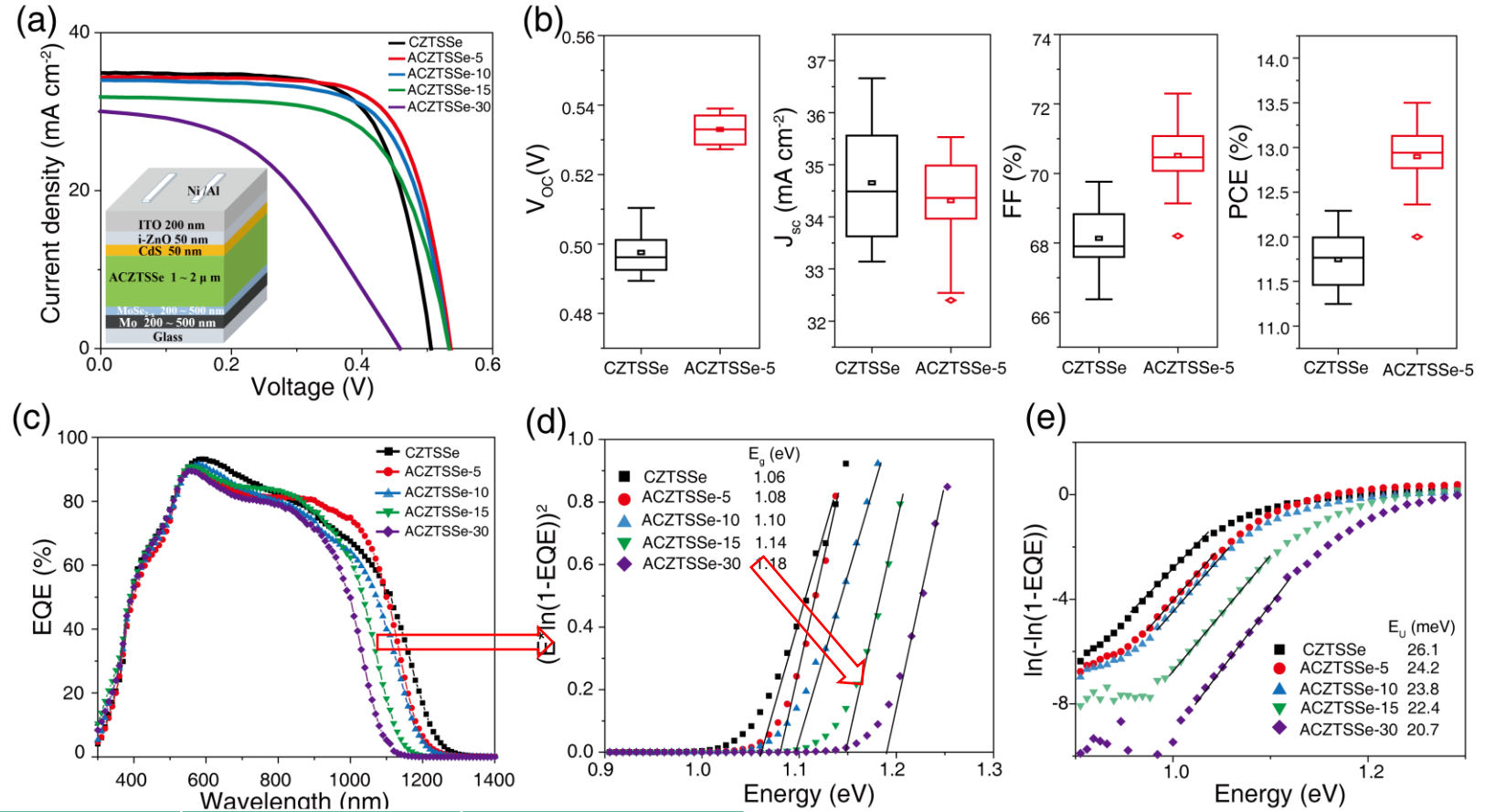
# Ag Incorporation Through DMSO Solution



**$(\text{Ag}_x, \text{Cu}_{1-x})_2\text{ZnSnS}_4$  (X=0-1) successfully fabricated.**

# New Ag Alloying Strategy Mitigates Band Tailing

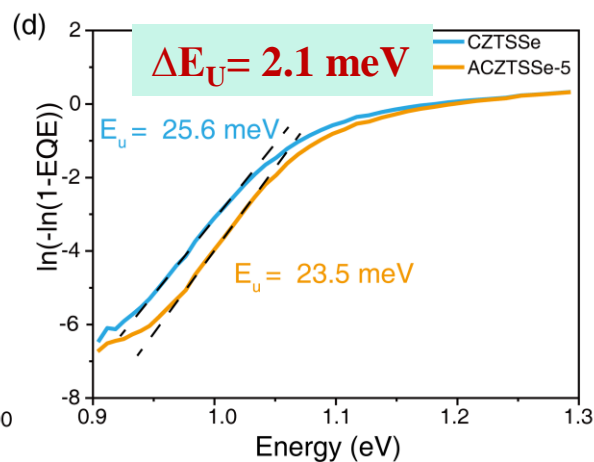
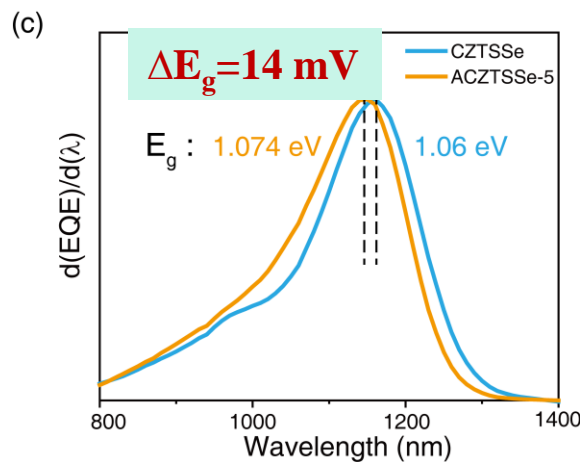
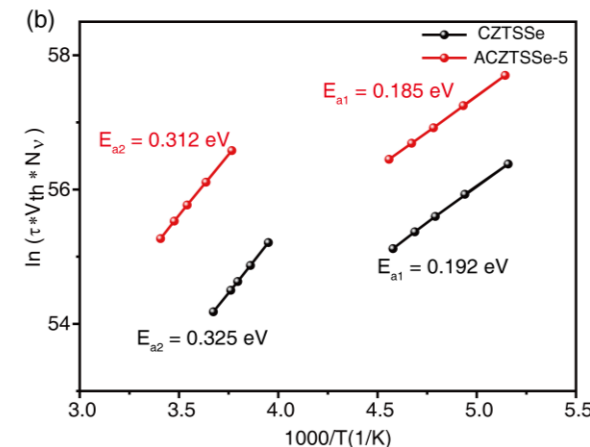
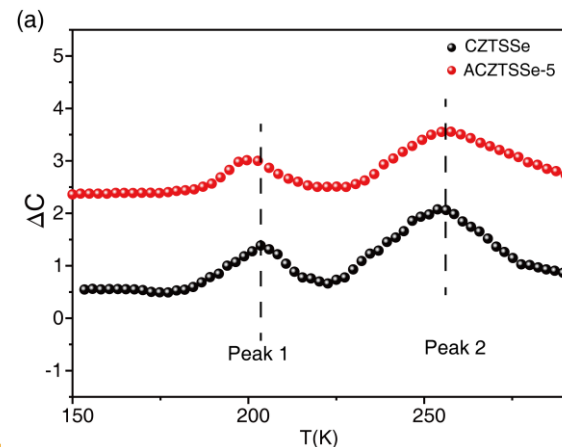
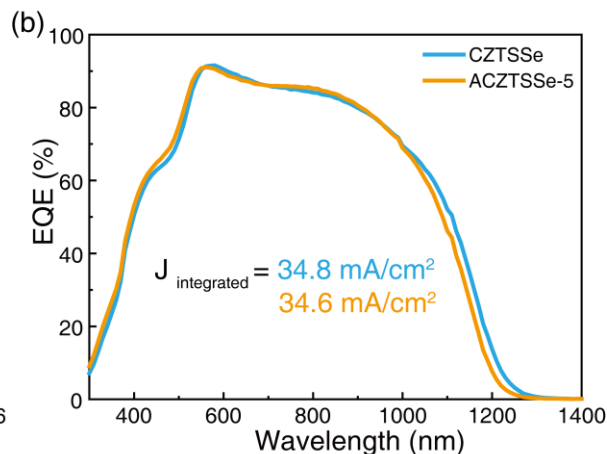
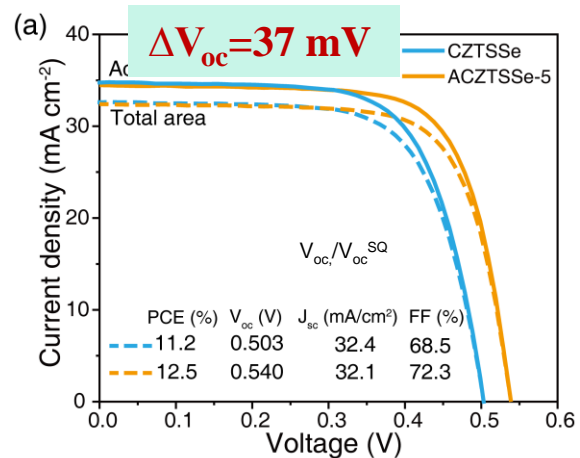
**JHT (200°C/20 h, vacuum)**



Device	V <sub>oc</sub> (V)	J <sub>sc</sub> (mA cm <sup>-2</sup> )	FF (%)	PCE (%)
CZTSSe	0.497±0.006	34.65±1.10	68.1±0.91	11.7±0.31
ACZTSSe-5	0.533±0.004	34.3±0.80	70.5±0.88	12.9±0.33
ACZTSSe-10	0.536±0.006	33.7±1.23	65.8±0.91	11.9±0.52
ACZTSSe-15	0.529±0.007	31.86±0.83	59.7±3.85	10.07±0.86
ACZTSSe-30	0.401±0.070	30.04±1.81	39.35±4.79	58 4.86±1.42

- Band gap increases with Ag concentration increases
- E<sub>U</sub> decreases with Ag concentration increases
- High efficiency with 5-10% Ag

# Ag (5%) Alloying on Defect Property



Device	Defect	$N_T$ (cm <sup>-3</sup> )	Lowest reported
No Ag	Cu <sub>Zn</sub>	$2.84 \times 10^{13}$	$5.79 \times 10^{13}$
	Cu <sub>Sn</sub>	$2.22 \times 10^{13}$	$8.32 \times 10^{13}$
Ag (5%)	Cu <sub>Zn</sub>	$5.12 \times 10^{12}$	$1.50 \times 10^{13}$
	Cu <sub>Sn</sub>	$1.48 \times 10^{13}$	$3.25 \times 10^{13}$

**Total area: 12.5%**  
**Active area: 13.5%**

$$V_{oc}/V_{oc}^{SQ} = 64.2\%$$

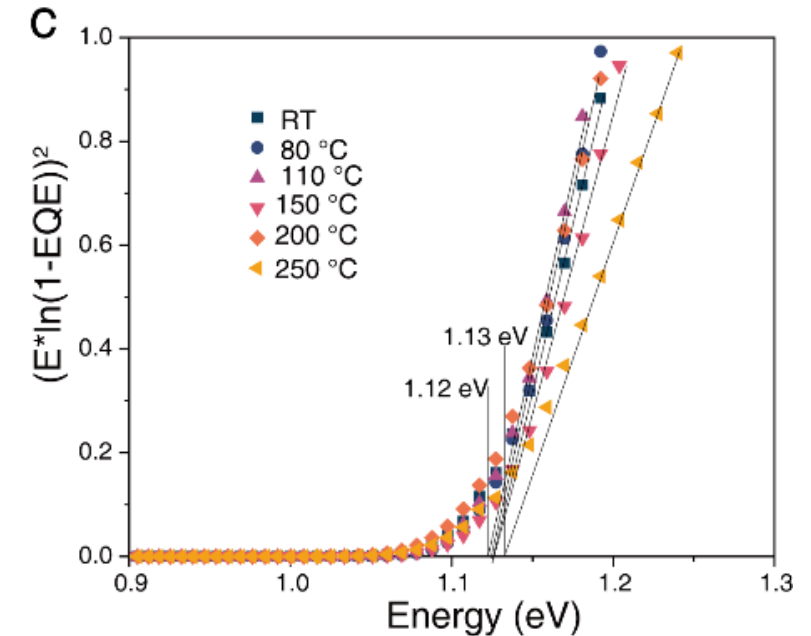
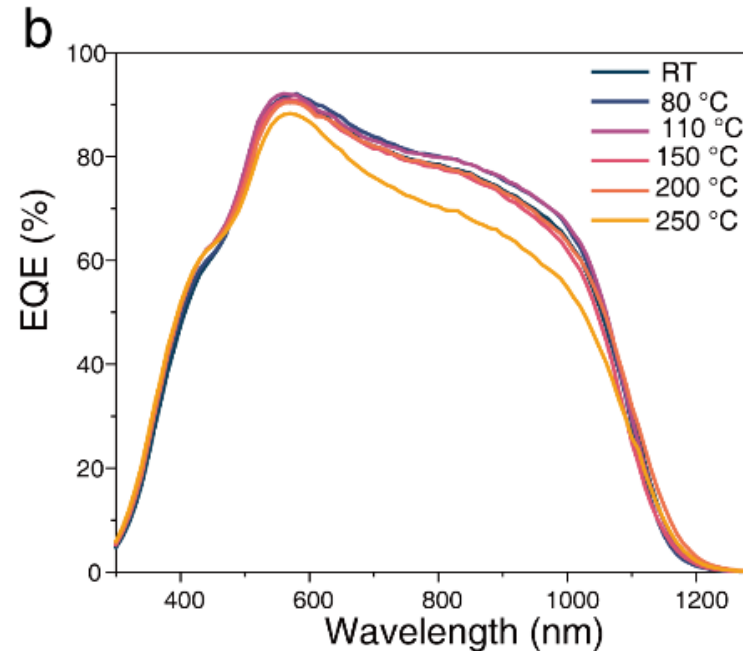
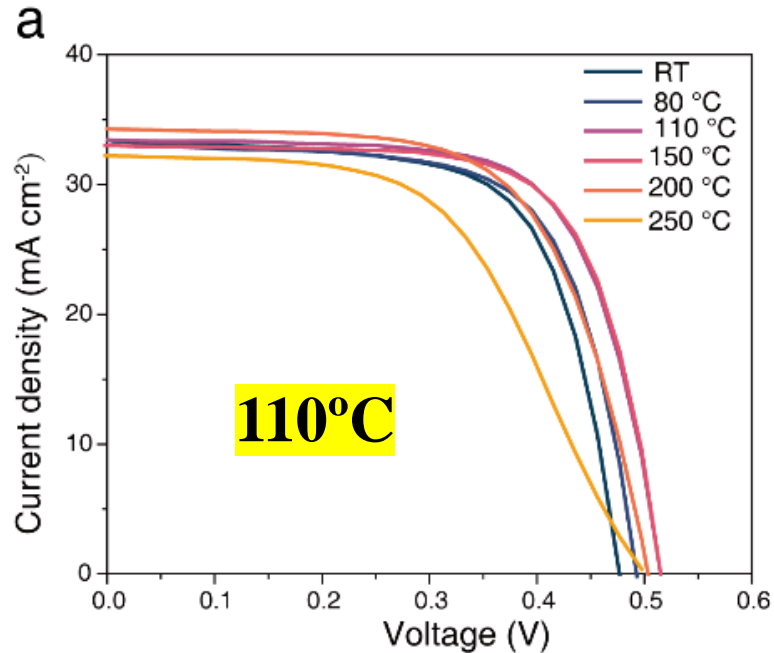
- Suppresses Cu<sub>Zn</sub> and Cu<sub>Sn</sub>
- $E_U$  decreased 2.1 meV,  $V_{oc}$  increased 23 mV

### 3. 异质结界面缺陷与调控

## Optimization of JHT Temperature

JHT (12h, in N<sub>2</sub> filled glovebox)

ACZTSSe-10

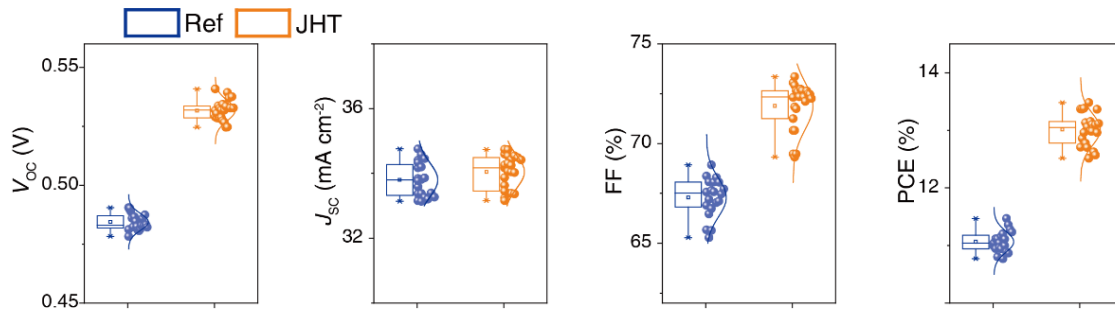
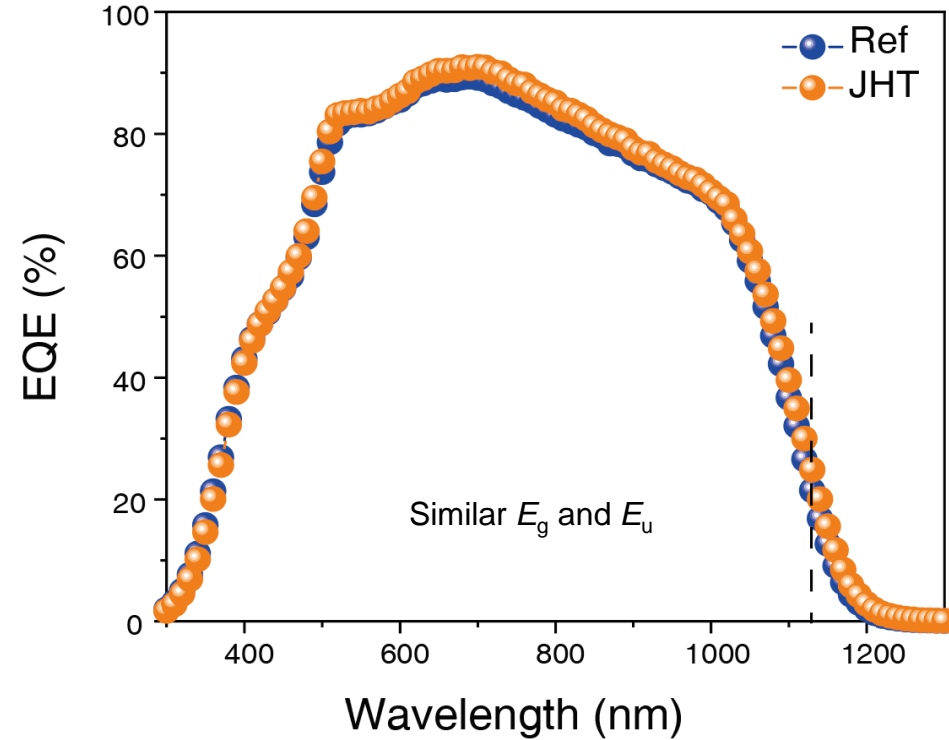
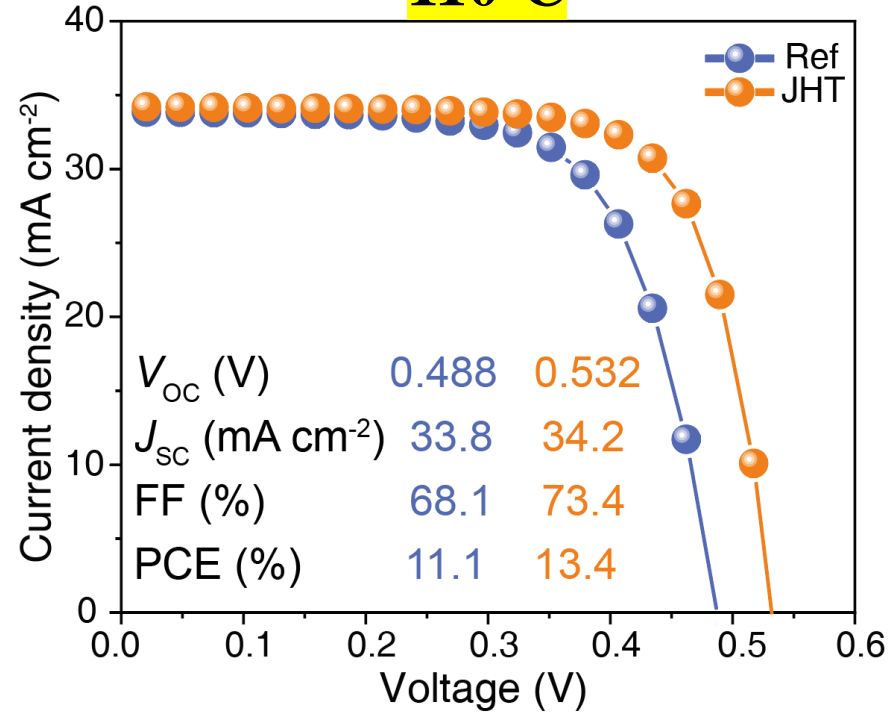


- V<sub>OC</sub> increase observed at temperature as low as 80 °C with 110 °C/150 °C the best
- No band gap increase at the optimized temperature
- No obvious improvement on Cu-Zn order level

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# Low-Temp Junction Heat Treatment (LT-JHT)

110°C



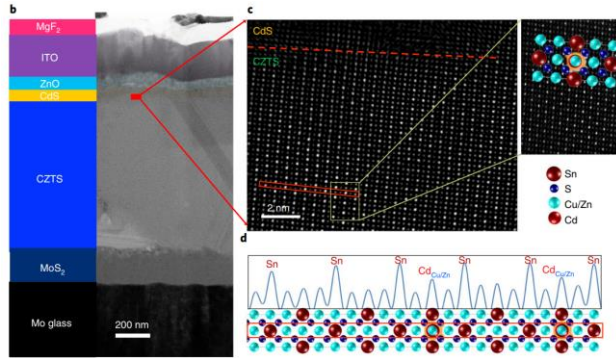
- No change on band gap, same  $E_u$
- No obvious improvement on absorber bulk
- Improvement comes from heterojunction

# JHT of CZTS/CdS and CZTSe/CdS

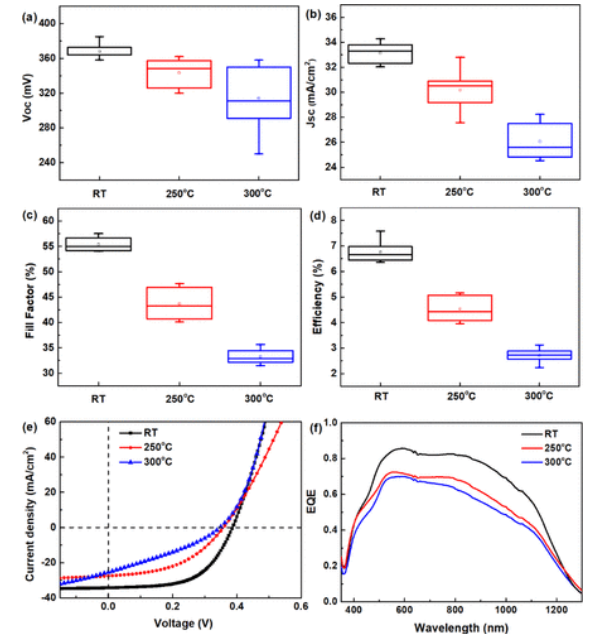
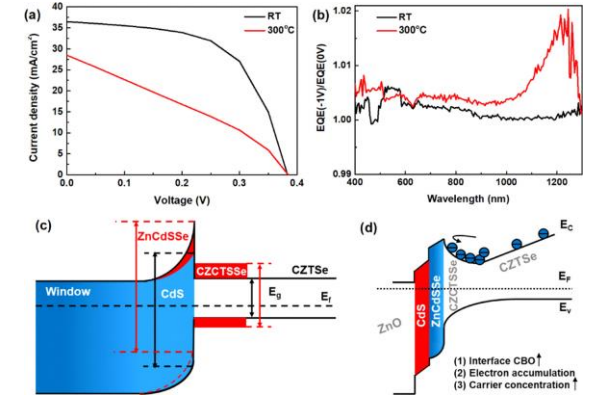
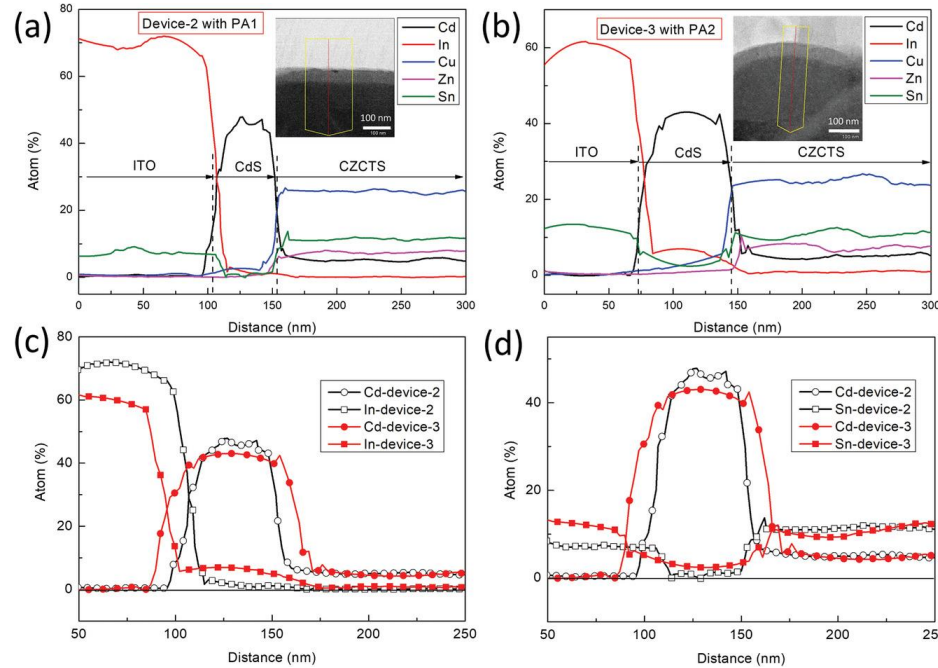
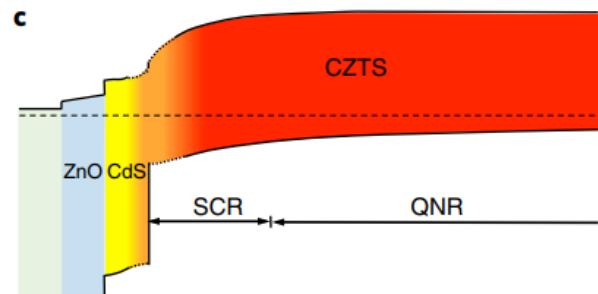
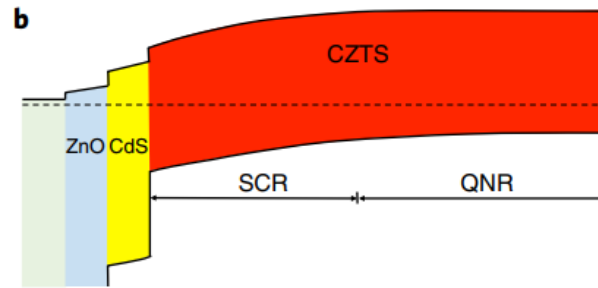
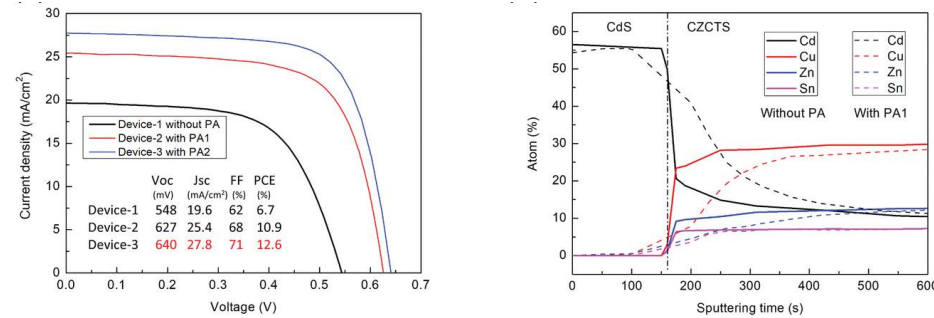
## CZTS/CdS

## CZTSe/CdS

270 °C/10 min

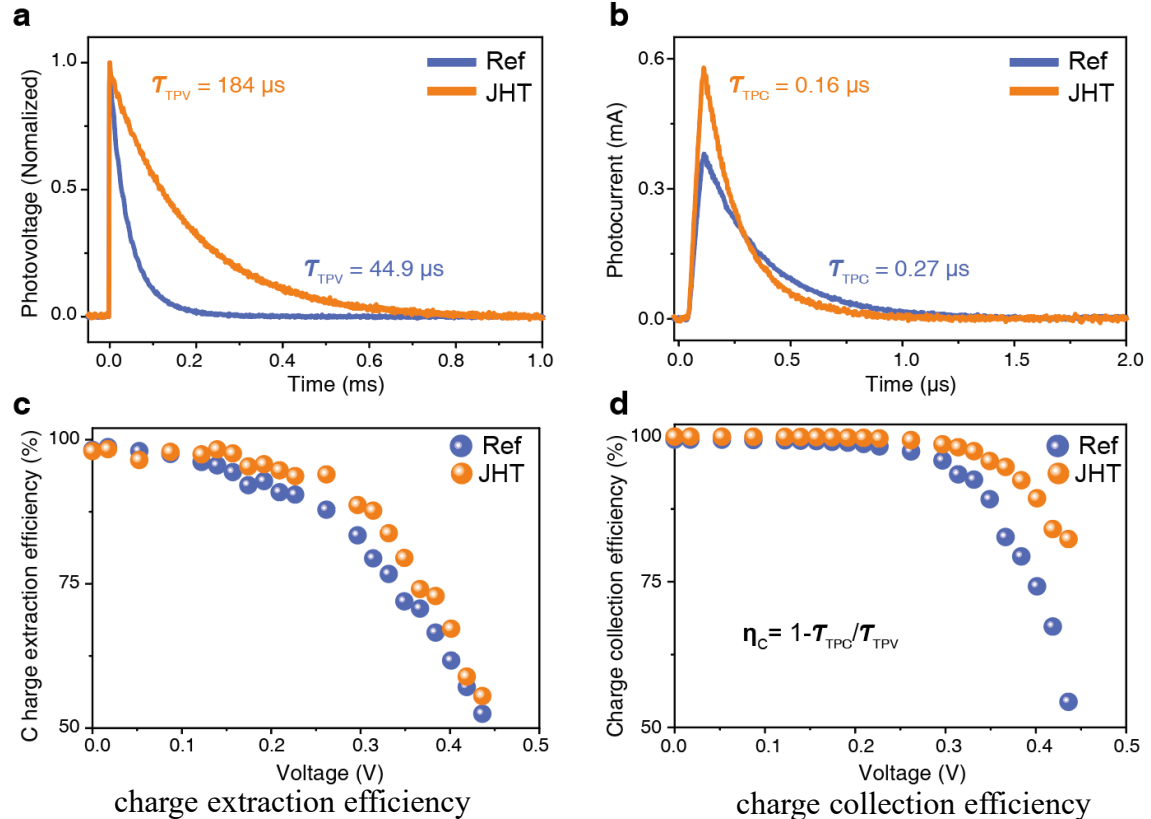


300 °C/8 min



# Interface Recombination Dynamics and Defect Property

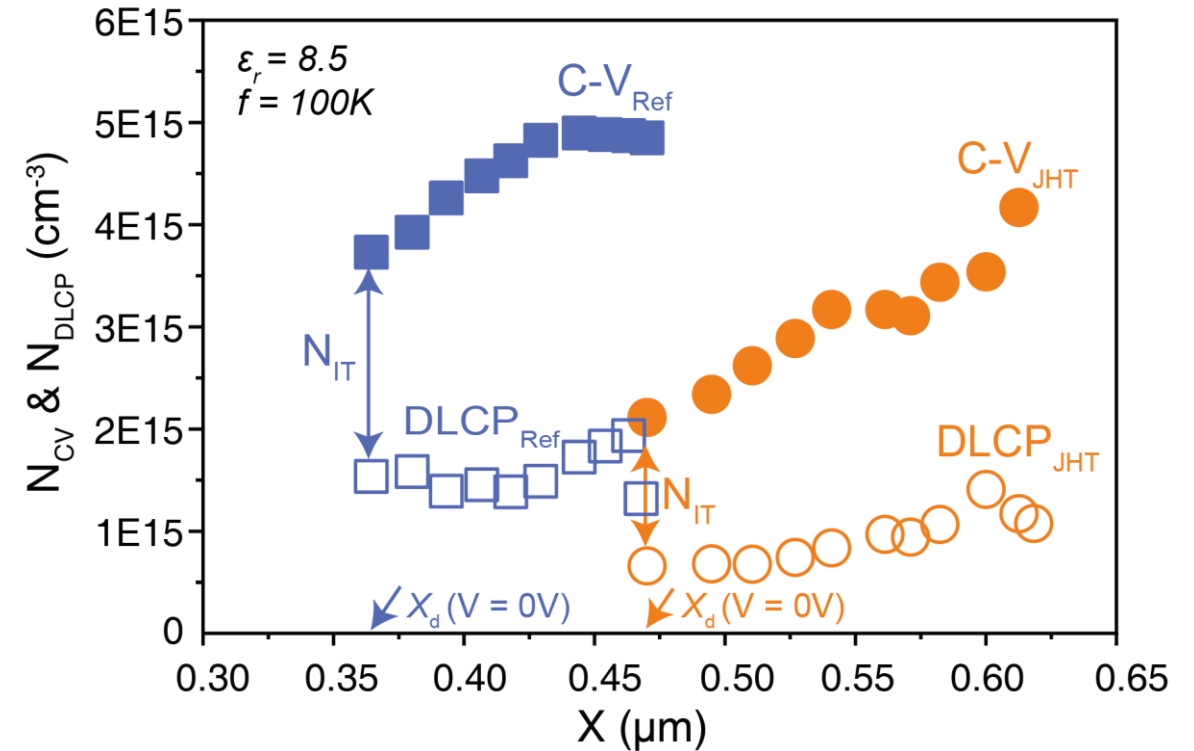
## M-TPV/M-TPC



recombination within the absorber

recombination at the heterojunction

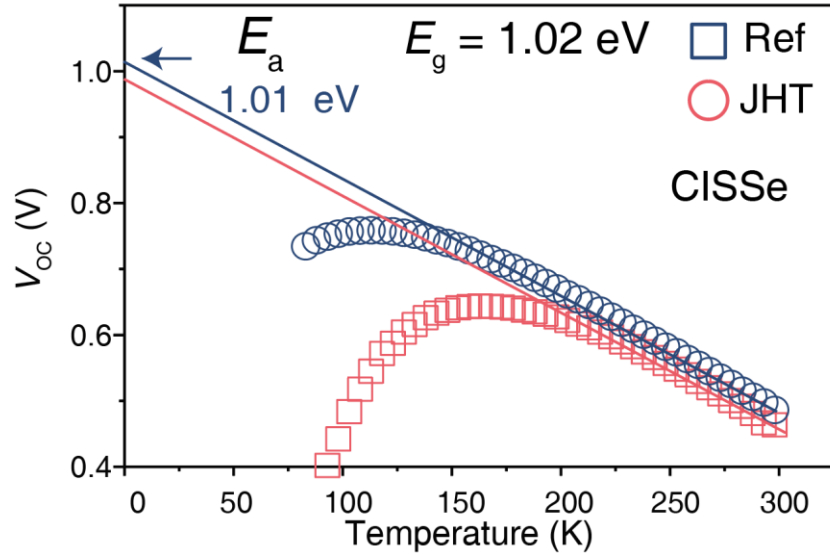
## CV/DLCP



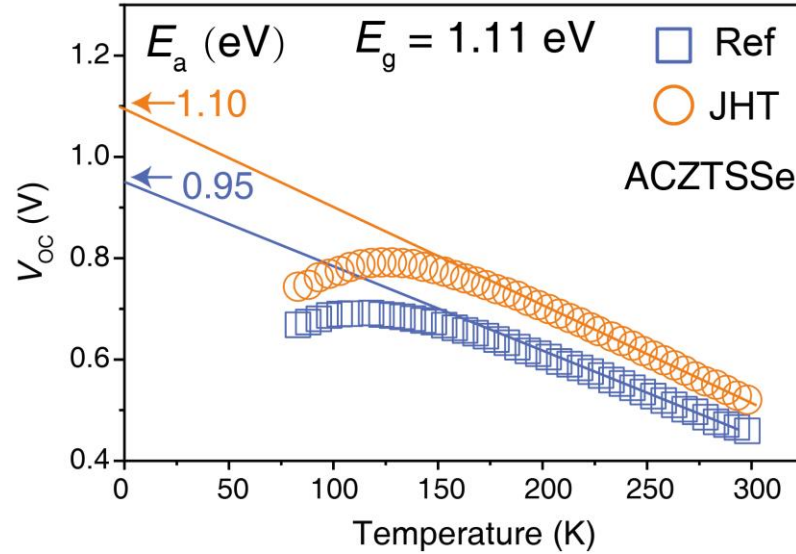
- **LT-JHT significantly reduces interface recombination**
- **LT-JHT greatly reduces interface charge density**

# Interface Recombination: CZTSSe vs CISSe

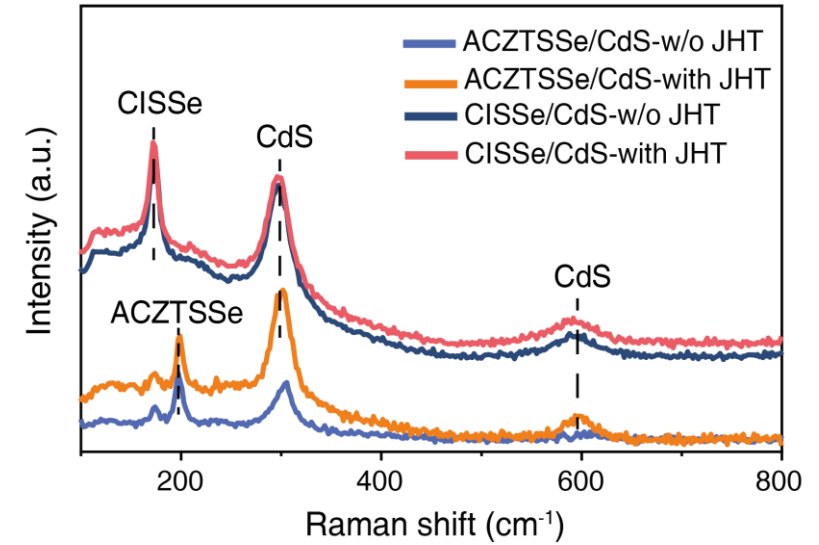
$V_{oc}$ -T



$V_{oc}$ -T



Raman



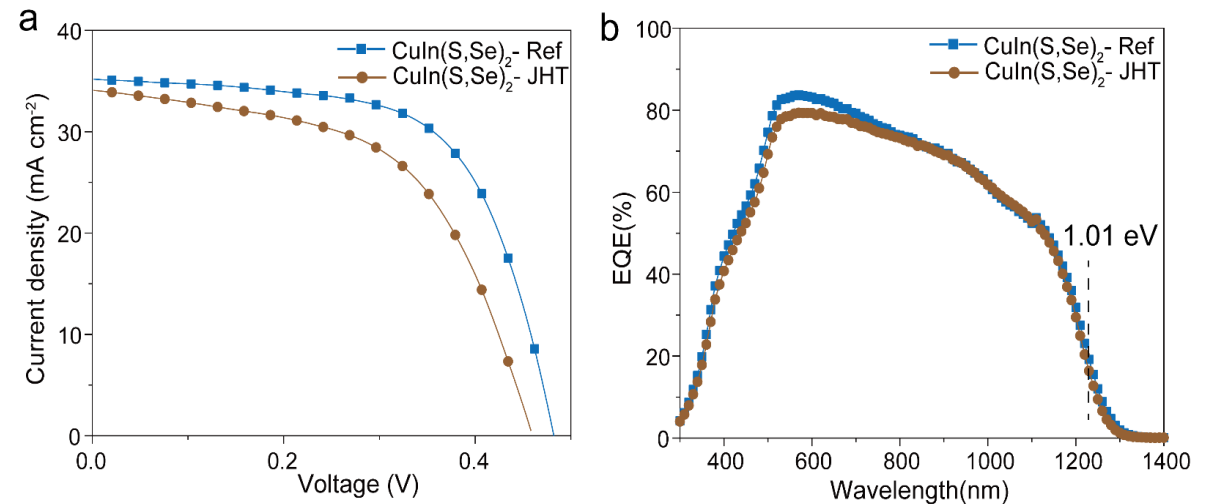
## CZTSSe

- JHT almost eliminates interface recombination
- Low CdS crystallinity
- JHT significant improves crystallinity of CdS

## CISSe

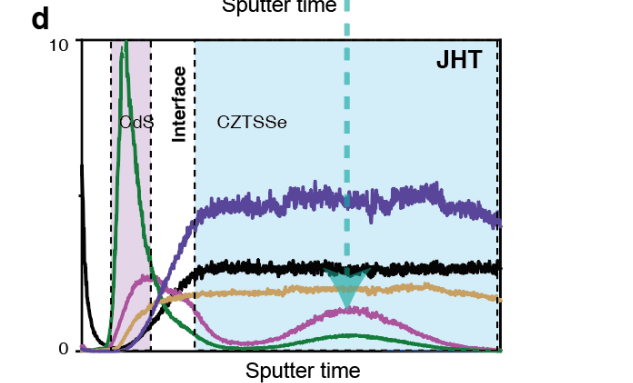
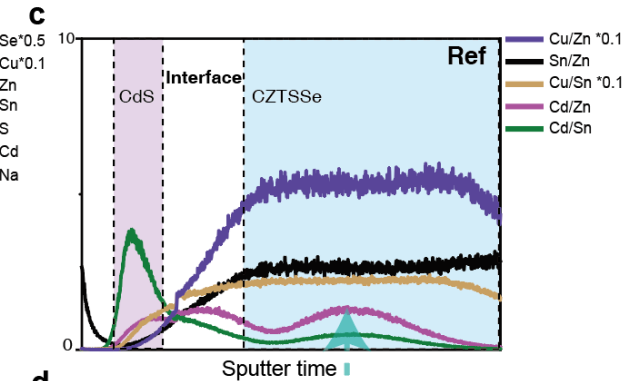
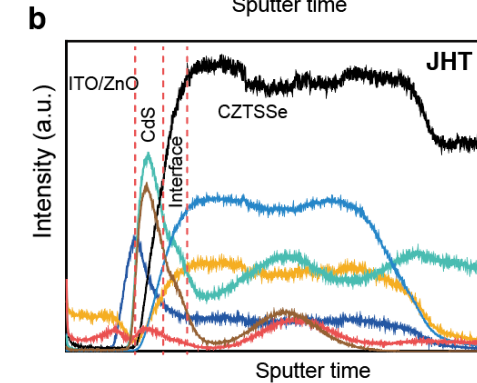
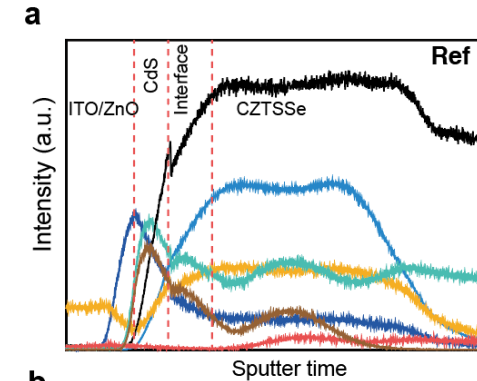
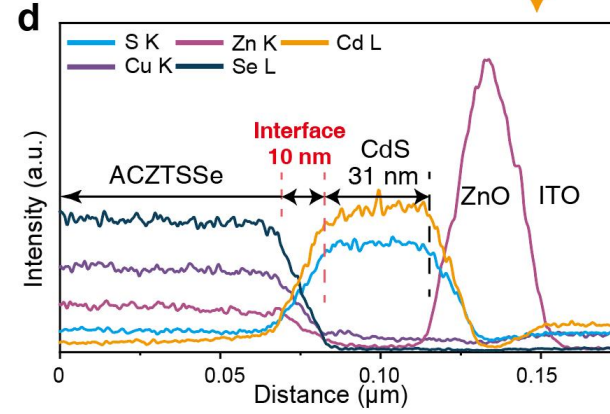
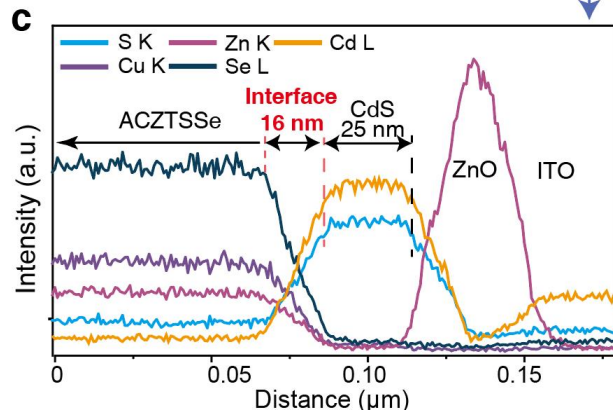
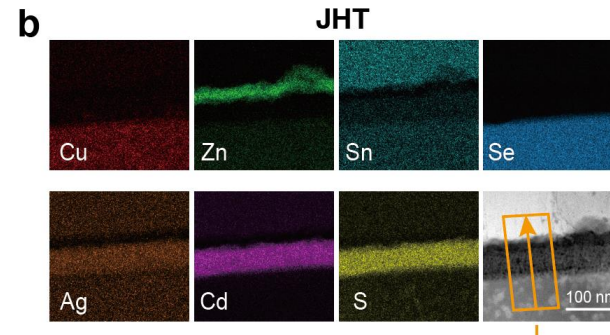
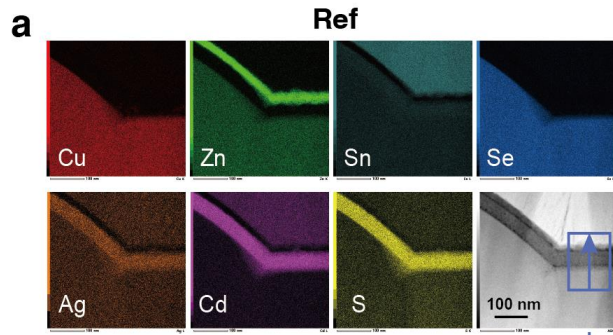
- Perfect heterojunction interface
- JHT deteriorates interface
- High CdS crystallinity
- JHT has little effect on CdS

## CISSe



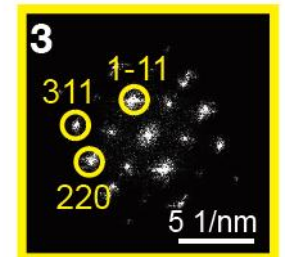
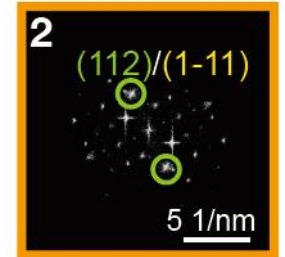
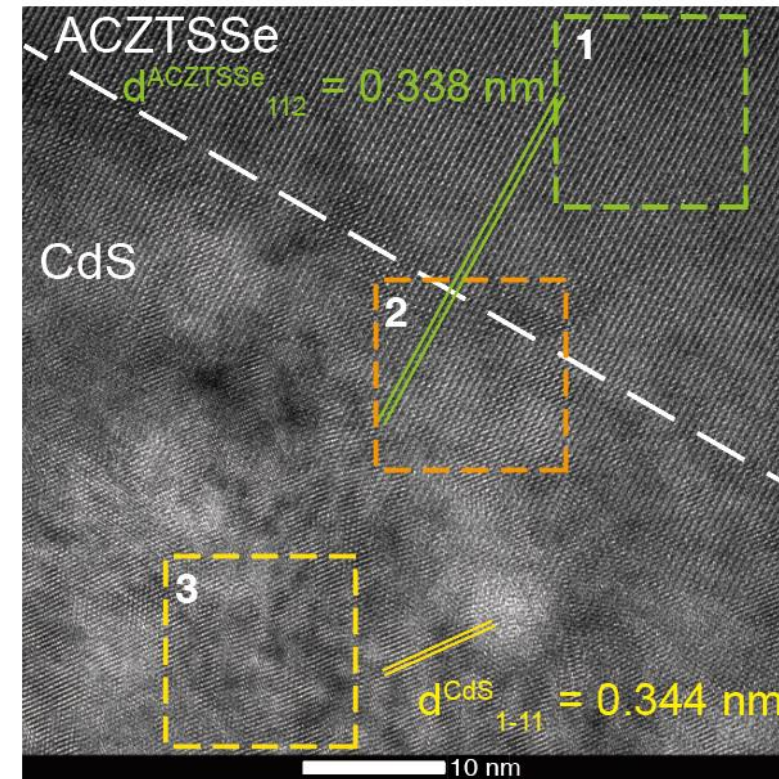
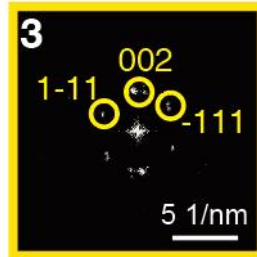
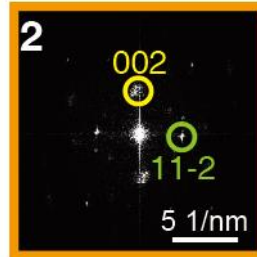
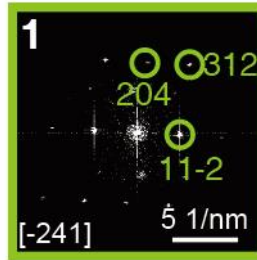
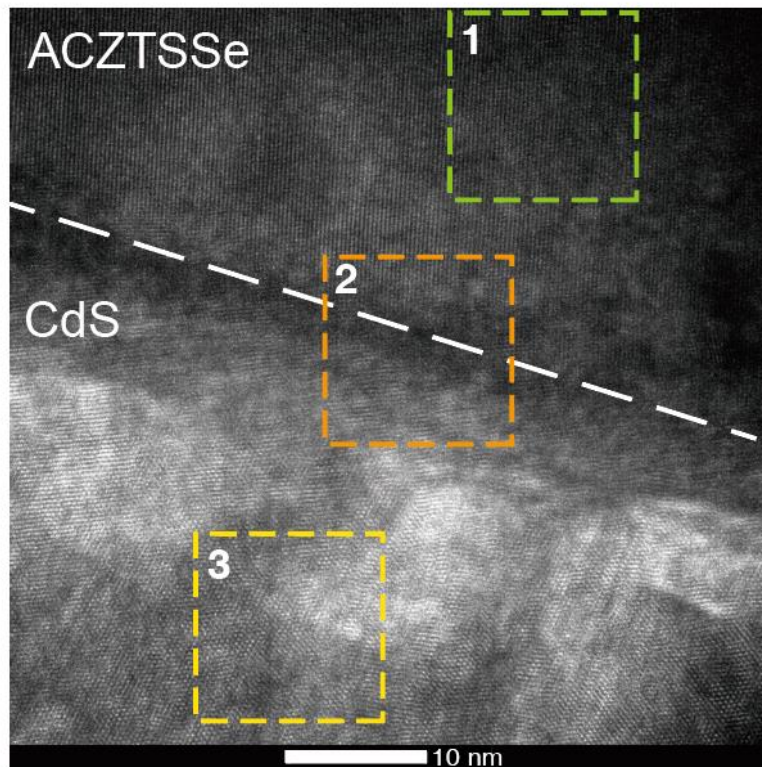


# LT-JHT Induces Interface Elemental Di-Mixing



- Cd in CZTSSe and Zn in CdS are observed in Ref sample
- Interface narrows and sharpens upon low-temperature JHT
- Elemental di-mixing: Cd and Zn back to original position
- Interface moves toward CdS layer

# Elemental Di-mixing Enables Epitaxial Interface

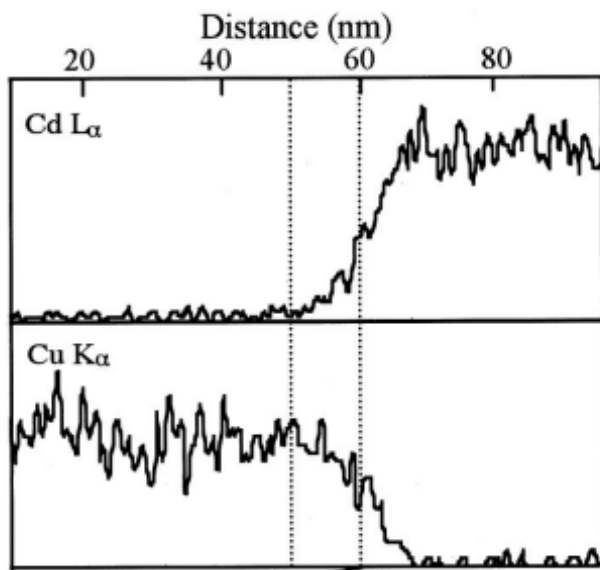
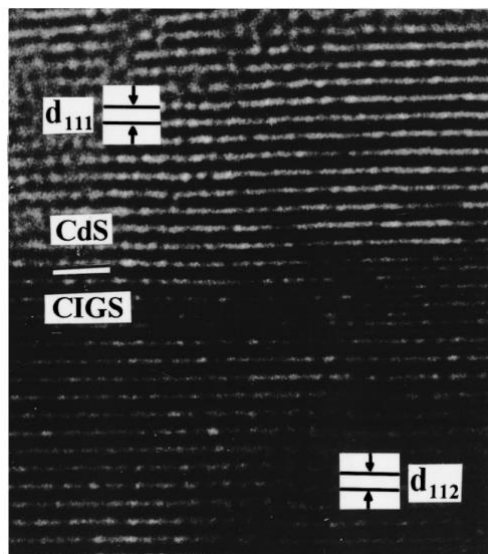


- Low crystallinity of CZTSSe and CdS
- Defective and non-coherent interface

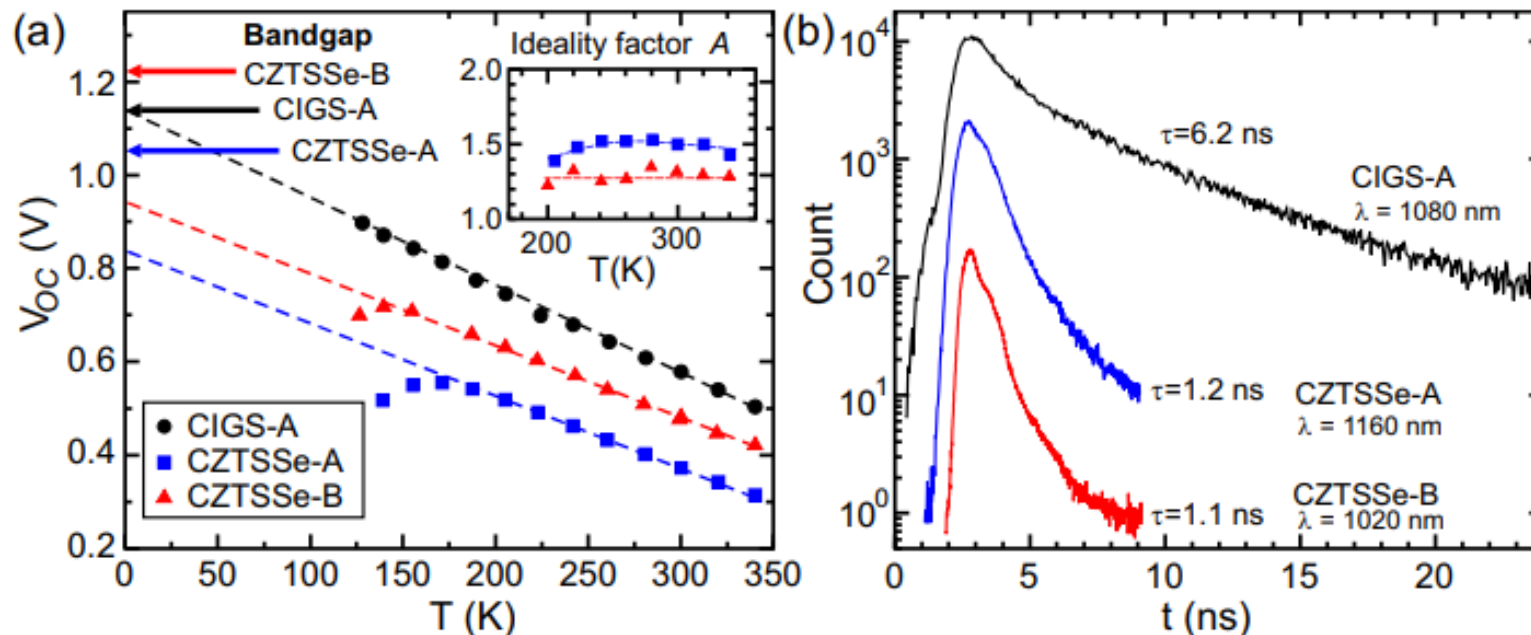
- Improved crystallinity for CZTSSe and CdS
- Coherent interface: CZTSSe(112)||CdS(111)

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# Heterojunction Interface: CZTSSe vs CISSe



Nakada T et al. . Appl. Phys. Lett., 1999.



Gunawan O et al. Appl. Phys. Lett., 2010.

## CIGS/CdS:

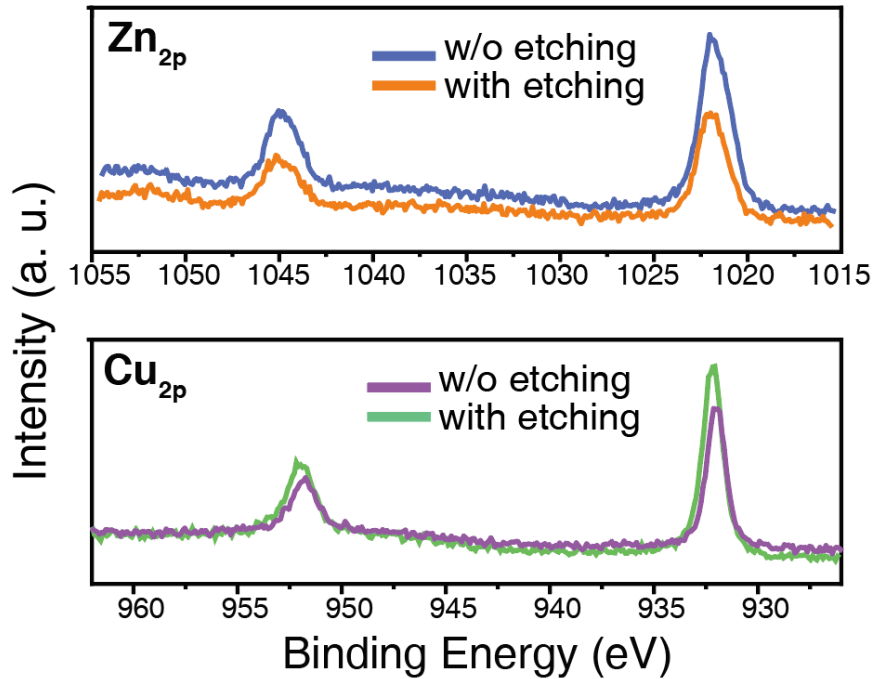
- $E_a \approx E_g$
- less interface recombination
- epitaxial heterointerface
- Cu-poor surface
- $\text{Cd}^{2+}$  occupies  $V_{\text{Cu}}$
- buried pn junction

## CZTSSe/CdS:

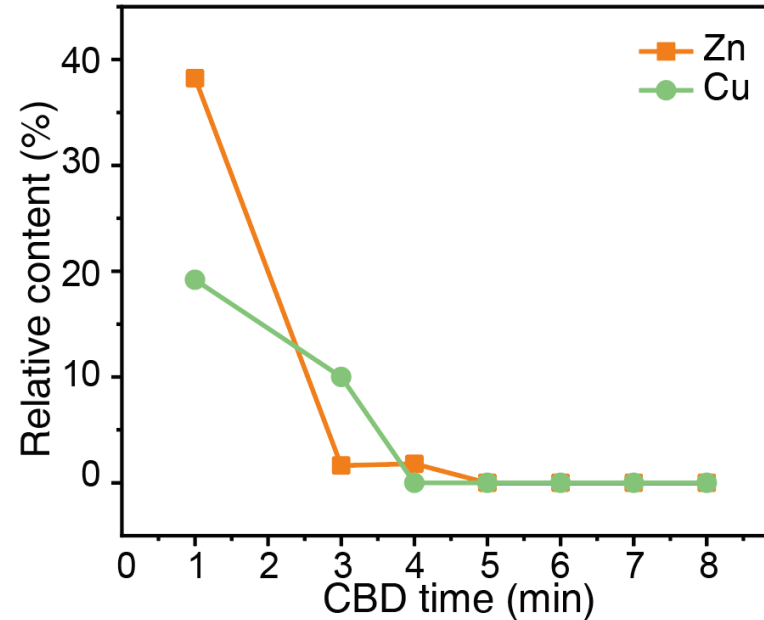
- $E_a < E_g$
- serious interface recombination
- Defective heterointerface
- Cu-poor surface ??
- $\text{Cd}^{2+}$  occupies  $V_{\text{Cu}}$ ??
- buried pn junction??

# Construction of CZTSSe/CdS Interface

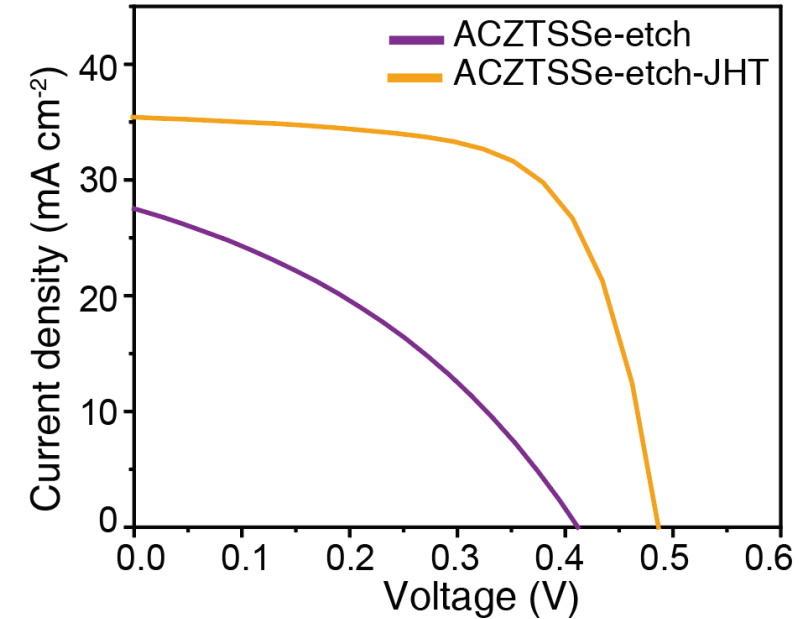
NH<sub>4</sub>OH etching



Zn Cu intensity change



Device with etching and JHT



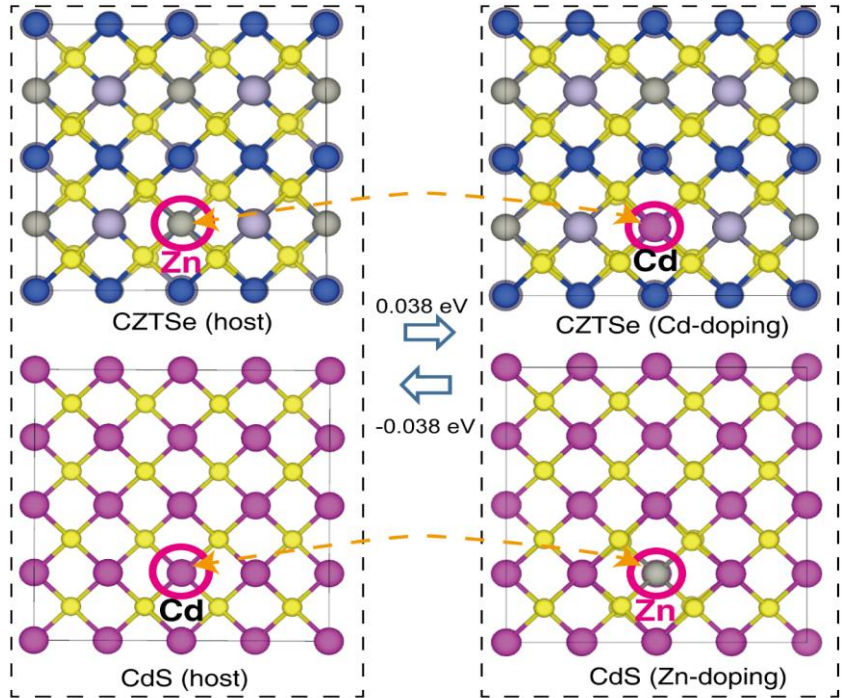
$$K = 8.2 \times 10^{-40}$$



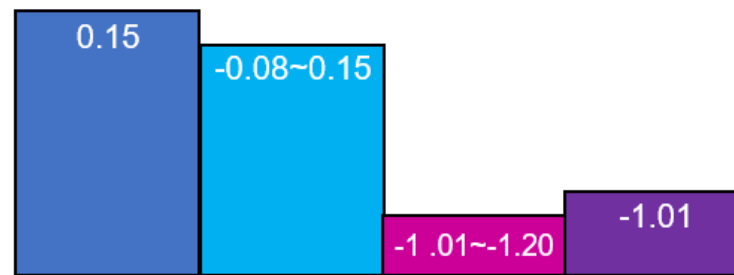
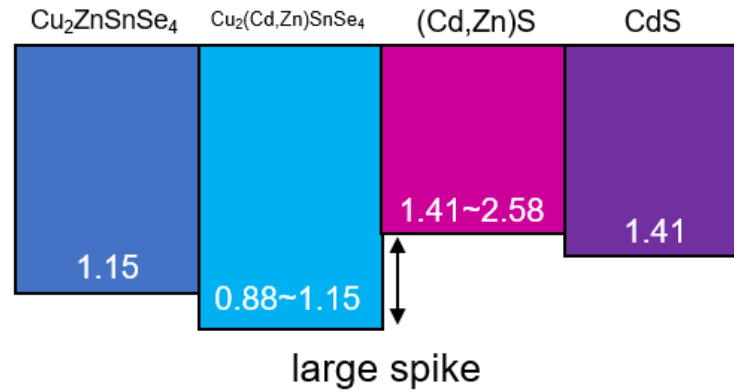
$$K = 1.48 \times 10^{-17}$$

- Zn dissolves with etching (during CBD)
- Cu poor/Zn-rich surface
- CdS constructed on Zn-poor surface (not Cu-poor as in CIGS)
- Zn re-deposition into CdS
- JHT recovers interface: Zn moves towards surface

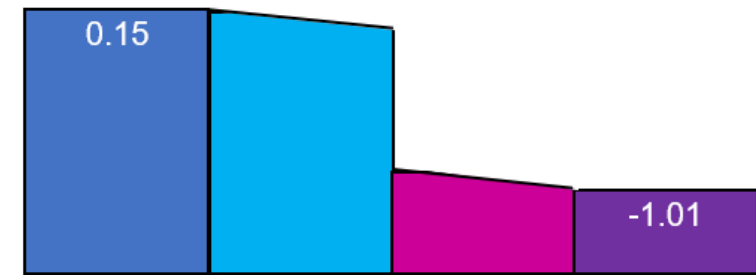
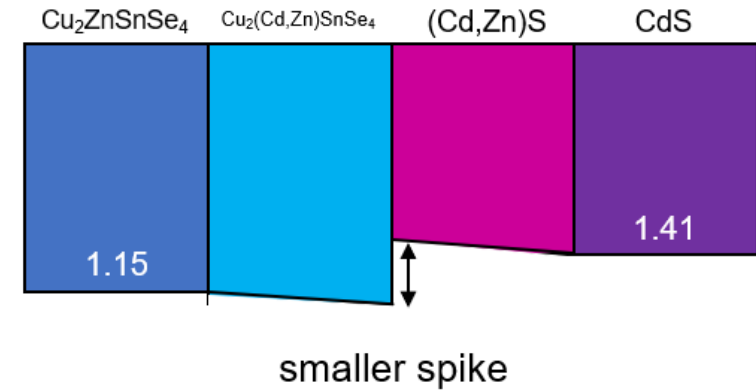
# Lattice Constrain and Band Alignment



$$\Delta E = E_{\text{host}}^{\text{CZTSe}} + E_{\text{host}}^{\text{CdS}} - E_{\text{doped}}^{\text{CZTSe}} - E_{\text{doped}}^{\text{CdS}} = -0.038 \text{ eV}$$

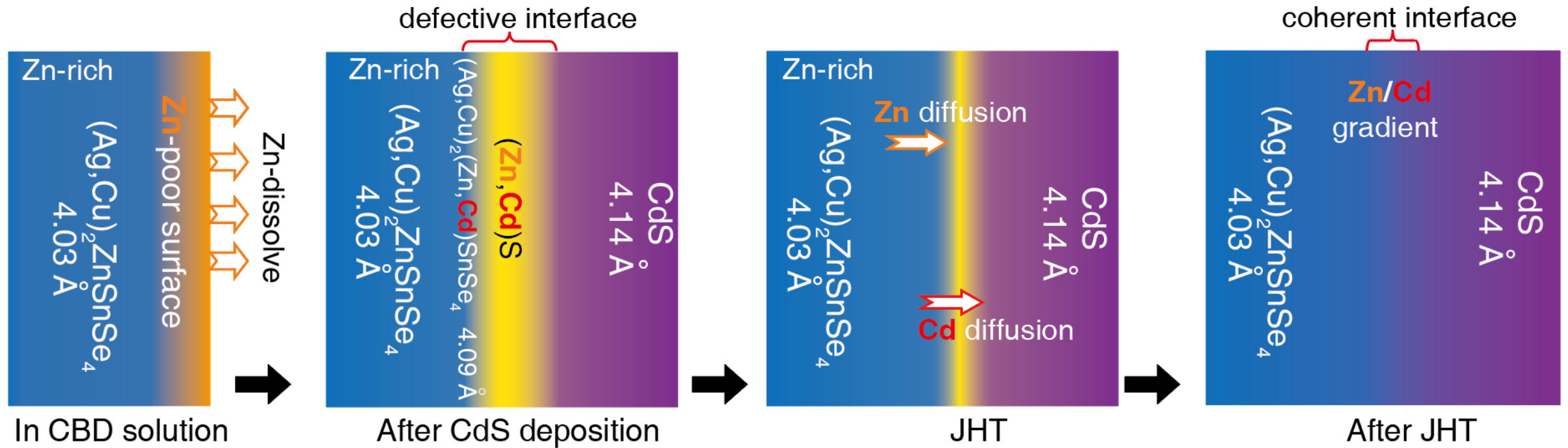


Ref



JHT

# CZTSSe/CdS Interface: Defective to Epitaxial

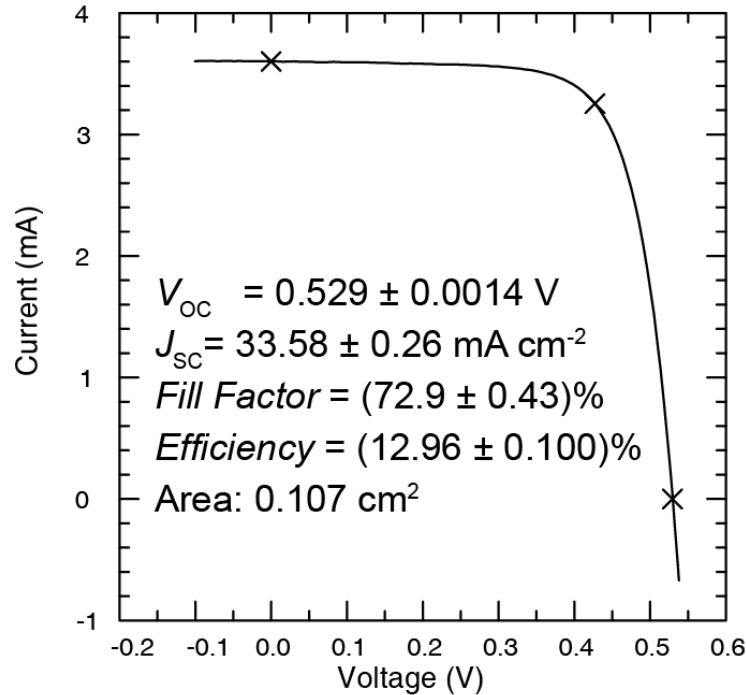


- Cd in CZTSSe and Zn in CdS are observed in Ref sample
- Interface narrows and sharpens upon low-temperature JHT
- Elemental di-mixing: Cd and Zn back to original position
- Interface moves toward CdS layer

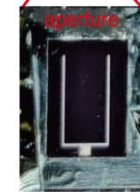
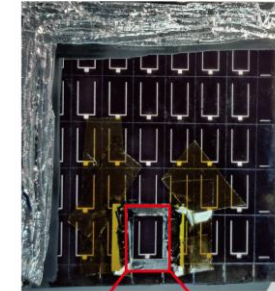
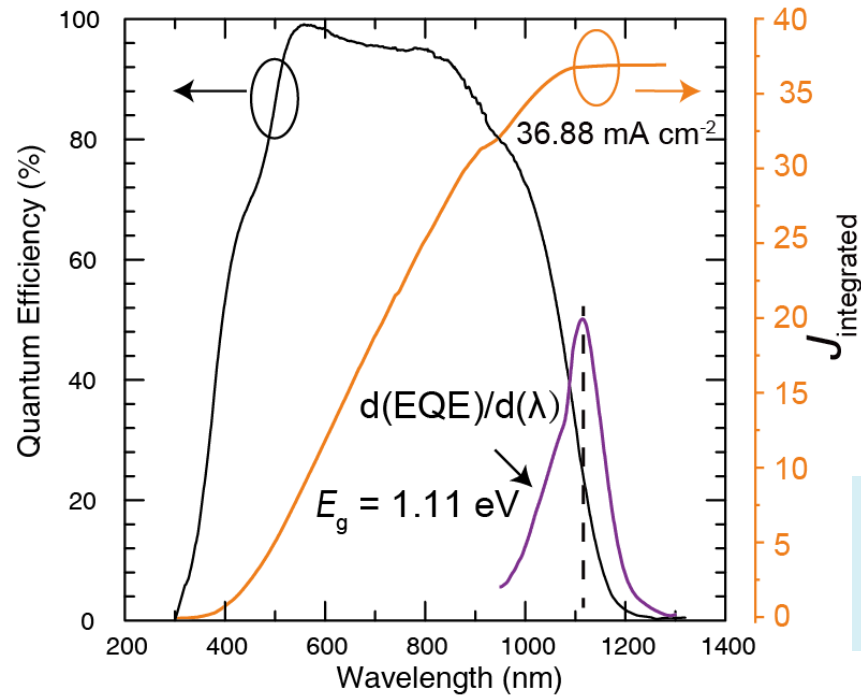
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# Record Efficiency Device via Low-Temp JHT

**NREL** X25 IV System  
NATIONAL RENEWABLE ENERGY LABORATORY PV Cell & Module Performance



**NREL** HLB QE system  
NATIONAL RENEWABLE ENERGY LABORATORY PV Cell & Module Performance

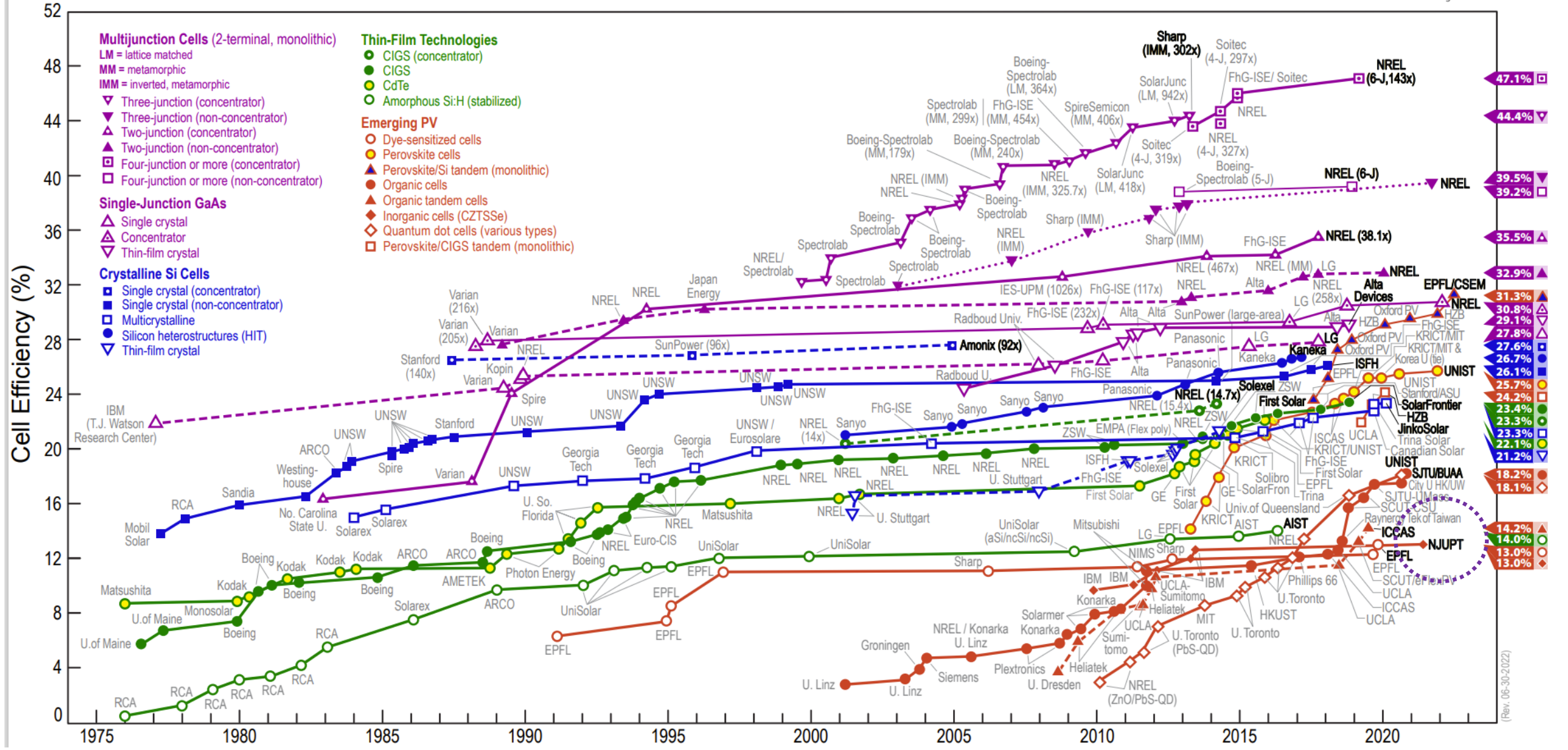


0.107 cm<sup>2</sup> Cell

**Aperture area: 12.96%**  
**Active area: 14.22%**

Device	Absorber	Area (cm <sup>2</sup> )	V <sub>oc</sub> (V)	J <sub>sc</sub> (mA/cm <sup>2</sup> )	FF (%)	Eff. (%)	n	J <sub>0</sub> (A/cm <sup>2</sup> )	R <sub>s</sub>	E <sub>g</sub> (eV)	V <sub>OC-def</sub> (V)	Certifying Center
This work	ACZTSSe*	0.107	0.529	33.7	72.9	13.0	1.35	$8.2 \times 10^{-9}$	0.35	1.11	0.337	NREL
IBM cell <sup>6</sup>	CZTSSe	0.420	0.513	35.2	69.8	12.6	1.45	$7.0 \times 10^{-8}$	0.72	1.13	0.373	Newport
DGIST cell <sup>7</sup>	CZTSSe	0.480	0.541	35.4	65.9	12.6	1.88	$9.6 \times 10^{-7}$	0.87	1.13	0.345	Newport
UNSW cell <sup>2</sup>	CZTS	0.233	0.730	21.7	69.3	11.0	1.44	$6.8 \times 10^{-8}$	2.58	1.50	0.500	NREL
IBM cell <sup>27</sup>	CZTSe	0.43	0.423	40.6	67.3	11.6	1.57	$1.3 \times 10^{-6}$	0.32	1.00	0.342	Newport

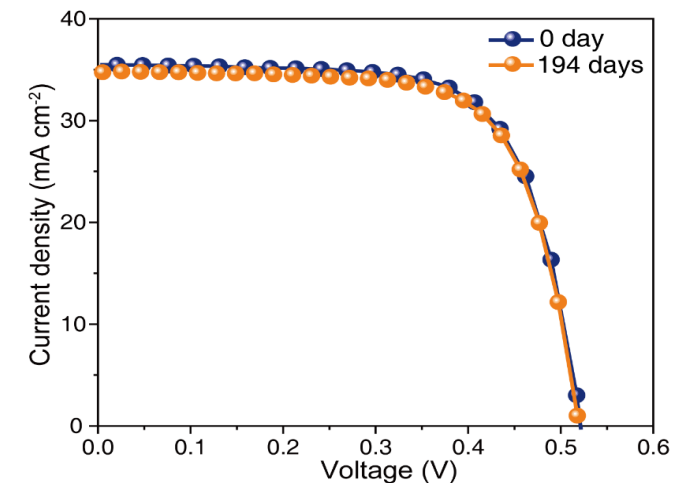
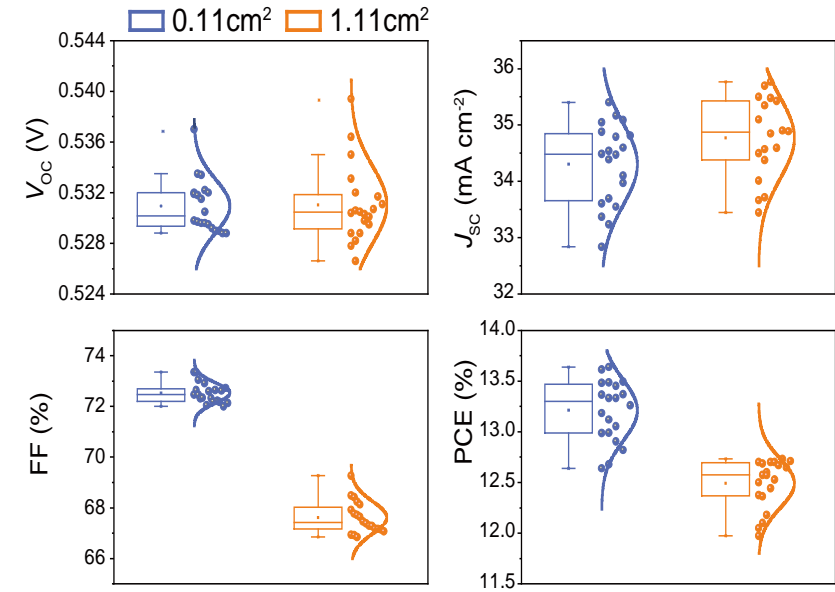
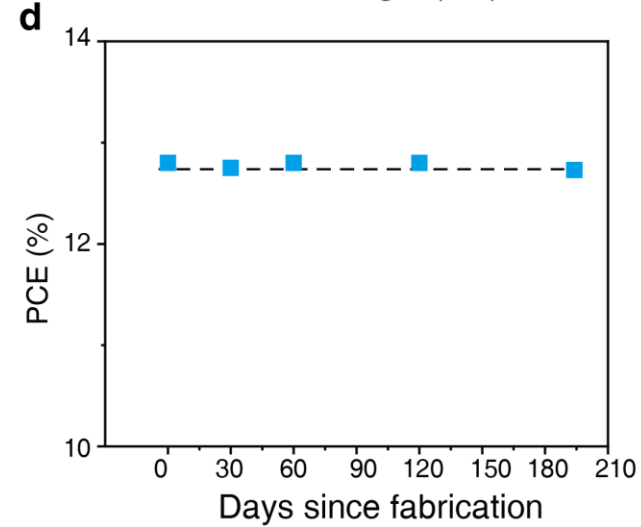
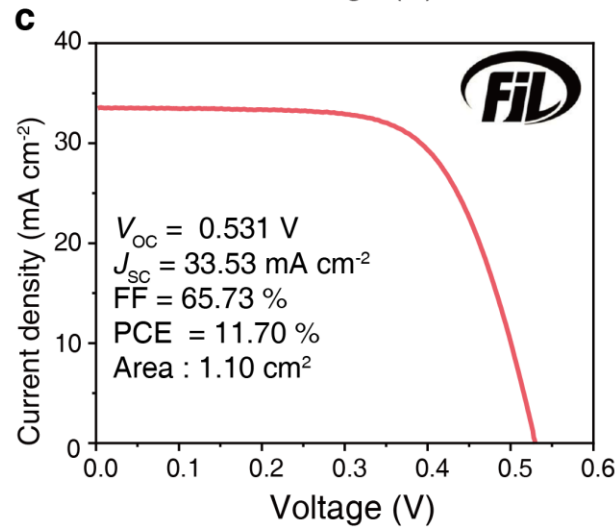
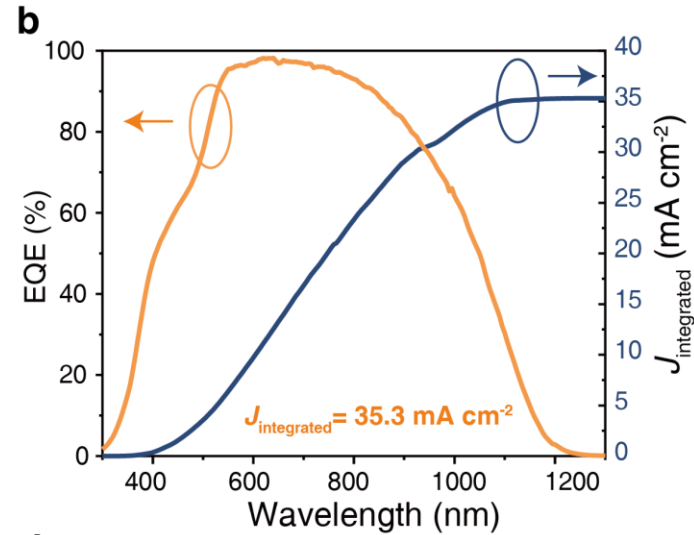
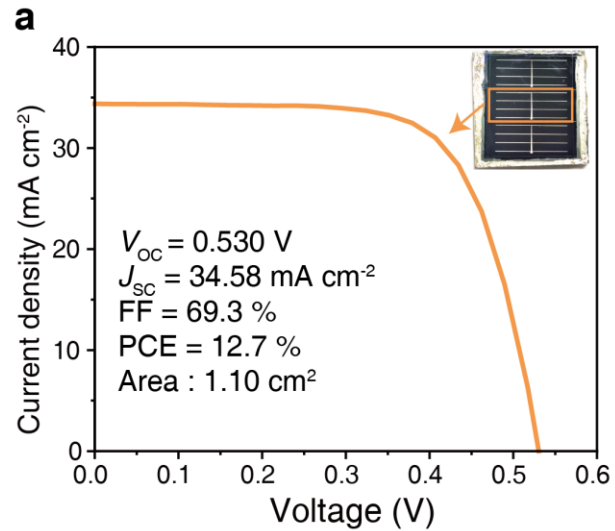
# Best Research-Cell Efficiencies



Best Research-Cell Efficiency Chart | Photovoltaic Research | NREL



# Solar Cells on 1-cm<sup>2</sup> Area and Device Stability



# Certification of 11.7% 1-cm<sup>2</sup> Size Device



福建省计量科学研究院  
FUJIAN METROLOGY INSTITUTE  
(国家光伏产业计量测试中心)  
National PV Industry Measurement and Testing Center



## 检测报告

Test Report

报告编号: 21Q3-00174

Report No.

客户名称  
Name of Customer: Nanjing University of Posts and Telecommunications

联络信息  
Contact Information: No. 9, Wenyuan Road, Qixia District, Nanjing City, Jiangsu Province, China

物品名称  
Name of Items: NJUPT-CZTSS<sub>6</sub>-1

型号/规格  
Type/Specification: Area: 1.11cm<sup>2</sup>

物品编号  
Items No.

制造厂商  
Manufacturer: Nanjing University of Posts and Telecommunications

物品接收日期  
Items Receipt Date: 2021-06-09

检测日期  
Test Date: 2021-06-09

批准人  
Approved by: 黎健生

核验员  
Checked by: 何翔

检测员  
Test by: 游宏亮

(盖章处)  
Stamp

发布日期 2021 年 06 月 21 日  
Date of Report Year month Day



扫一扫查真伪

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咨询电话: 0591-87845050  
Inquiry line  
投诉电话: 0591-87823025  
Fax for complaint



福建省计量科学研究院  
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报告编号: 21Q3-00174

Report No.

### 检测结果/说明:

Results of Test and additional explanation.

- Standard Test Condition (STC): Total Irradiance: 1000 W/m<sup>2</sup>  
Temperature: 25.0 °C  
Spectral Distribution: AM1.5G

### 2 Measurement Data under STC

Test Times	$I_{sc}$ (mA)	$V_{oc}$ (V)	$I_{MPP}$ (mA)	$V_{MPP}$ (V)	$P_{MPP}$ (mW)	FF (%)	$\eta$ (%) total area	$\eta$ (%) effective area (with subtracted busbars area)
1	36.89	0.5305	32.81	0.3929	12.89	65.87	11.70	12.38
2	36.92	0.5315	32.77	0.3935	12.89	65.69	11.70	12.38
3	36.92	0.5319	32.79	0.3931	12.89	65.64	11.70	12.38
Average Value	36.91	0.5313	32.79	0.3932	12.89	65.73	11.70	12.38

Mismatch factor: 1.019

### 3 I-V & P-V Characteristic Curves under STC

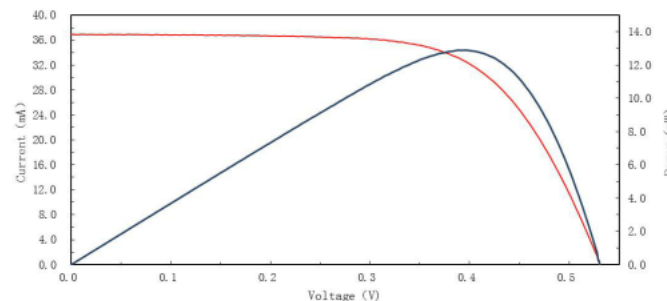
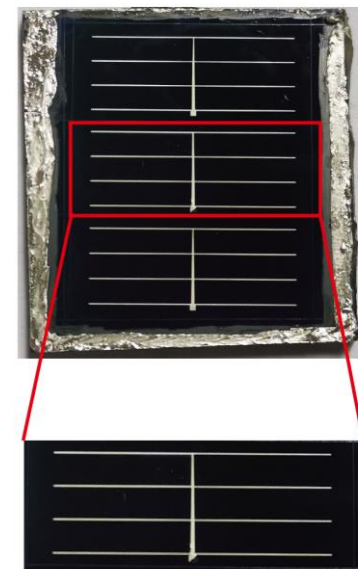


Figure 1. I-V and P-V characteristic curves of the measured sample under STC



**Total area: 11.70%**  
**Active area: 12.38%**

**$V_{oc} = 0.5313$  mV**

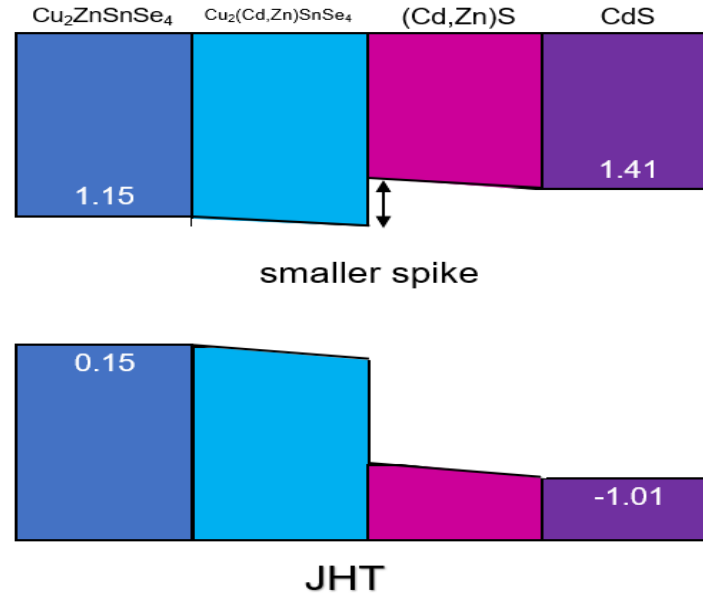
**FF = 65.73%**

# Recombination-free Heterojunction Interface

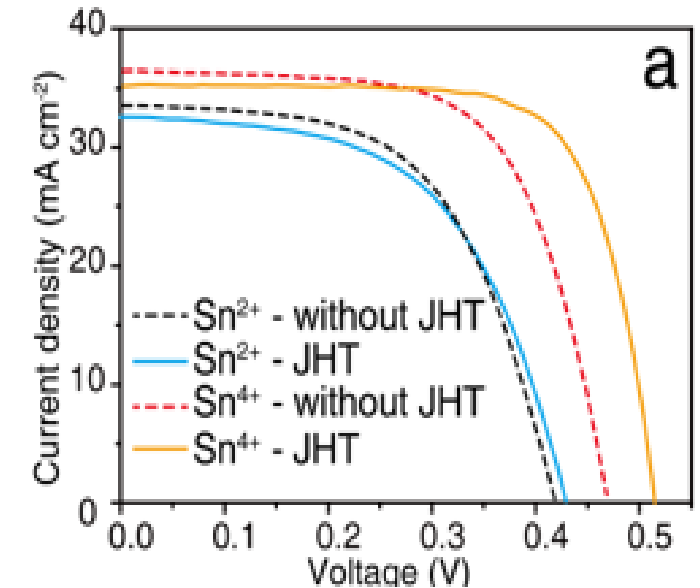
epitaxial interface  
(matched lattice constants)

	Zinc-blende	(112)/(111) in-plane cons.	layer distance
<b>CdS</b>	<b>5.848</b>	<b>4.136</b>	<b>3.376</b>
<b>CuInSe<sub>2</sub></b>	<b>a=5.781, c=11.642</b>	<b>4.103</b>	<b>3.349</b>
Cu <sub>2</sub> ZnSnSe <sub>4</sub>	a=5.680, c=11.360	4.016	3.278
Cu <sub>2</sub> CdSnSe <sub>4</sub>	a=5.826, c=11.394	4.074	3.326
Ag <sub>2</sub> ZnSnSe <sub>4</sub>	a=6.036, c=11.301	4.134	3.375
Cu <sub>2</sub> ZnSnS <sub>4</sub>	a=5.429, c=10.847	3.837	3.132
Cu <sub>2</sub> CdSnS <sub>4</sub>	a=5.590, c=10.840	3.893	3.178
Ag <sub>2</sub> ZnSnS <sub>4</sub>	a=5.776, c=10.869	3.965	3.237

reasonable CBO  
(small spike)



uniform surface  
(less defective)

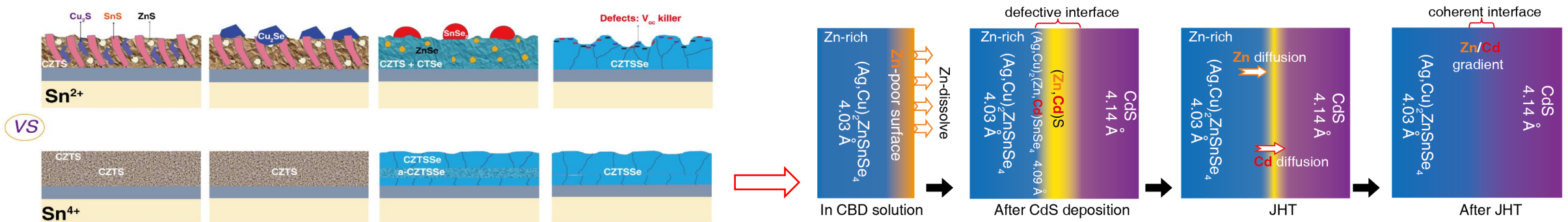


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- CdS is a good buffer layer for CZTSe but not for CZTS
- Uniform surface (grain growth) is crucial for kesterite

# 4. 总结与展望

- ◆ Controlled solution chemistry enables fabrication of CZTSSe through direct phase transformation grain growth, which sufficiently suppresses defects and band tailing.
- ◆ For the first time **unveils that the kesterite/CdS heterojunction is constructed on a Zn-poor surface** (not Cu-poor surface as CIGS), accounting for the defective heterojunction interface.
- ◆ Low temperature JHT induces **elemental di-mixing**, which **reconstructs epitaxial interface**.
- ◆ **We have achieved 13% new record efficiency and 11.7% certified efficiency on 1 cm<sup>2</sup> size.**
- ◆ The findings are expected to advance the development of kesterite solar cells.
- ◆ The strategies developed here can be applied to other solution based multi-element semiconductors.



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**Dr. Weibo Yan**  
**Dr. Jingjing Jiang**  
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**Yage Zhou**



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Ministry of Science and Technology of the People's Republic of China

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Nanjing University of Posts and Telecommunications